

TENTATIVE TOSHIBA MOS DIGITAL INTEGRATED CIRCUIT SILICON GATE CMOS

**4 GBIT (512M × 8 BIT) CMOS NAND E<sup>2</sup>PROM (Multi Level Cell)****DESCRIPTION**

The TC58NVG2D4B is a single 3.3 V 4 Gbit (4,429,185,024 bits) NAND Electrically Erasable and Programmable Read-Only Memory (NAND E<sup>2</sup>PROM) organized as (2048 + 64) bytes × 128 pages × 2048 blocks.

The device has two 2112-byte static registers which allow program and read data to be transferred between the register and the memory cell array in 2112-byte increments. The Erase operation is implemented in a single block unit (256 Kbytes + 8 Kbytes: 2112 bytes × 128 pages).

The TC58NVG2D4B is a serial-type memory device which utilizes the I/O pins for both address and data input/output as well as for command inputs. The Erase and Program operations are automatically executed making the device most suitable for applications such as solid-state file storage, voice recording, image file memory for still cameras and other systems which require high-density non-volatile memory data storage.

**FEATURES**

- Organization

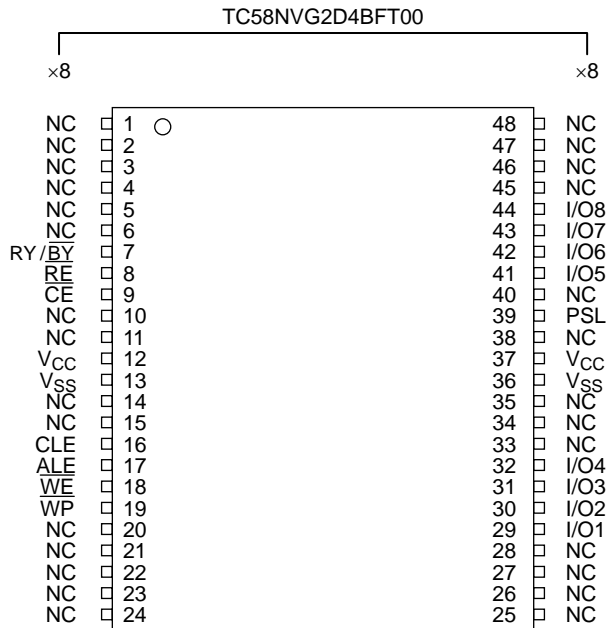
|                   |                   |
|-------------------|-------------------|
|                   | TC58NVG2D4B       |
| Memory cell array | 2112 × 256K × 8   |
| Register          | 2112 × 8          |
| Page size         | 2112 bytes        |
| Block size        | (256K + 4K) bytes |
  
- Modes
  - Read, Read with Data Cache, Reset, Auto Page Program, Auto Page Program with Data Cache, Multi Page Program with Cache, Auto Block Erase, Status Read, Page Copy
  
- Mode control
  - Serial input/output
  - Command control
  
- Number of valid blocks
  - Max 2048 blocks
  - Min 1968 blocks
  
- Power supply
  - V<sub>CC</sub> = 2.7 V to 3.6 V
  
- Program/Erase Cycles
  - TBD Cycles (With 4bit/528Byte ECC)
  
- Access time

|                        |           |
|------------------------|-----------|
| Cell array to register | 50 μs max |
| Serial Read Cycle      | 50 ns min |
  
- Program/Erase time

|                   |                  |
|-------------------|------------------|
| Auto Page Program | 800 μs/page typ. |
| Auto Block Erase  | 3 ms/block typ.  |
  
- Operating current

|                    |            |
|--------------------|------------|
| Read (50 ns cycle) | 10 mA typ. |
| Program (avg.)     | 10 mA typ. |
| Erase (avg.)       | 10 mA typ. |
| Standby            | 50 μA max  |
  
- Package
  - TC58NVG2D4BFT00 TSOP I 48-P-1220-0.50
  - (Weight: 0.53 g typ.)

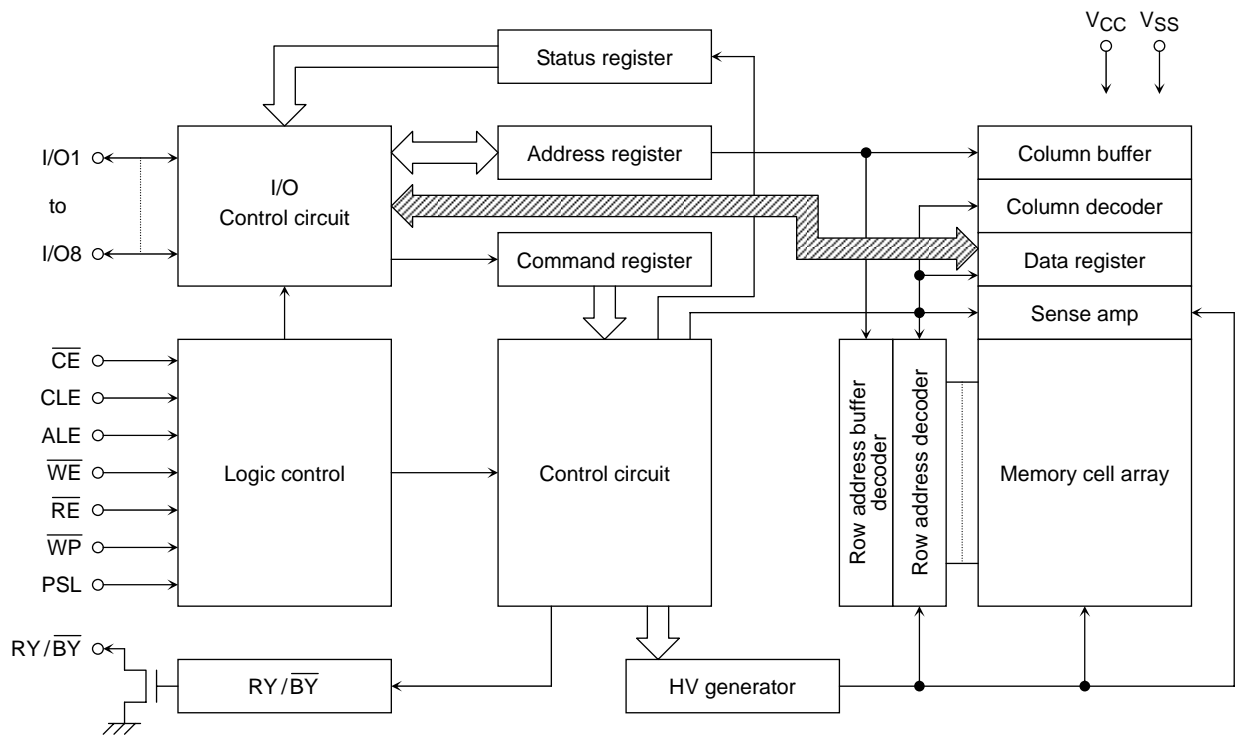
PIN ASSIGNMENT (TOP VIEW)



**PINNAMES**

| I/O1 to I/O8        | I/O port             |
|---------------------|----------------------|
| $\overline{CE}$     | Chip enable          |
| $\overline{WE}$     | Write enable         |
| $\overline{RE}$     | Read enable          |
| CLE                 | Command latch enable |
| ALE                 | Address latch enable |
| PSL                 | Power on select      |
| $\overline{WP}$     | Write protect        |
| RY/ $\overline{BY}$ | Ready/Busy           |
| V <sub>CC</sub>     | Power supply         |
| V <sub>SS</sub>     | Ground               |

**BLOCK DIAGRAM**



**ABSOLUTE MAXIMUM RATINGS**

| SYMBOL              | RATING                        | VALUE                                       | UNIT |
|---------------------|-------------------------------|---|------|
| V <sub>CC</sub>     | Power Supply Voltage          | -0.6 to 4.6                                 | V    |
| V <sub>IN</sub>     | Input Voltage                 | -0.6 to 4.6                                 | V    |
| V <sub>I/O</sub>    | Input /Output Voltage         | -0.6 V to V <sub>CC</sub> + 0.3 V (≤ 4.6 V) | V    |
| P <sub>D</sub>      | Power Dissipation             | 0.3   | W    |
| T <sub>SOLDER</sub> | Soldering Temperature (10 s)  | 260   | °C   |
| T <sub>STG</sub>    | Storage Temperature           | -55 to 150                                  | °C   |
| T <sub>a</sub>      | Operating Ambient Temperature | 0 to 70                                     | °C   |

**CAPACITANCE** \*(T<sub>a</sub> = 25°C, f = 1 MHz)

| SYMBOL           | PARAMETER | CONDITION              | MIN | MAX | UNIT |
|------------------|-----------|------------------------|-----|-----|------|
| C <sub>IN</sub>  | Input     | V <sub>IN</sub> = 0 V  | —   | 10  | pF   |
| C <sub>OUT</sub> | Output    | V <sub>OUT</sub> = 0 V | —   | 10  | pF   |

\* This parameter is periodically sampled and is not tested for every device.

**VALID BLOCKS**

| SYMBOL          | PARAMETER              | MIN  | TYP. | MAX  | UNIT   |
|-----------------|------------------------|------|------|------|--------|
| N <sub>VB</sub> | Number of Valid Blocks | 1968 | —    | 2048 | Blocks |

NOTE: The device occasionally contains unusable blocks. Refer to Application Note (13) toward the end of this document.  
 The first block (Block 0) is guaranteed to be a valid block at the time of shipment.  
 The minimum number of valid blocks is guaranteed over the lifetime.

**RECOMMENDED DC OPERATING CONDITIONS**

| SYMBOL          | PARAMETER                |  | MIN   | TYP. | MAX            | UNIT |
|-----------------|--------------------------|--|-------|------|----------------|------|
| V <sub>CC</sub> | Power Supply Voltage     |  | 2.7 V | —    | 3.6 V          | V    |
| V <sub>IH</sub> | High Level input Voltage | $2.7\text{ V} \leq V_{CC} \leq 3.6\text{ V}$ | 2.0   | —    | $V_{CC} + 0.3$ | V    |
| V <sub>IL</sub> | Low Level Input Voltage  | $2.7\text{ V} \leq V_{CC} \leq 3.6\text{ V}$ | -0.3* | —    | 0.8            | V    |

\* -2 V (pulse width lower than 20 ns)

**DC CHARACTERISTICS (Ta = 0 to 70 , V<sub>CC</sub> = 2.7 V to 3.6 V)**

| SYMBOL   | PARAMETER   | CONDITION   | MIN | TYP. | MAX | UNIT |
|--|---|---|-----|------|-----|------|
| I <sub>IL</sub>                                      | Input Leakage Current                                   | V <sub>IN</sub> = 0 V to V <sub>CC</sub>  | —   | —    | ±10 | μA   |
| I <sub>LO</sub>                                      | Output Leakage Current                                  | V <sub>OUT</sub> = 0 V to V <sub>CC</sub>   | —   | —    | ±10 | μA   |
| I <sub>CC0</sub> *                                   | Power On Reset Current                                  | PSL = GND or NU   | —   | 10   | 30  | mA   |
|  |   | PSL = V <sub>CC</sub> , FFh command input after Power On  | —   | 10   | 30  |      |
| I <sub>CC01</sub>                                    | Serial Read Current                                     | $\overline{CE} = V_{IL}$ , I <sub>OUT</sub> = 0 mA, t <sub>cycle</sub> = 50 ns                                  | —   | 10   | 30  | mA   |
| I <sub>CC02</sub>                                    | Programming Current                                     | —   | —   | 10   | 30  | mA   |
| I <sub>CC03</sub>                                    | Erasing Current   | —   | —   | 10   | 30  | mA   |
| I <sub>CCS1</sub>                                    | Standby Current   | $\overline{CE} = V_{IH}$ , $\overline{WP} = 0\text{ V}/V_{CC}$ ,<br>PSL = 0 V/V <sub>CC</sub> /NU               | —   | —    | 1   | mA   |
| I <sub>CCS2</sub>                                    | Standby Current   | $\overline{CE} = V_{CC} - 0.2\text{ V}$ , $\overline{WP} = 0\text{ V}/V_{CC}$ ,<br>PSL = 0V/V <sub>CC</sub> /NU | —   | 10   | 50  | μA   |
| V <sub>OH</sub>                                      | High Level Output Voltage                               | I <sub>OH</sub> = -0.4 mA (2.7 V ≤ V <sub>CC</sub> ≤ 3.6 V)   | 2.4 | —    | —   | V    |
| V <sub>OL</sub>                                      | Low Level Output Voltage                                | I <sub>OL</sub> = 2.1 mA (2.7 V ≤ V <sub>CC</sub> ≤ 3.6 V)  | —   | —    | 0.4 | V    |
| I <sub>OL</sub><br>(R <sub>Y</sub> /B <sub>Y</sub> ) | Output current of R <sub>Y</sub> /B <sub>Y</sub><br>pin | V <sub>OL</sub> = 0.4 V (2.7 V ≤ V <sub>CC</sub> ≤ 3.6 V)   | —   | 8    | —   | mA   |

\* Refer to application note (2) for detail

**AC CHARACTERISTICS AND RECOMMENDED OPERATING CONDITIONS**

(Ta = 0 to 70 , Vcc = 2.7 V to 3.6 V)

| SYMBOL               | PARAMETER  | MIN | MAX        | UNIT | NOTES |
|----------------------|--|-----|------------|------|-------|
| t <sub>CLS</sub>     | CLE Setup Time   | 0   | —          | ns   |       |
| t <sub>CLH</sub>     | CLE Hold Time  | 10  | —          | ns   |       |
| t <sub>CS</sub>      | $\overline{CE}$ Setup Time                             | 0   | —          | ns   |       |
| t <sub>CH</sub>      | $\overline{CE}$ Hold Time                              | 10  | —          | ns   |       |
| t <sub>WP</sub>      | Write Pulse Width                                      | 25  | —          | ns   |       |
| t <sub>ALS</sub>     | ALE Setup Time   | 0   | —          | ns   |       |
| t <sub>ALH</sub>     | ALE Hold Time  | 10  | —          | ns   |       |
| t <sub>DS</sub>      | Data Setup Time  | 20  | —          | ns   |       |
| t <sub>DH</sub>      | Data Hold Time   | 10  | —          | ns   |       |
| t <sub>WC</sub>      | Write Cycle Time                                       | 50  | —          | ns   |       |
| t <sub>WH</sub>      | $\overline{WE}$ High Hold Time                         | 15  | —          | ns   |       |
| t <sub>WW</sub>      | $\overline{WP}$ High to $\overline{WE}$ Low            | 100 | —          | ns   |       |
| t <sub>RR</sub>      | Ready to $\overline{RE}$ Falling Edge                  | 20  | —          | ns   |       |
| t <sub>RW</sub>      | Ready to $\overline{WE}$ Falling Edge                  | 20  | —          | ns   |       |
| t <sub>RP</sub>      | Read Pulse Width                                       | 35  | —          | ns   |       |
| t <sub>RC</sub>      | Read Cycle Time  | 50  | —          | ns   |       |
| t <sub>REA</sub>     | $\overline{RE}$ Access Time                            | —   | 35         | ns   |       |
| t <sub>CEA</sub>     | $\overline{CE}$ Access Time                            | —   | 45         | ns   |       |
| t <sub>CLEA</sub>    | CLE Access Time  | —   | 45         | ns   |       |
| t <sub>ALEA</sub>    | ALE Access Time  | —   | 45         | ns   |       |
| t <sub>OH</sub>      | Data Output Hold Time                                  | 10  | —          | ns   |       |
| t <sub>RHZ</sub>     | $\overline{RE}$ High to Output High Impedance          | —   | 30         | ns   |       |
| t <sub>CHZ</sub>     | $\overline{CE}$ High to Output High Impedance          | —   | 20         | ns   |       |
| t <sub>REH</sub>     | $\overline{RE}$ High Hold Time                         | 15  | —          | ns   |       |
| t <sub>IR</sub>      | Output-High-impedance-to- $\overline{RE}$ Falling Edge | 0   | —          | ns   |       |
| t <sub>RHW</sub>     | $\overline{RE}$ High to $\overline{WE}$ Low            | 30  | —          | ns   |       |
| t <sub>WHC</sub>     | $\overline{WE}$ High to $\overline{CE}$ Low            | 30  | —          | ns   |       |
| t <sub>WHR</sub>     | $\overline{WE}$ High to $\overline{RE}$ Low            | 30  | —          | ns   |       |
| t <sub>R</sub>       | Memory Cell Array to Starting Address                  | —   | 50         | μs   |       |
| t <sub>DCBSYR1</sub> | Data Cache Busy in Read Cache (following 31h and 3Fh)  | —   | 50         | μs   |       |
| t <sub>DCBSYR2</sub> | Data Cache Busy in Page Copy (following 3Ah)           | —   | 55         | μs   |       |
| t <sub>WB</sub>      | $\overline{WE}$ High to Busy                           | —   | 200        | ns   |       |
| t <sub>RST</sub>     | Device Reset Time (Ready/Read/Program/Erase)           | —   | 6/6/10/500 | μs   |       |

**AC TEST CONDITIONS**

| PARAMETER                      | CONDITION                                    |
|--------------------------------|--|
|                                | $2.7\text{ V} \leq V_{CC} \leq 3.6\text{ V}$ |
| Input level                    | 2.4 V, 0.4 V                                 |
| Input pulse rise and fall time | 3ns  |
| Input comparison level         | 1.5 V, 1.5 V                                 |
| Output data comparison level   | 1.5 V, 1.5 V                                 |
| Output load                    | $C_L (100\text{ pF}) + 1\text{ TTL}$         |

Note: Busy to ready time depends on the pull-up resistor tied to the  $\overline{RY}/\overline{BY}$  pin.  
 (Refer to Application Note (9) toward the end of this document.)

**PROGRAMMING AND ERASING CHARACTERISTICS**

( $T_a = 0$  to  $70$  ,  $V_{CC} = 2.7\text{ V}$  to  $3.6\text{ V}$ )

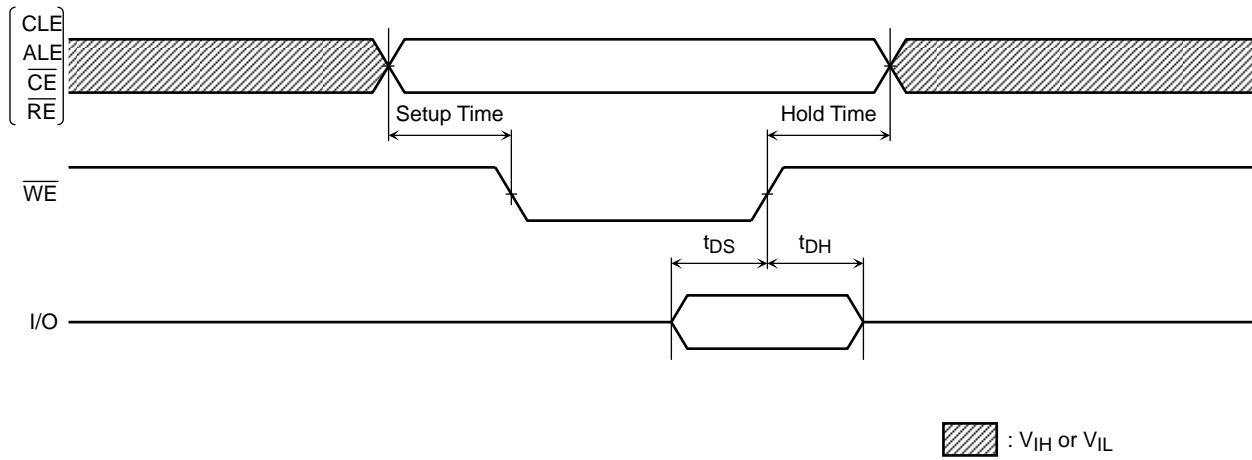
| SYMBOL              | PARAMETER   | MIN | TYP. | MAX  | UNIT | NOTES |
|---------------------|---|-----|------|------|------|-------|
| t <sub>PROG</sub>   | Average Programming Time                          | —   | 800  | 2000 | μs   |       |
| t <sub>DCBSYW</sub> | Data Cache Busy Time in Write Cache               | —   | —    | 2000 | μs   | (2)   |
| t <sub>DCMPW</sub>  | Data Cache Busy Time in Multi page Programming    | —   | 5    | 10   | μs   |       |
| N                   | Number of Partial Program Cycles in the Same Page | —   | —    | —    |      | (1)   |
| t <sub>BERASE</sub> | Block Erasing Time                                | —   | 3    | 10   | ms   |       |

(1) Refer to Application Note (12) toward the end of this document.

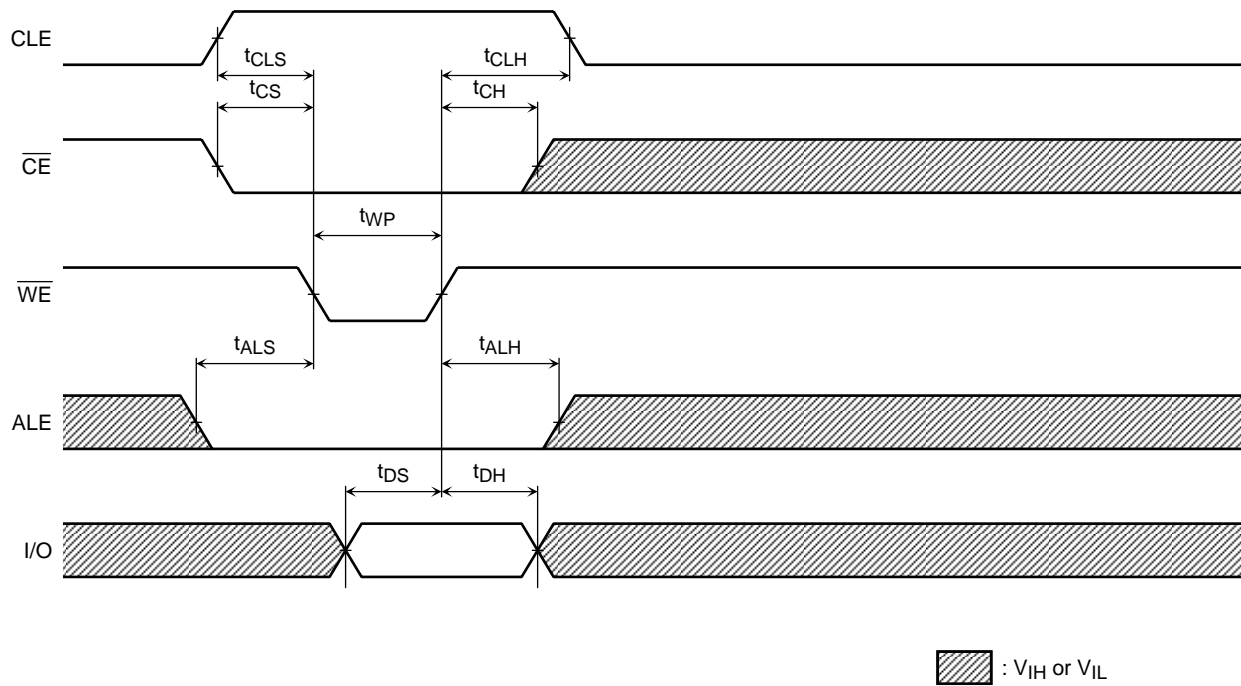
(2) t<sub>DCBSYW</sub> depends on the timing between internal programming time and data in time.

**TIMING DIAGRAMS**

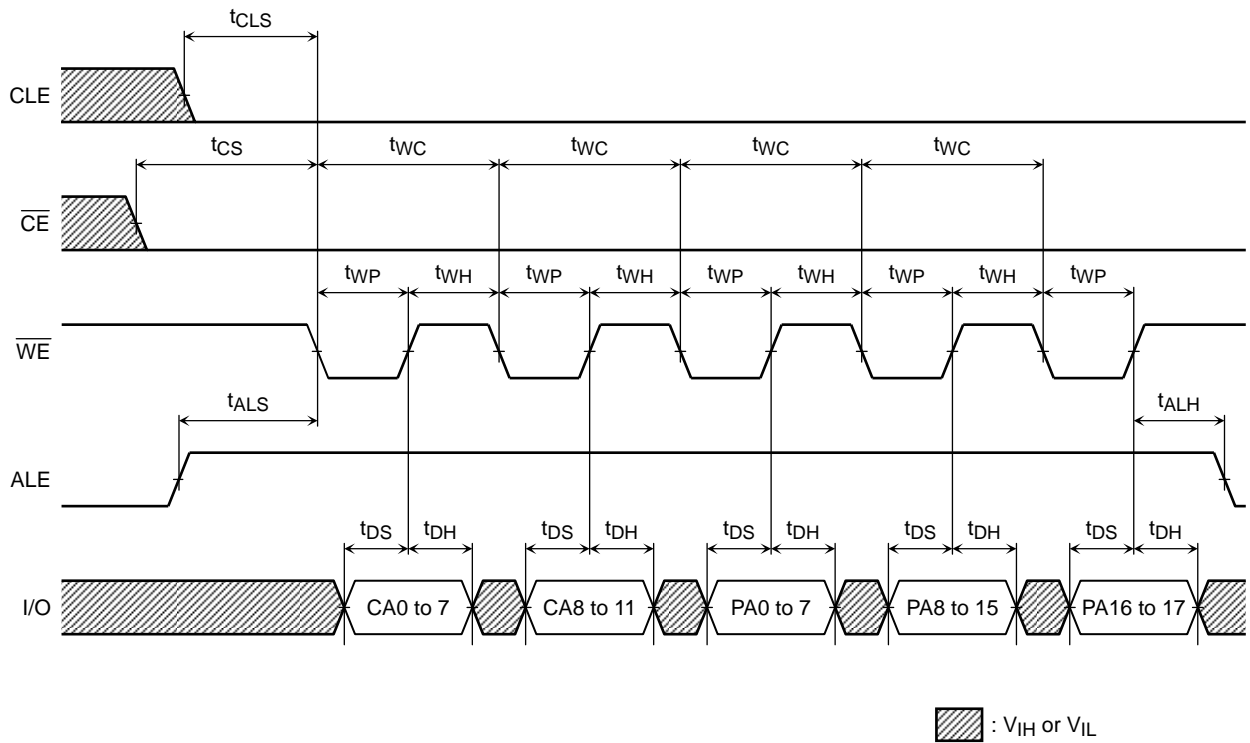
Latch Timing Diagram for Command/Address/Data



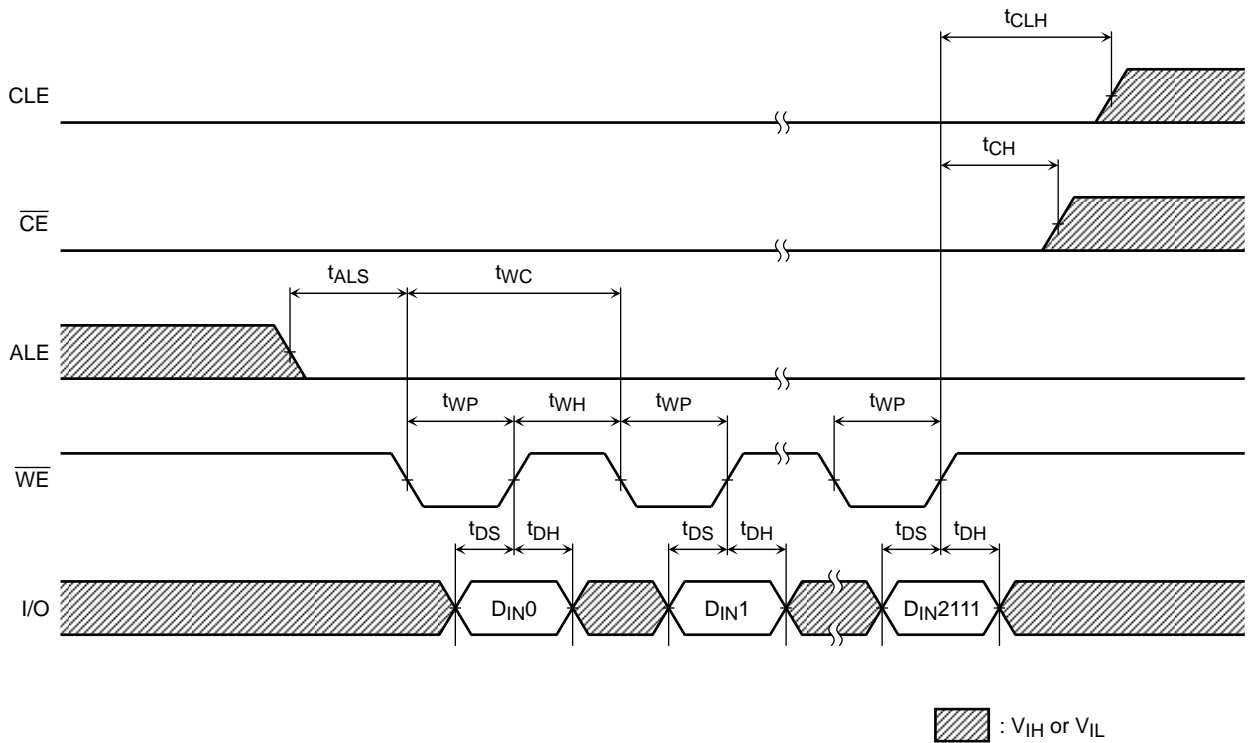
Command Input Cycle Timing Diagram



Address Input Cycle Timing Diagram

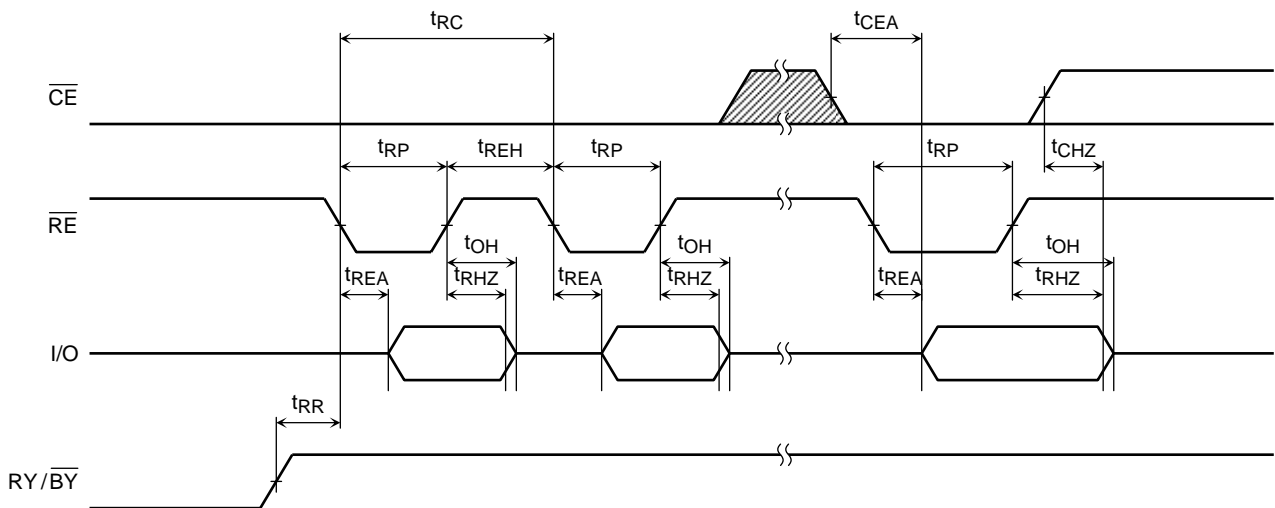


Data Input Cycle Timing Diagram

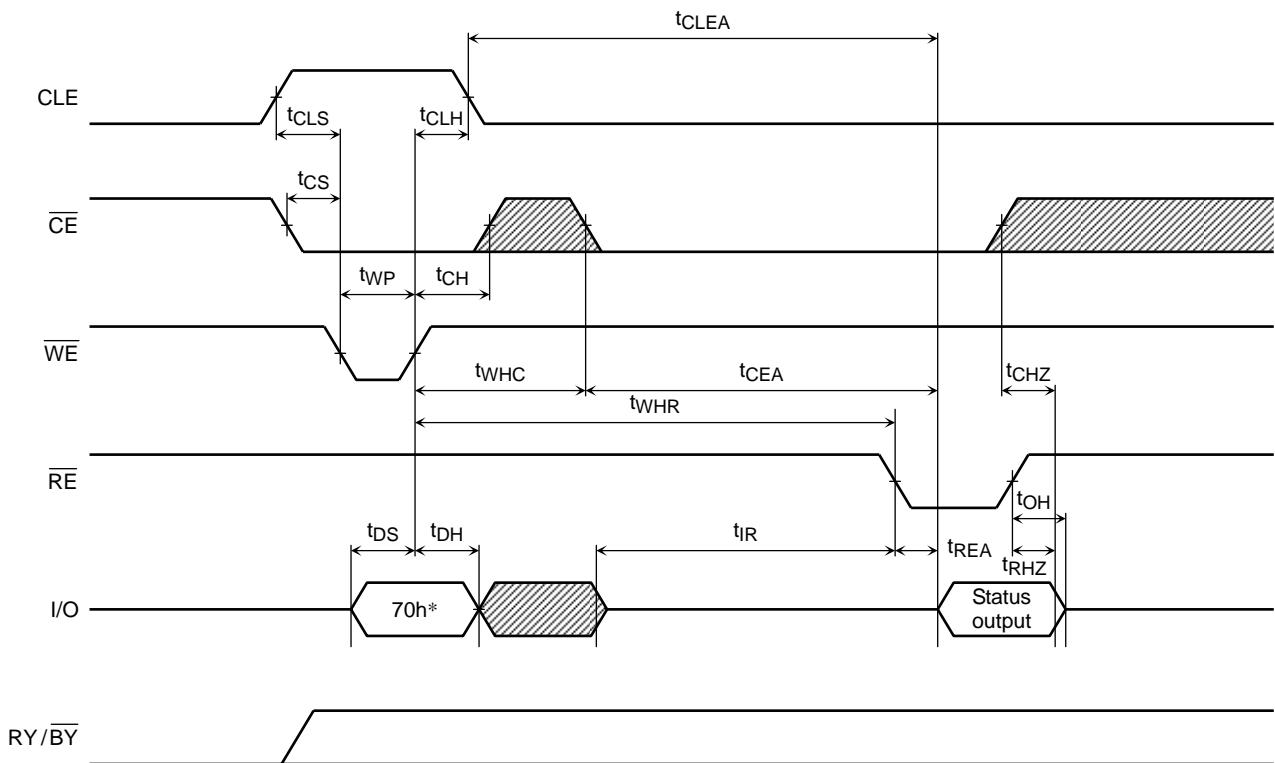




Serial Read Cycle Timing Diagram



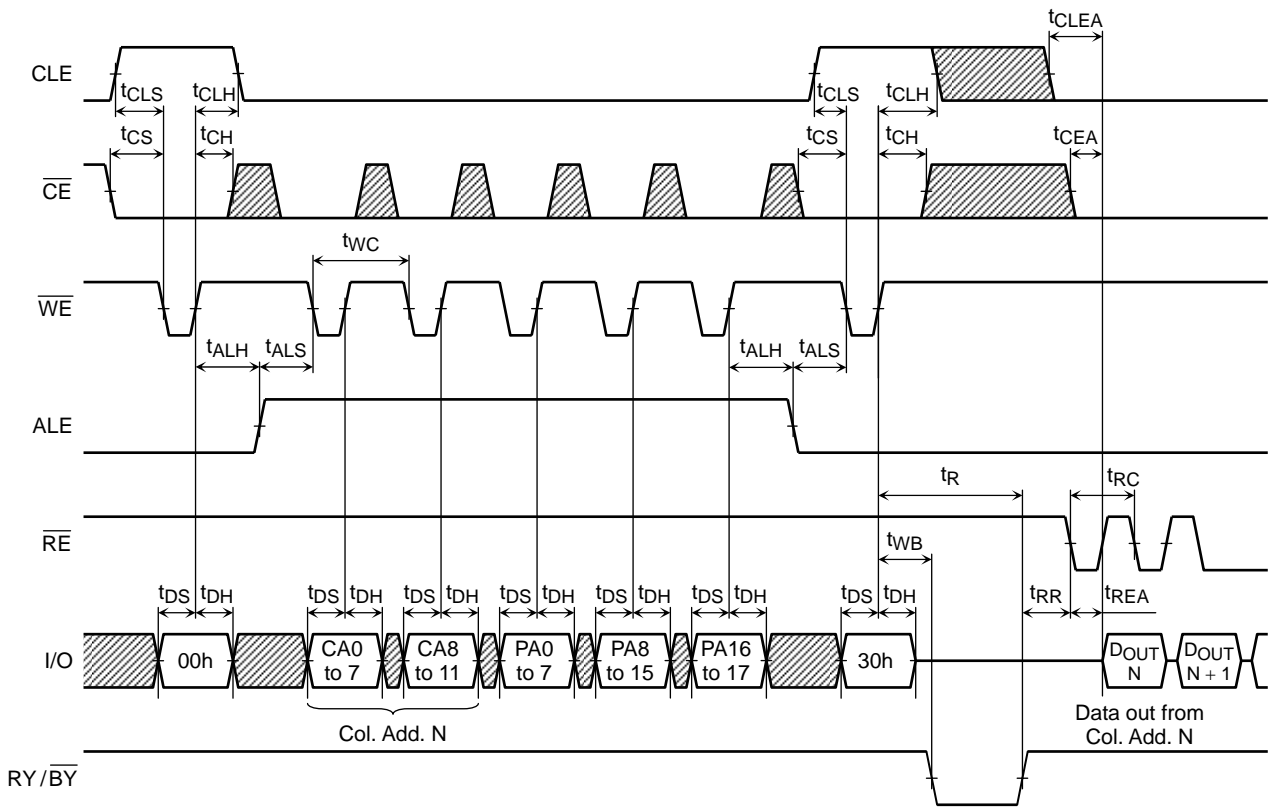
Status Read Cycle Timing Diagram



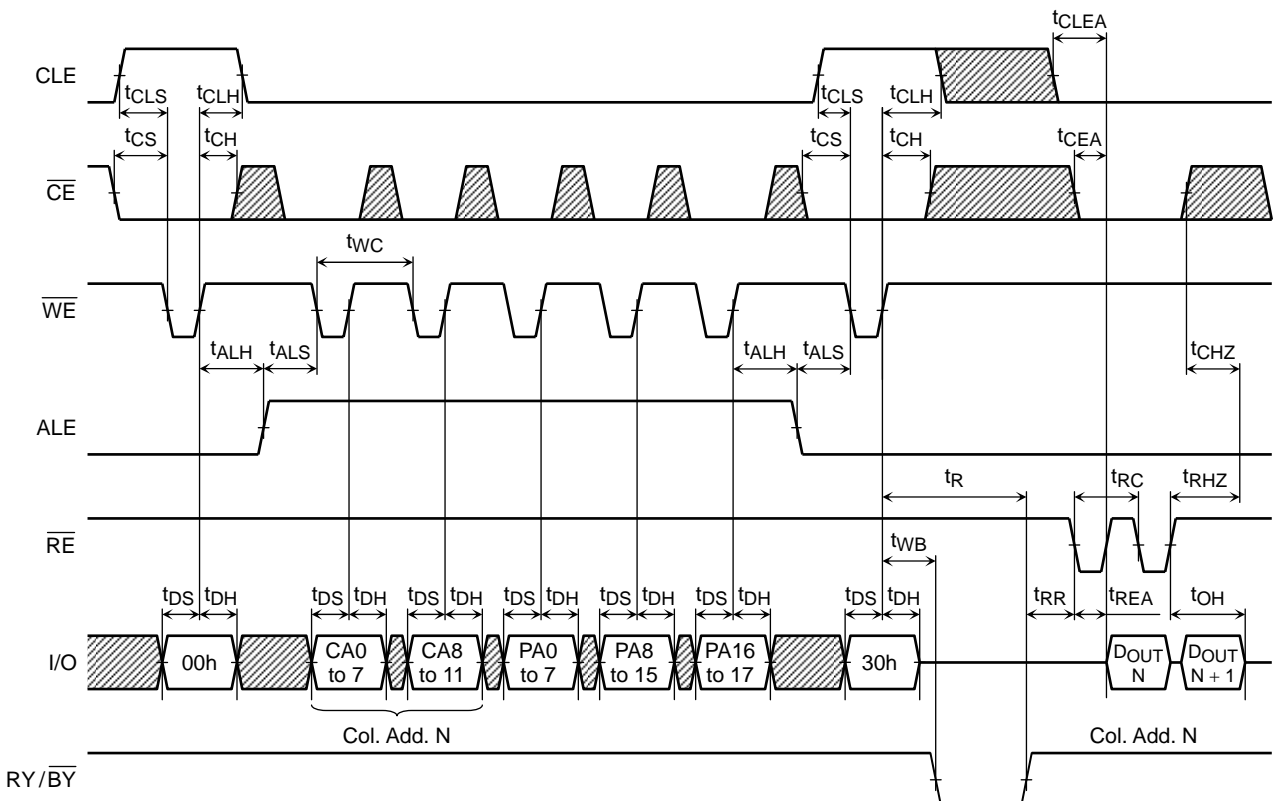
\*: 70h represents the hexadecimal number

 :  $V_{IH}$  or  $V_{IL}$

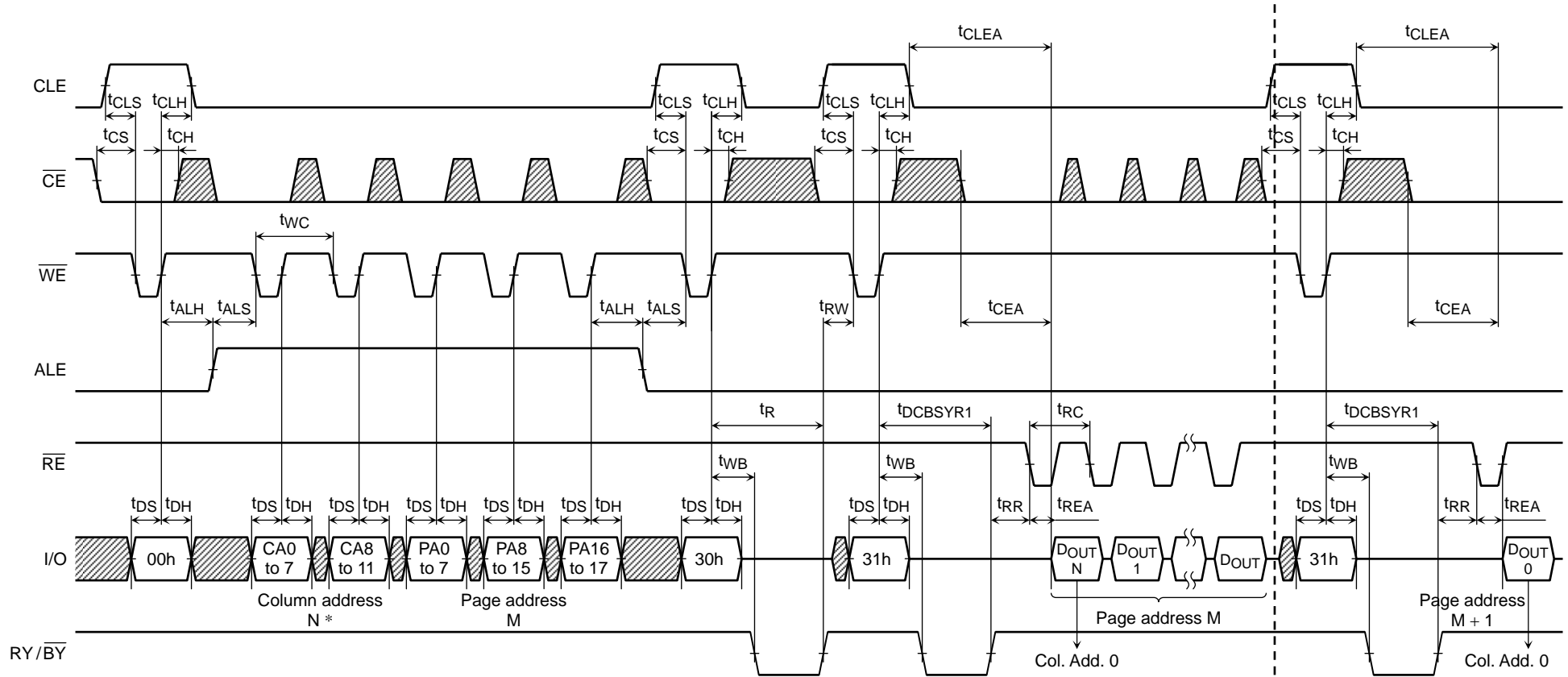
Read Cycle Timing Diagram



Read Cycle Timing Diagram: When Interrupted by  $\overline{CE}$



Read Cycle with Data Cache Timing Diagram (1/2)

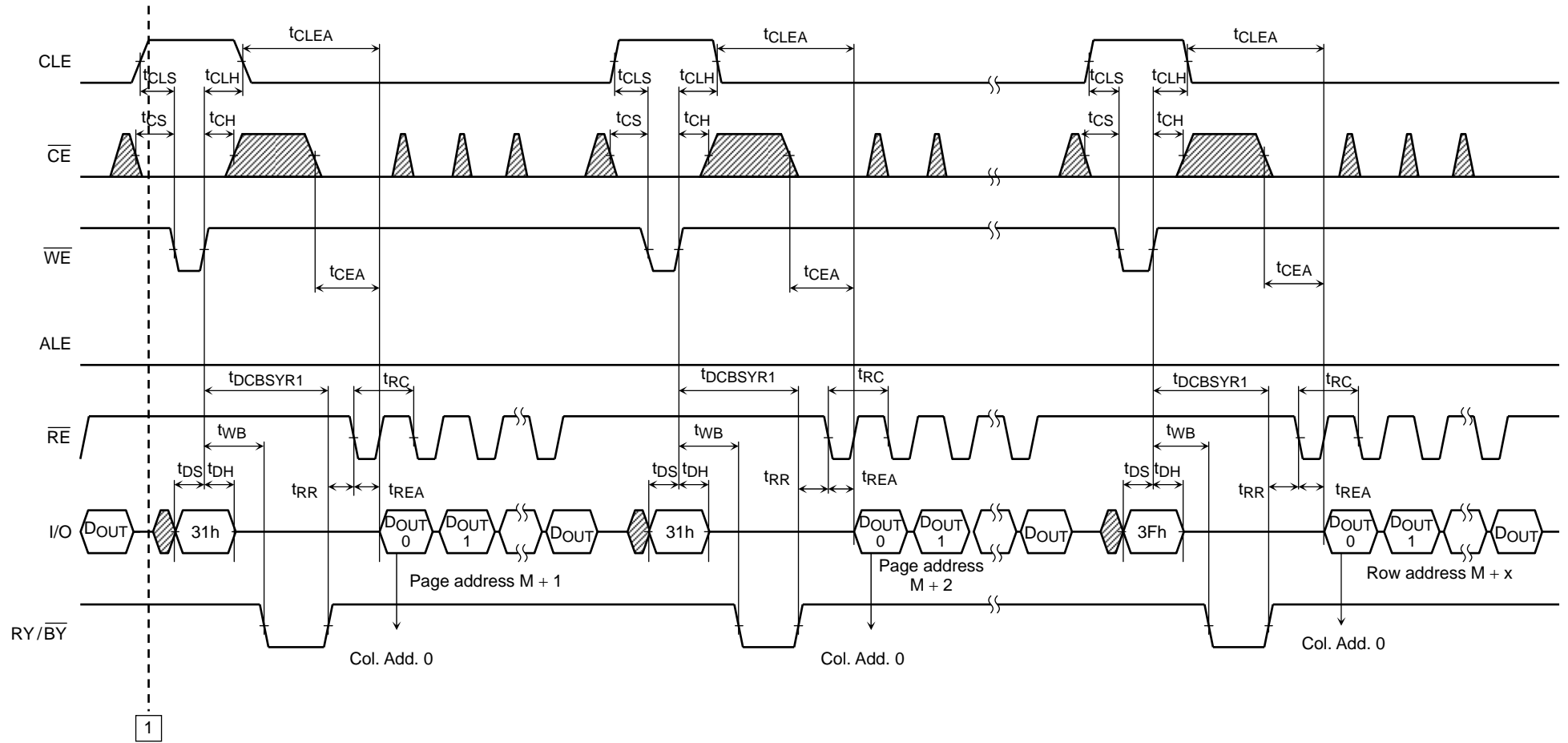


\* The column address will be reset to 0 by the 31h command input.

1

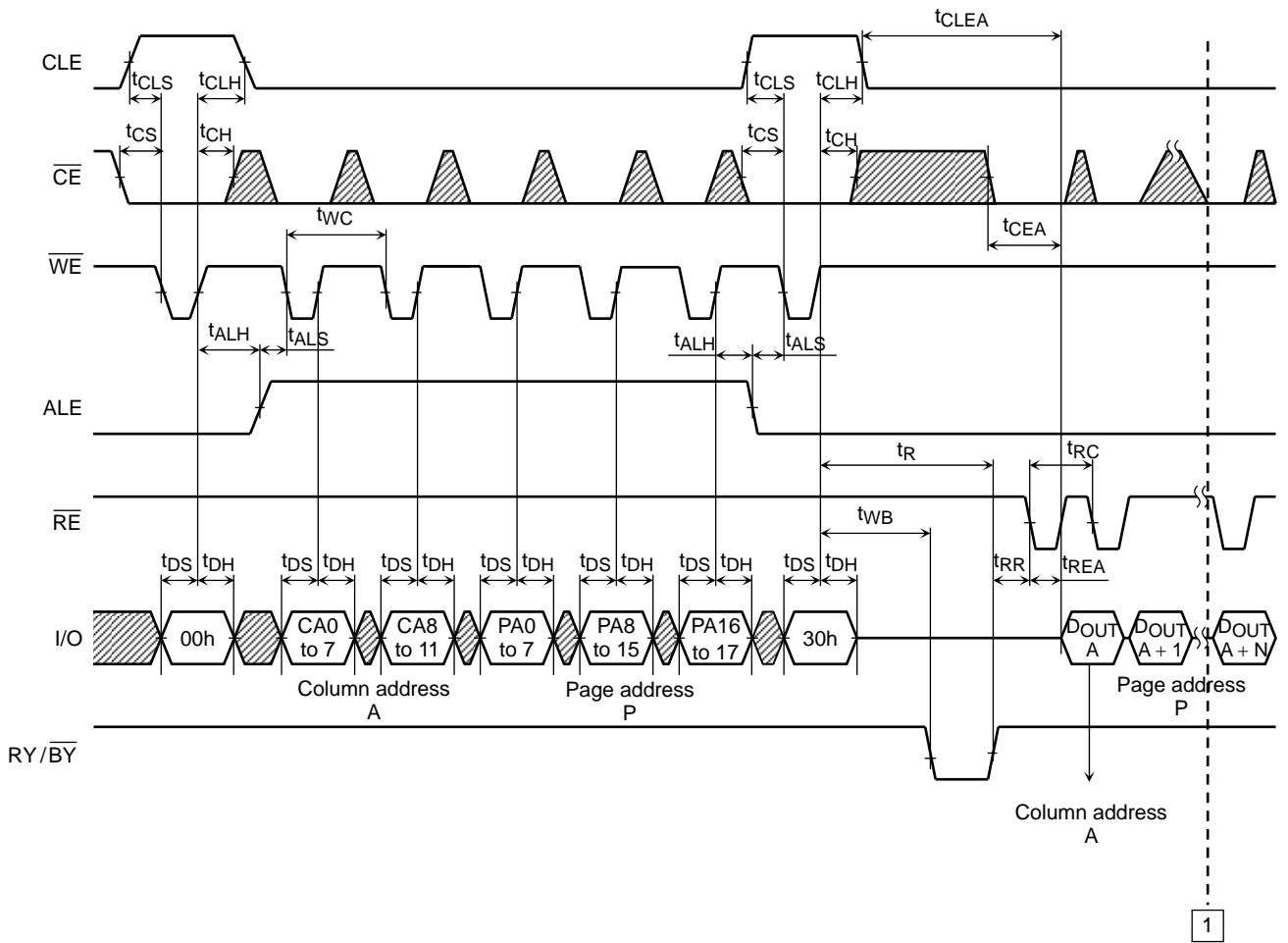
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Read Cycle with Data Cache Timing Diagram (2/2)



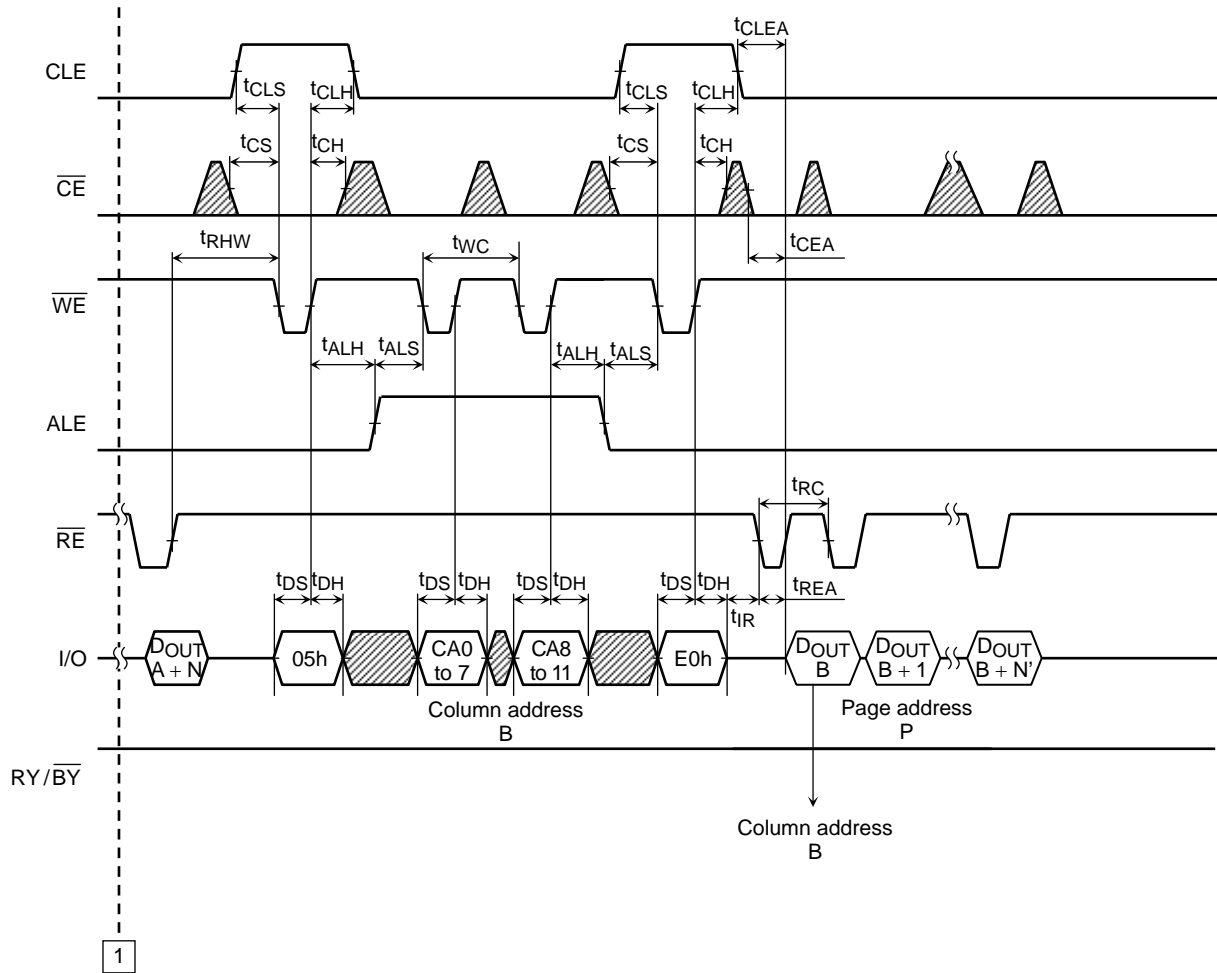
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Column Address Change in Read Cycle Timing Diagram (1/2)



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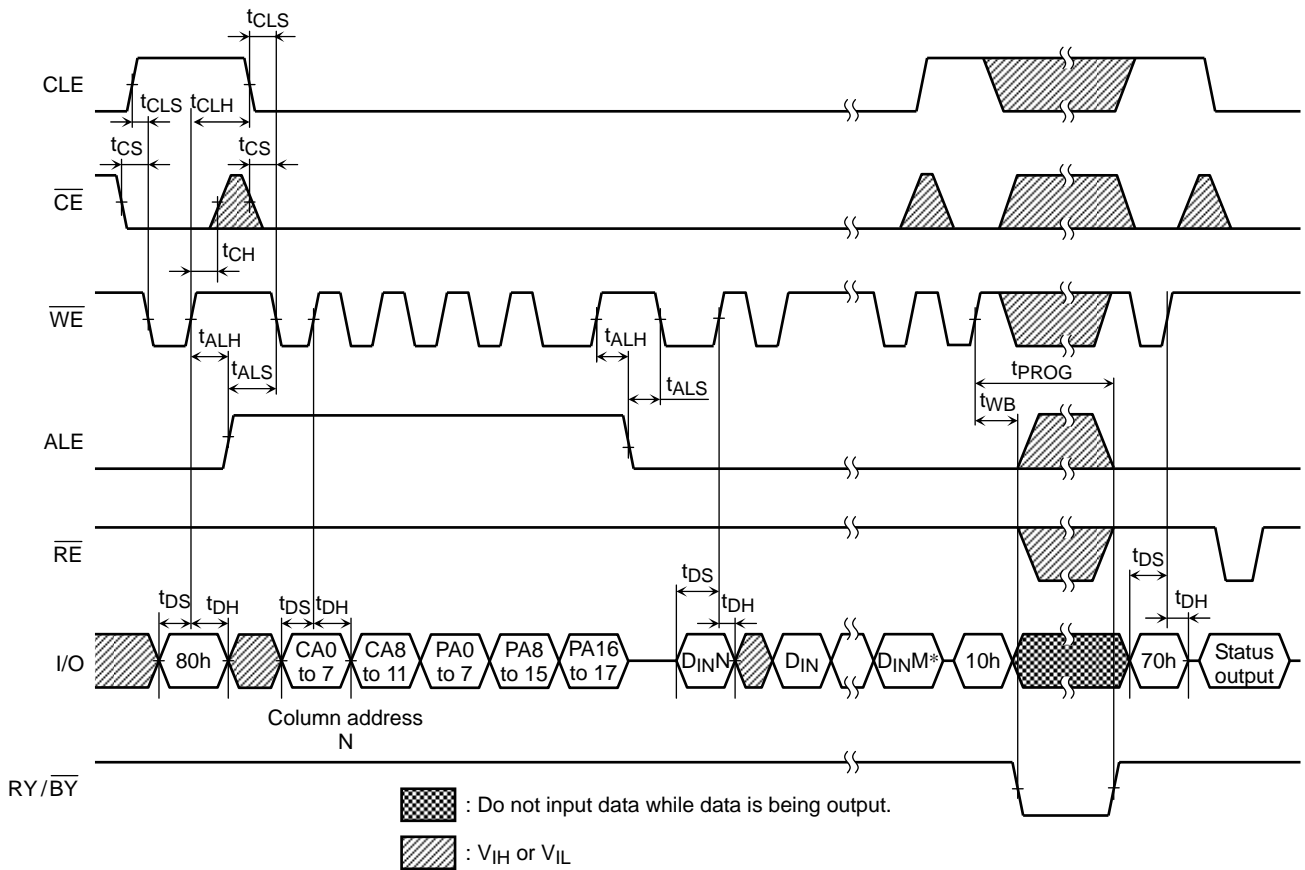
Column Address Change in Read Cycle Timing Diagram (2/2)



1

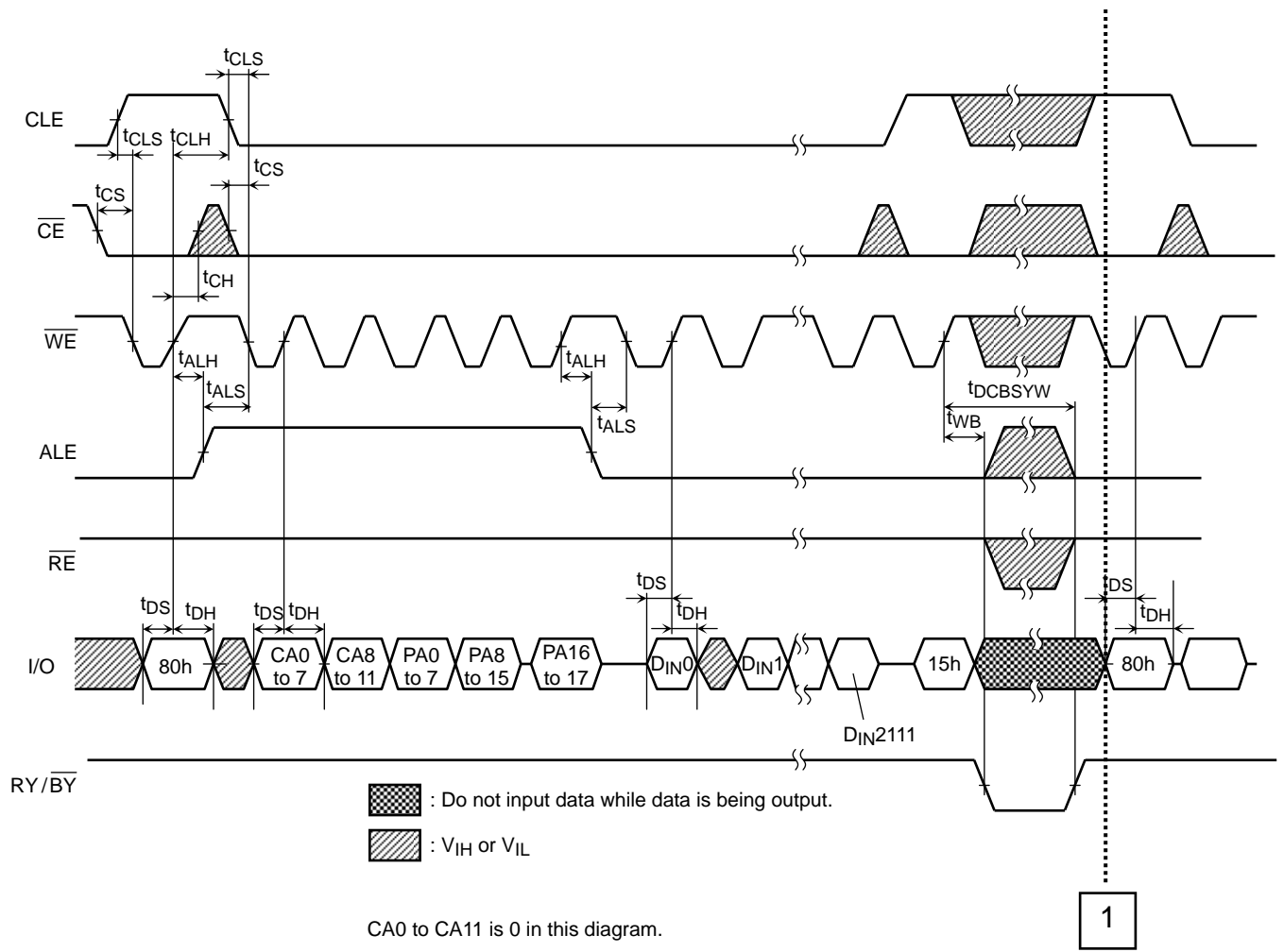
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Auto-Program Operation Timing Diagram



\*) M: up to 2112 (byte input data for ×8 device).

Auto-Program Operation with Data Cache Timing Diagram (1/3)

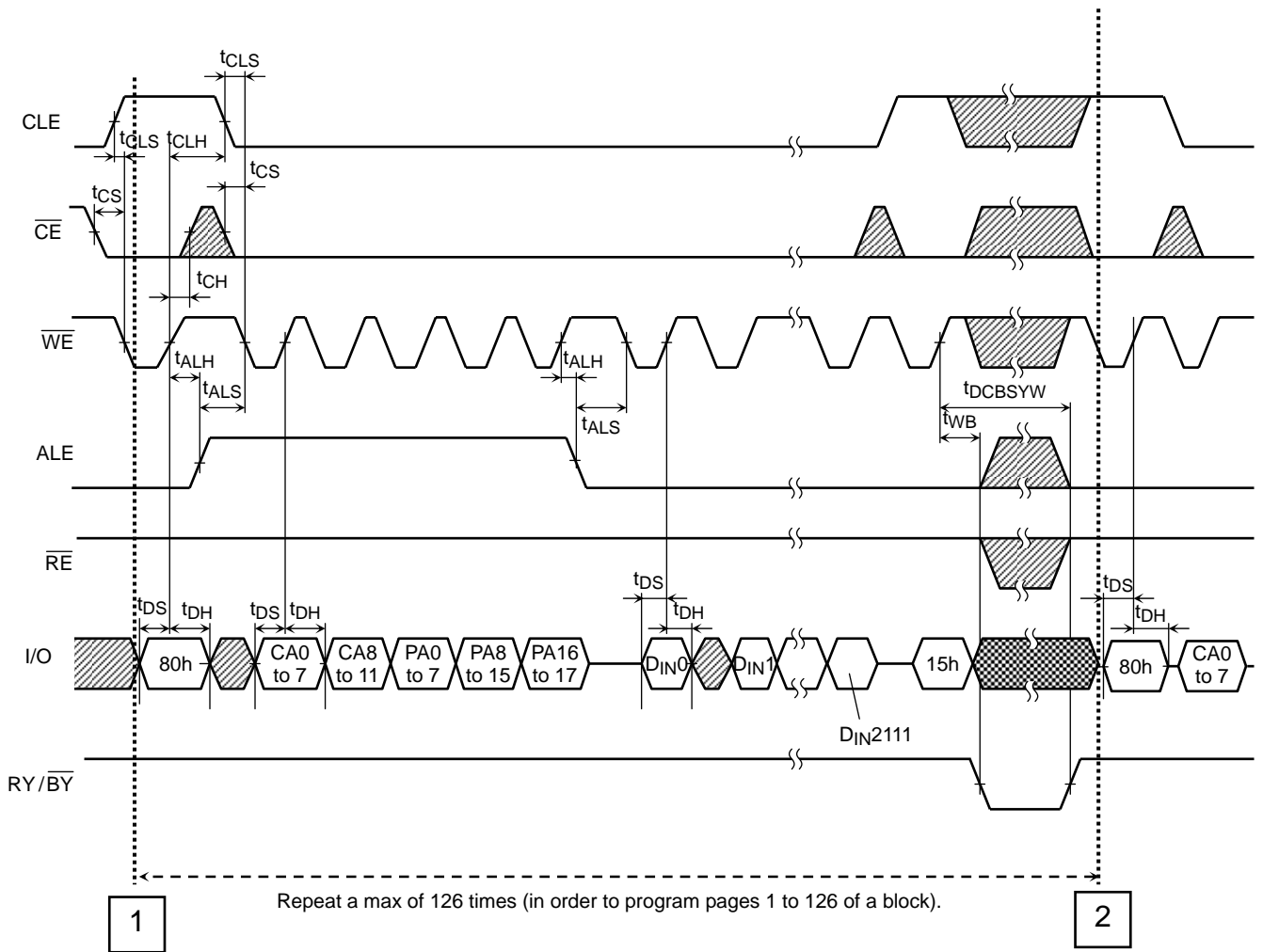


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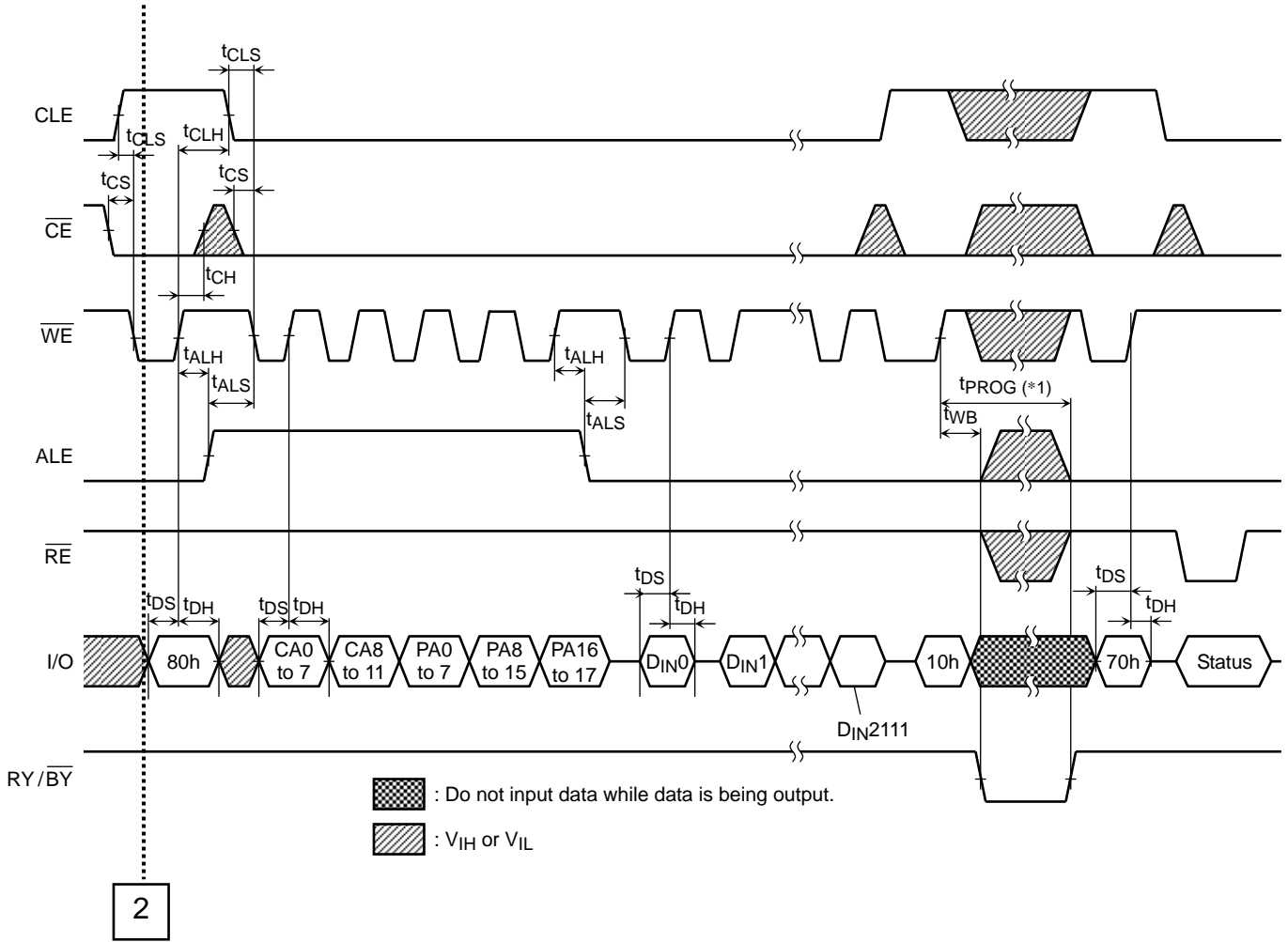
(Note) Make sure to terminate the operation with 80h-10h- command sequence.  
 If the operation is terminated by 80h-15h command sequence, monitor I/O 6 (Ready / Busy) by issuing Status Read command (70h) and make sure the previous page program operation is completed. If the page program operation is completed issue FFh reset before next operation.



Auto-Program Operation with Data Cache Timing Diagram (2/3)



Auto-Program Operation with Data Cache Timing Diagram (3/3)



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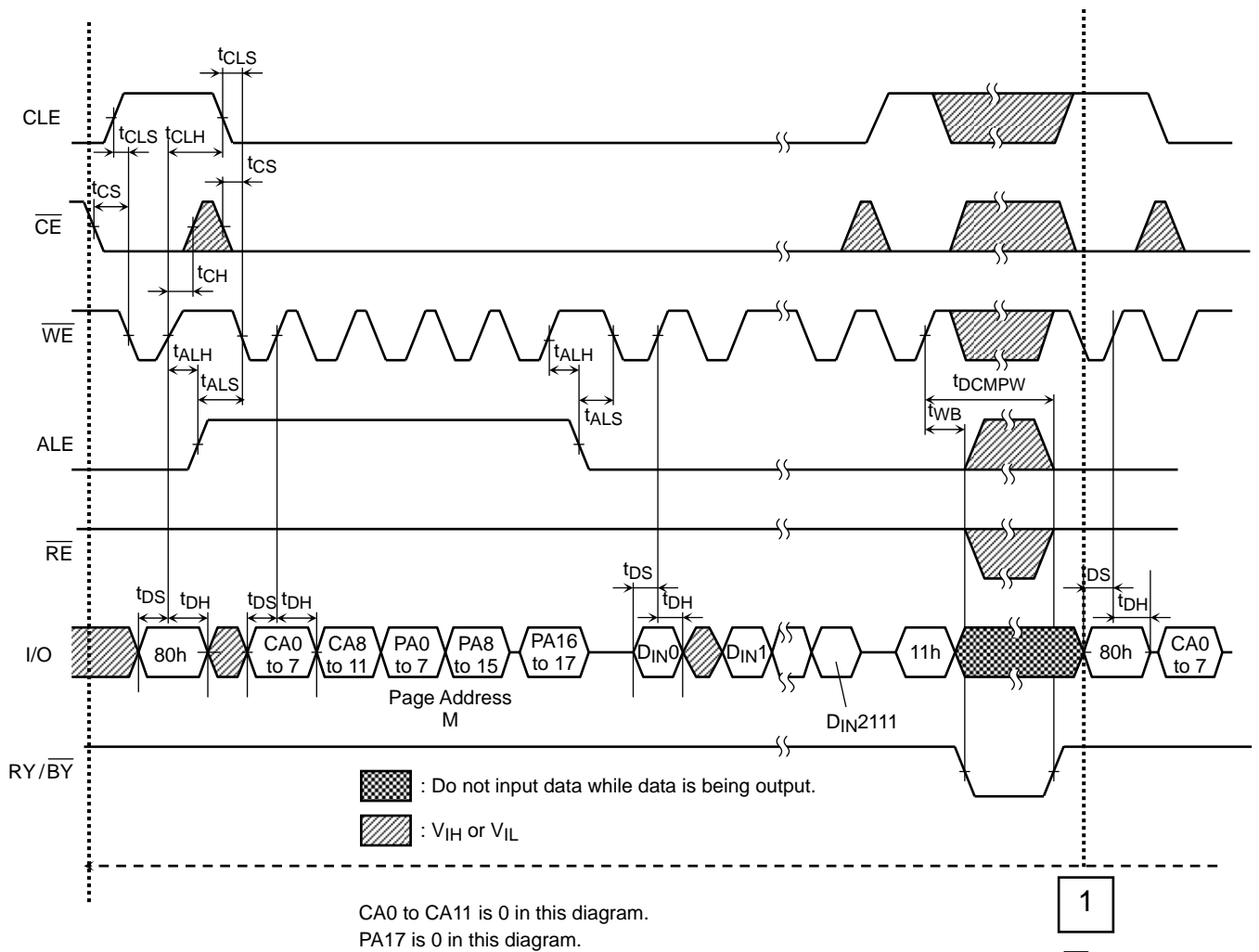
(\*1)  $t_{PROG}$ : Since the last page programming by 10h command is initiated after the previous cache program, the  $t_{PROG}$  during cache programming is given by the following equation.

$$t_{PROG} = t_{PROG} \text{ of the last page} + t_{PROG} \text{ of the previous page} - A$$

$$A = (\text{command input cycle} + \text{address input cycle} + \text{data input cycle time of the last page})$$

If "A" exceeds the  $t_{PROG}$  of previous page,  $t_{PROG}$  of the last page is 2000  $\mu$ s max.

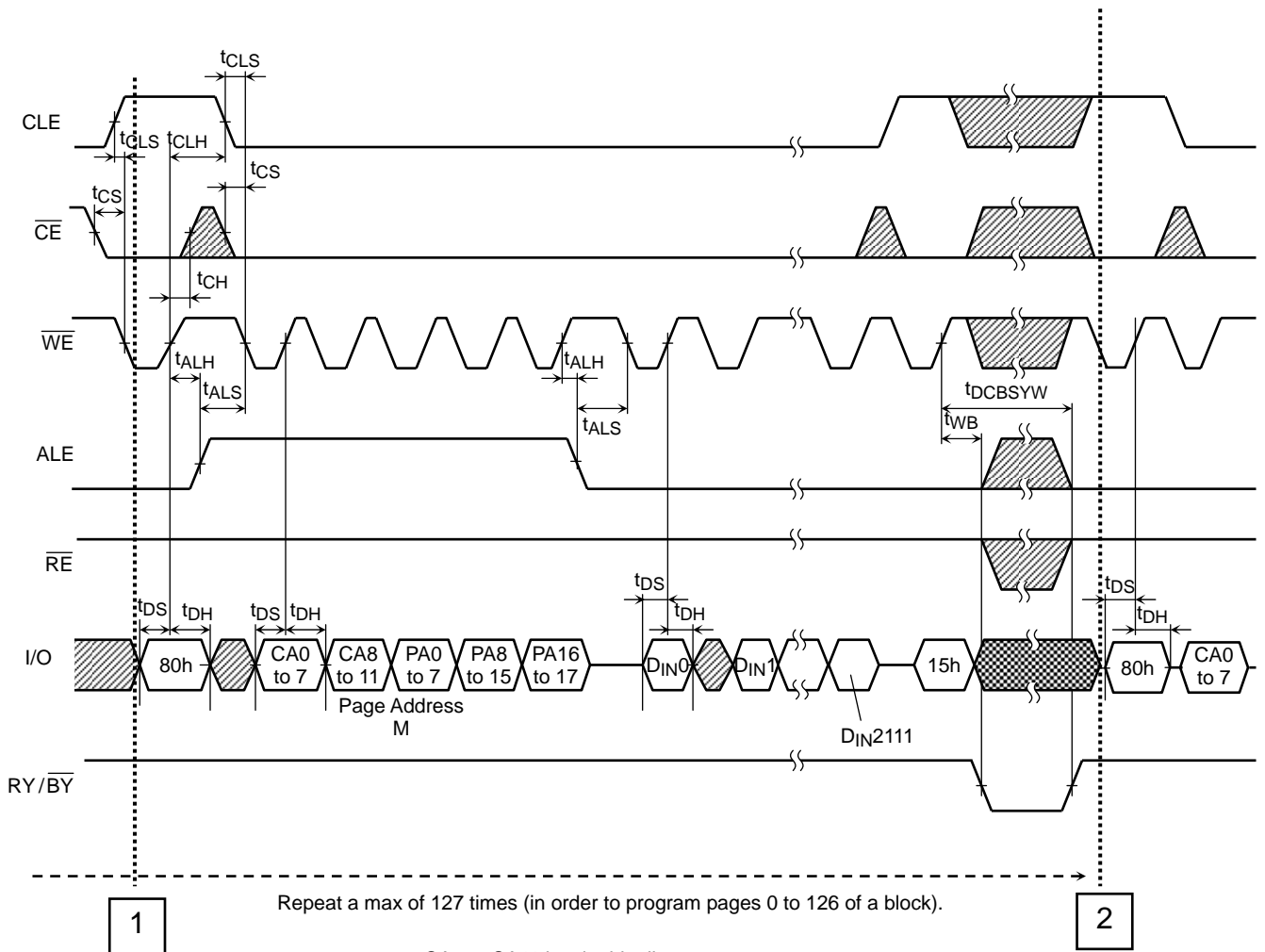
Multi-Page Program Operation with Data Cache Timing Diagram (1/4)



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(Note) Make sure to terminate the operation with 80h-10h- command sequence.  
If the operation is terminated by 80h-15h command sequence, monitor I/O 6 (Ready / Busy) by issuing Status Read command (70h) and make sure the previous page program operation is completed. If the page program operation is completed issue FFh reset before next operation.

Multi-Page Program Operation with Data Cache Timing Diagram (2/4)

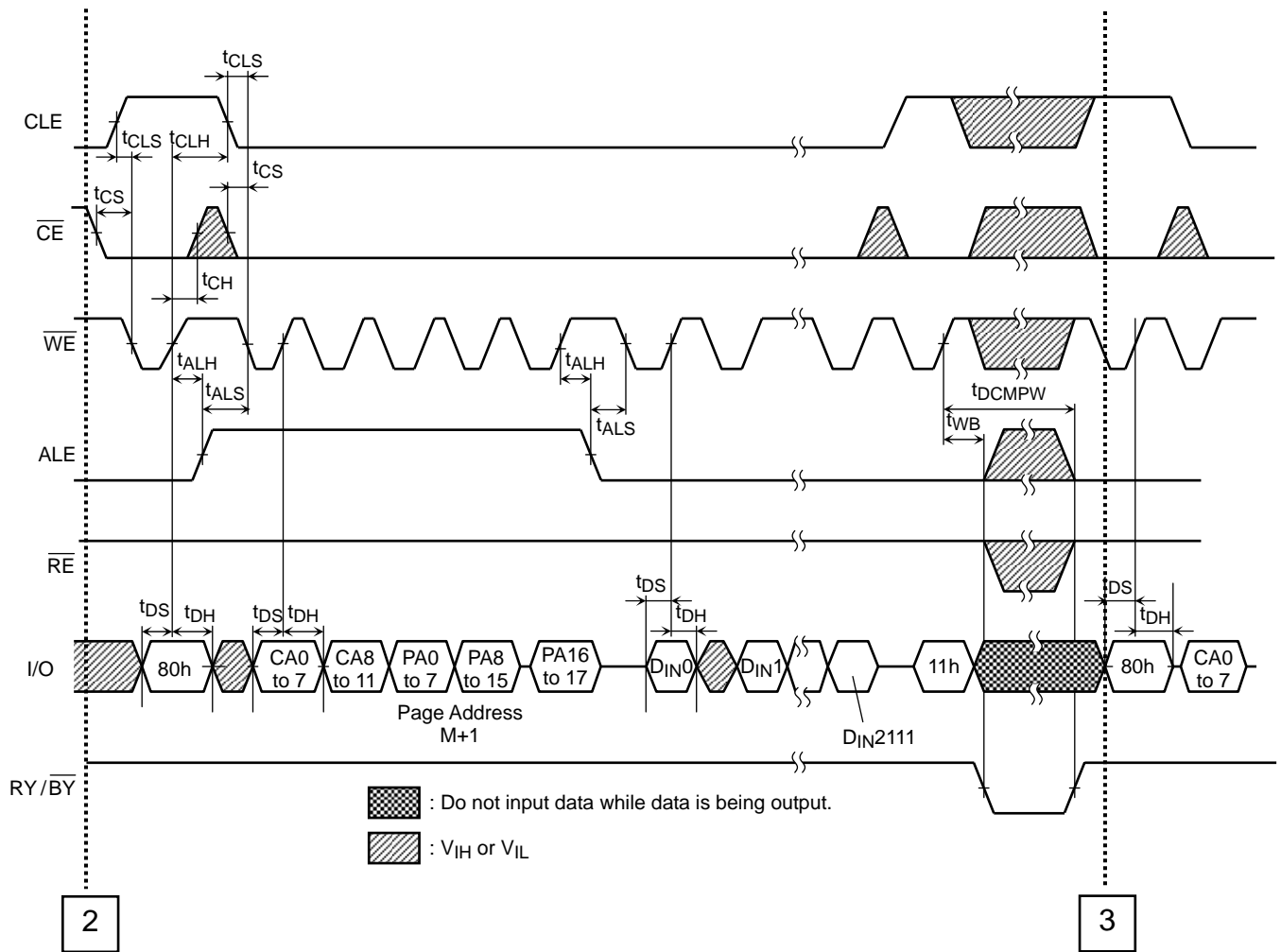


CA0 to CA11 is 0 in this diagram.  
PA17 is 1 in this diagram.

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- : Do not input data while data is being output.
- :  $V_{IH}$  or  $V_{IL}$

Multi-Page Program Operation with Data Cache Timing Diagram (3/4)



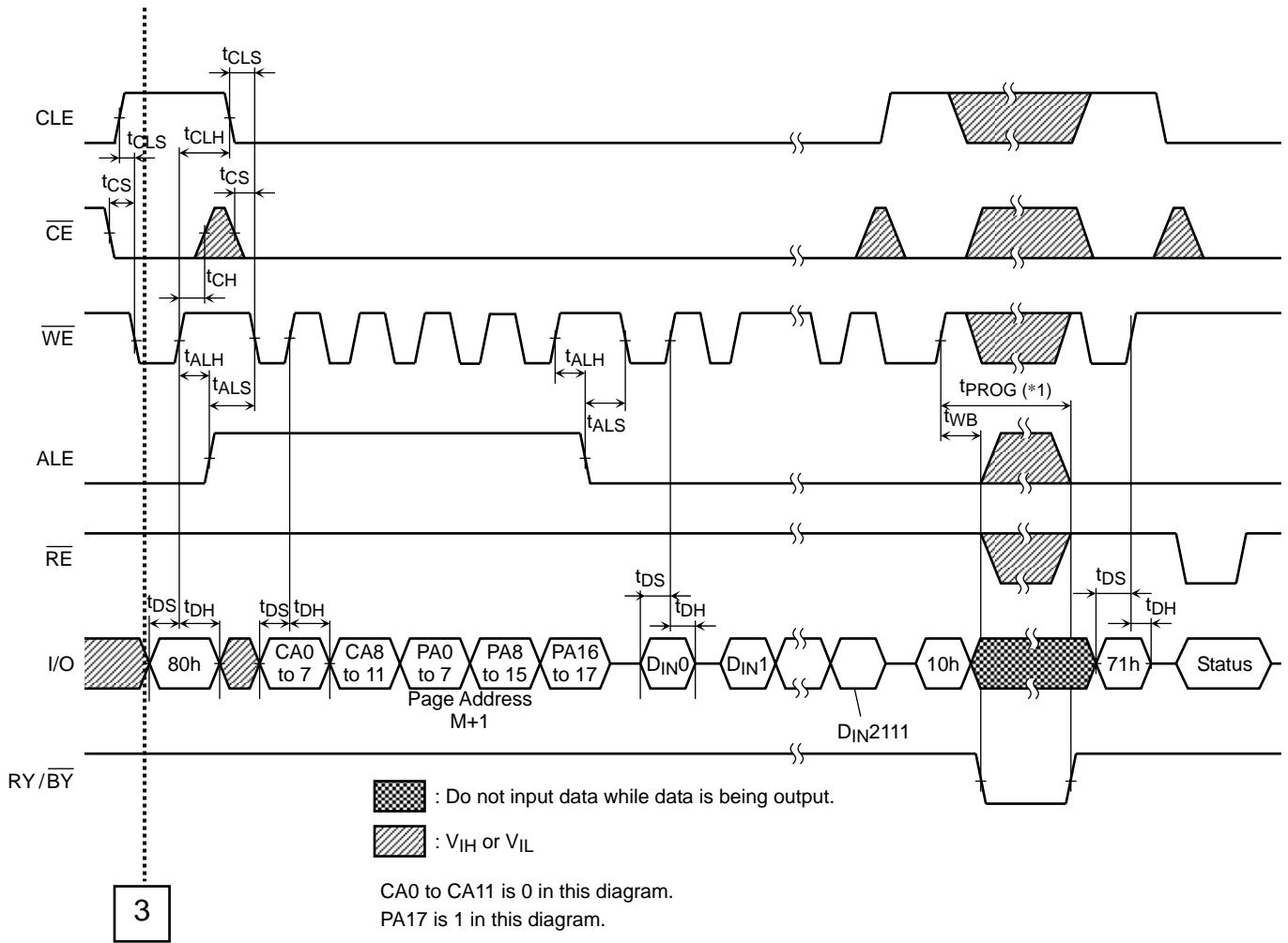
2

3

CA0 to CA11 is 0 in this diagram.  
 PA17 is 0 in this diagram.

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Multi-Page Program Operation with Data Cache Timing Diagram (4/4)



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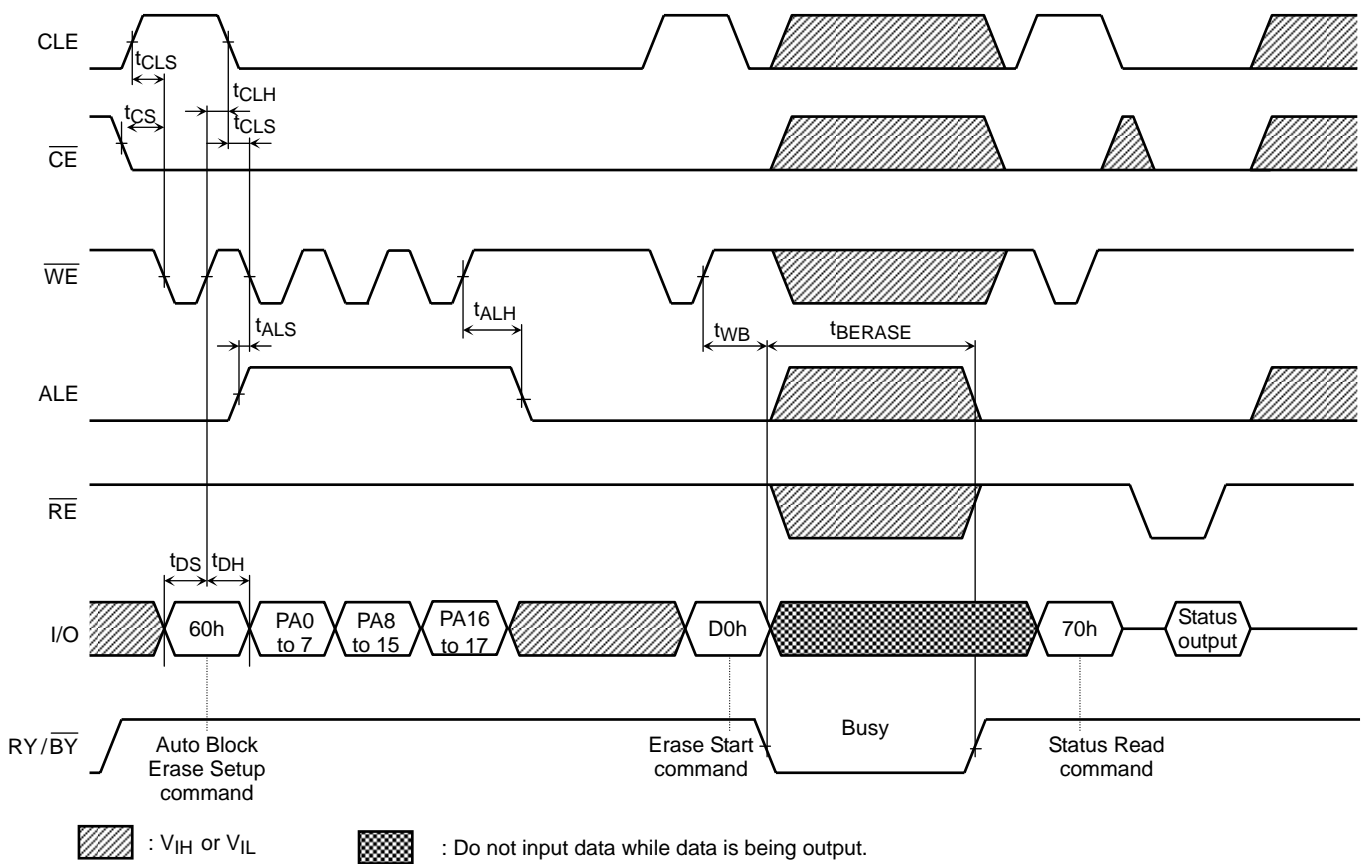
(\*1)  $t_{PROG}$ : Since the last page programming by 10h command is initiated after the previous cache program, the  $t_{PROG}$  during cache programming is given by the following equation.

$$t_{PROG} = t_{PROG} \text{ of the last page} + t_{PROG} \text{ of the previous page} - A$$

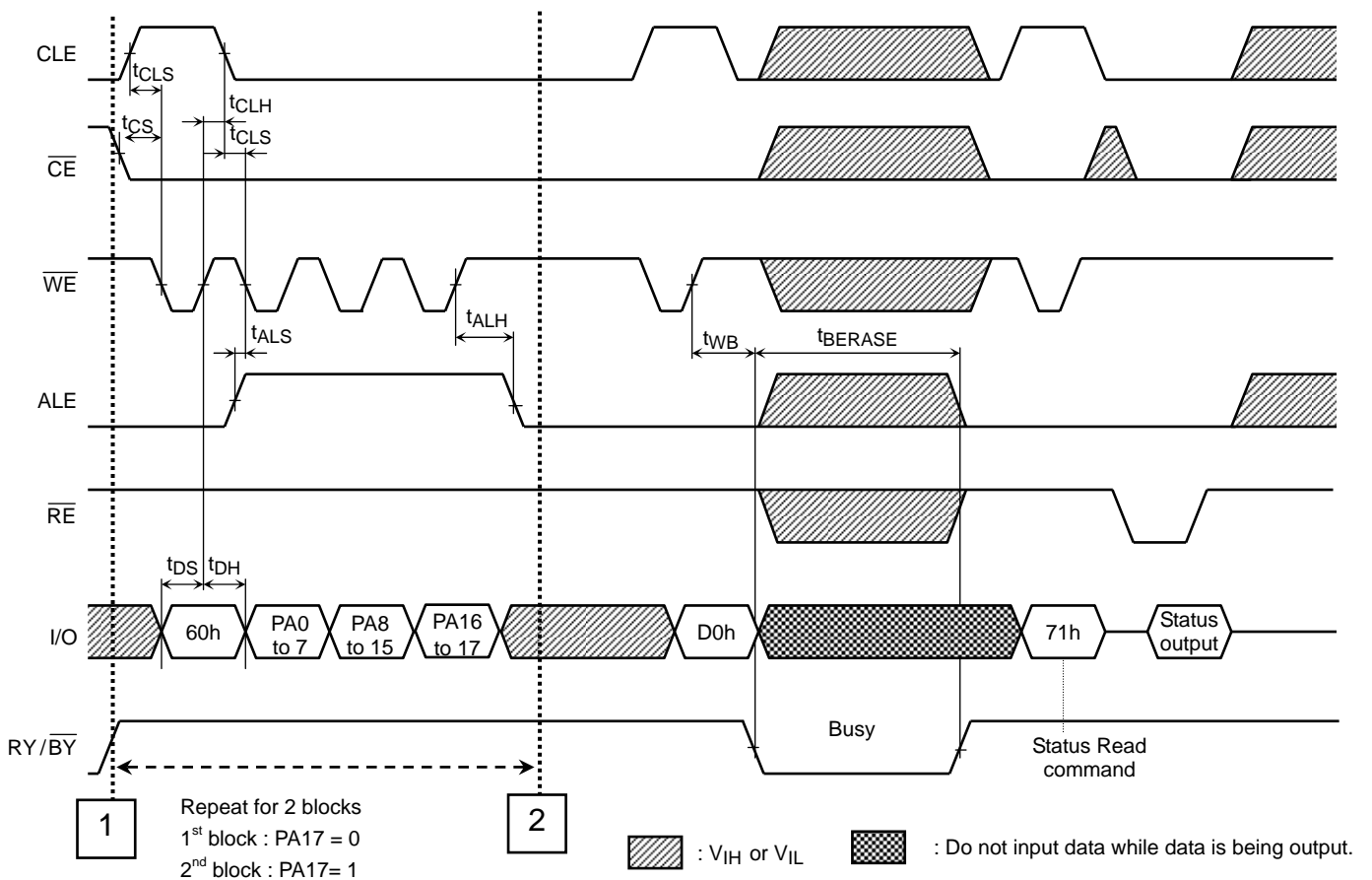
$$A = (\text{command input cycle} + \text{address input cycle} + \text{data input cycle time of the last page})$$

If "A" exceeds the  $t_{PROG}$  of previous page,  $t_{PROG}$  of the last page is 2000  $\mu\text{s}$  max.

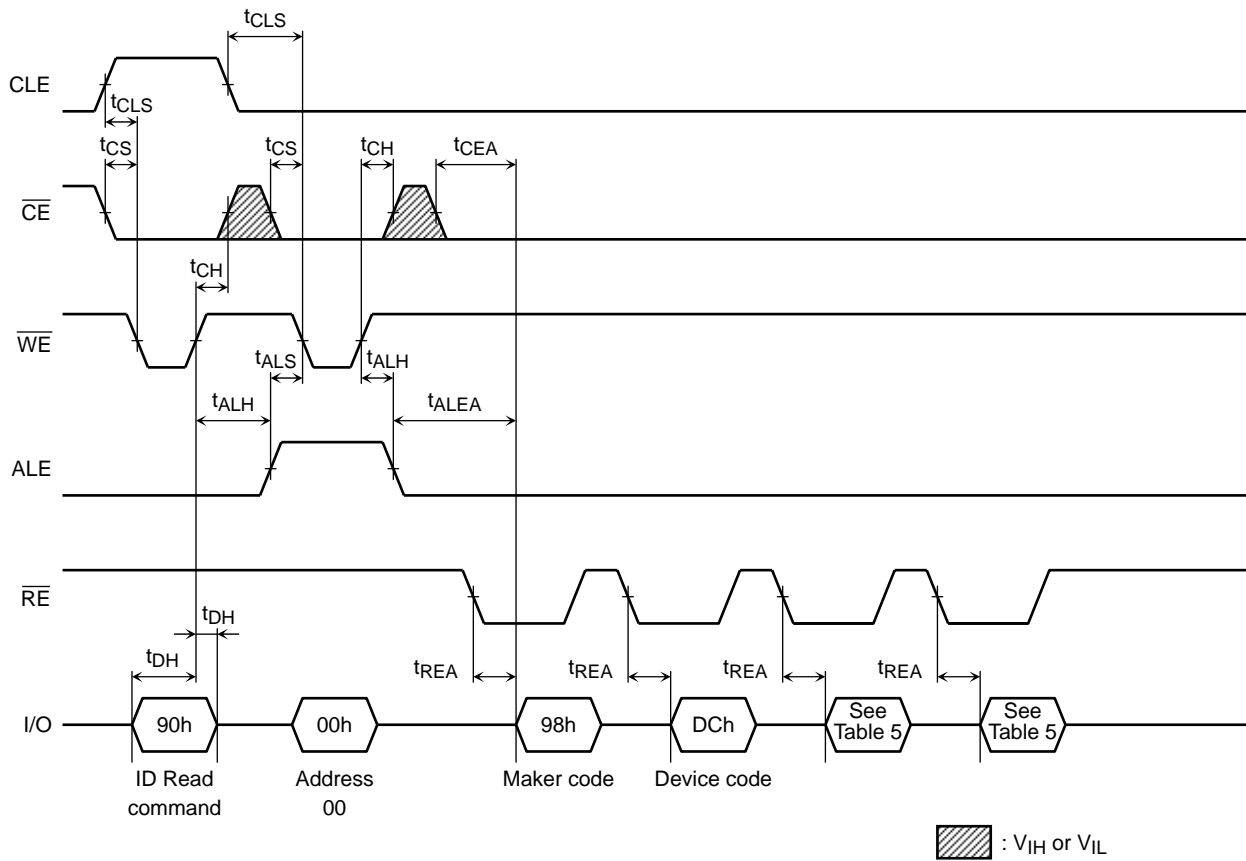
Auto Block Erase Timing Diagram



Multi Block Erase Timing Diagram

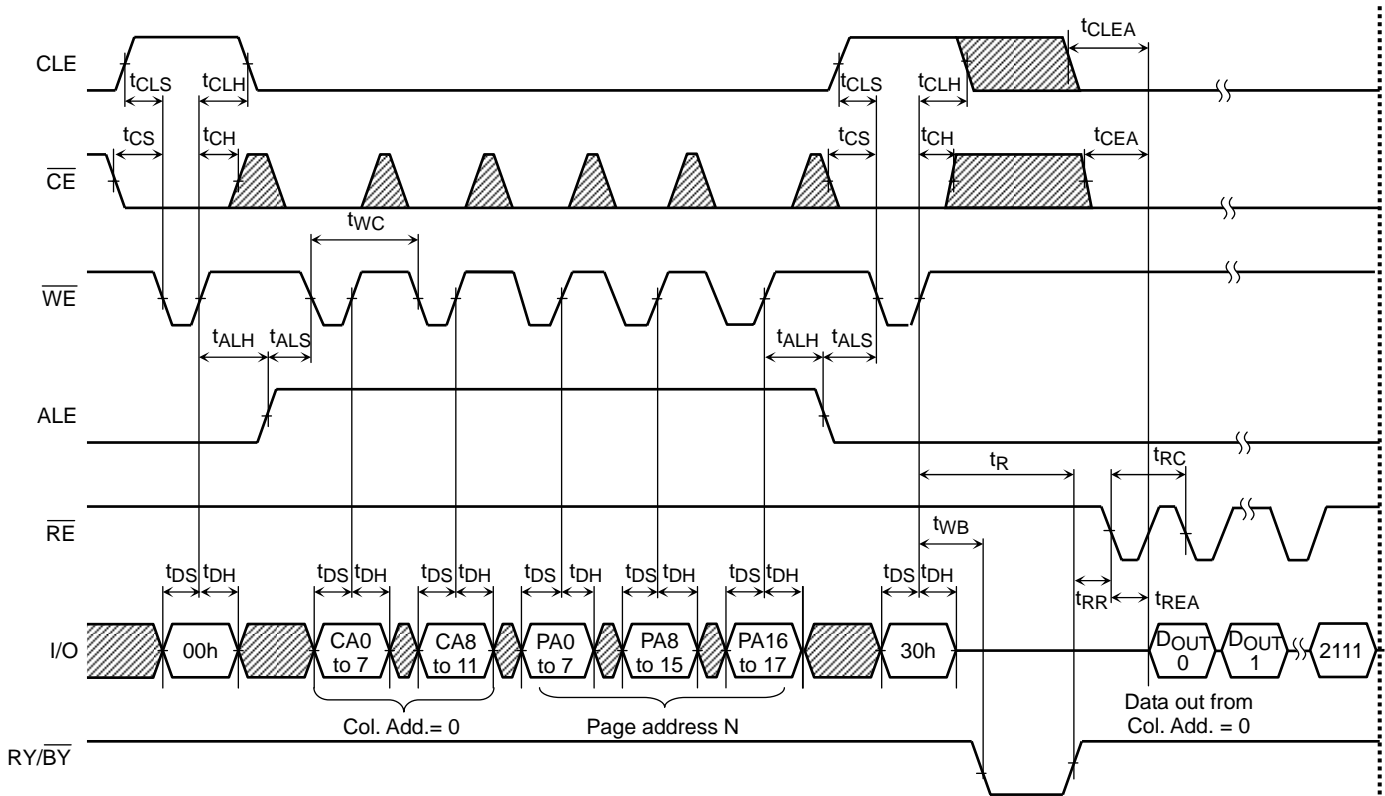


ID Read Operation Timing Diagram



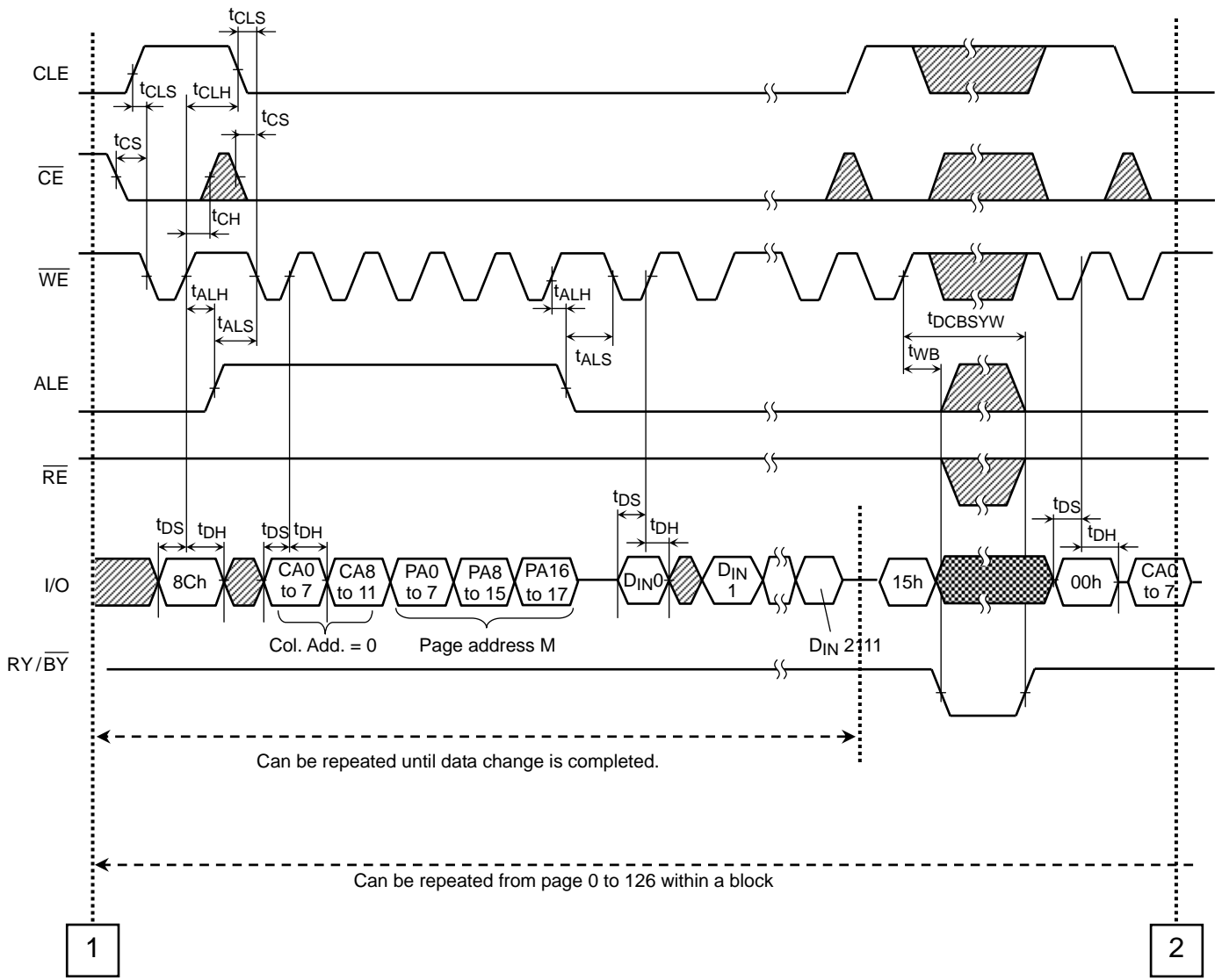


Page Copy(2) (1/4)



1

(Note) Make sure  $\overline{WP}$  is held to High level when Page Copy (2) operation is performed.  
 Also make sure the Page Copy operation is terminated with 8Ch-10h command sequence.



Can be repeated until data change is completed.

Can be repeated from page 0 to 126 within a block

1

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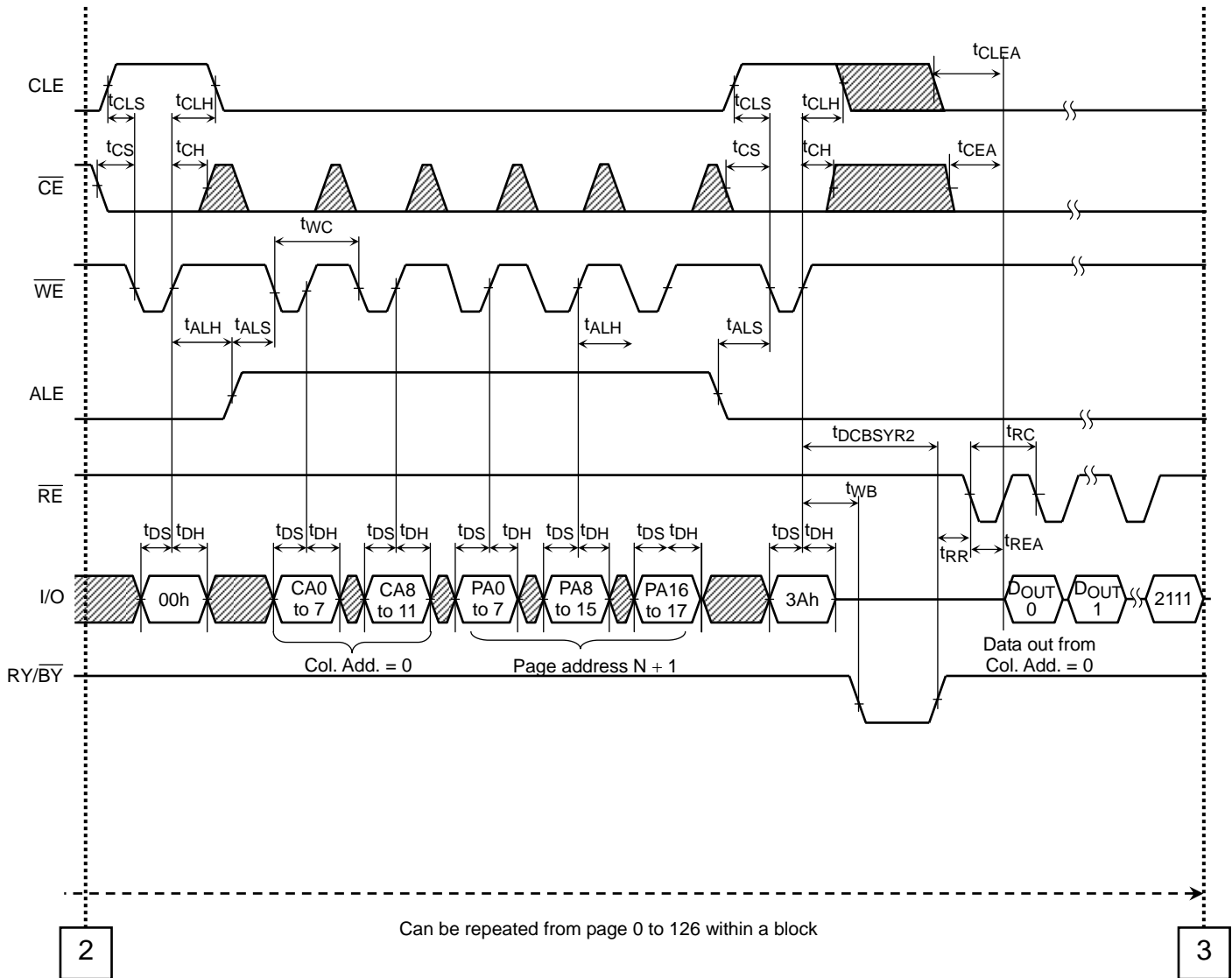
2

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- : Do not input data while data is being output.
- :  $V_{IH}$  or  $V_{IL}$

Data input is required only if previous data output needs to be altered.  
 If the data has to be changed, locate the desired address with the column address input after the 8Ch command, and change only the data that needs be changed.  
 If the data does not have to be changed, data input cycles are not required.

Page Copy(2) (3/4)



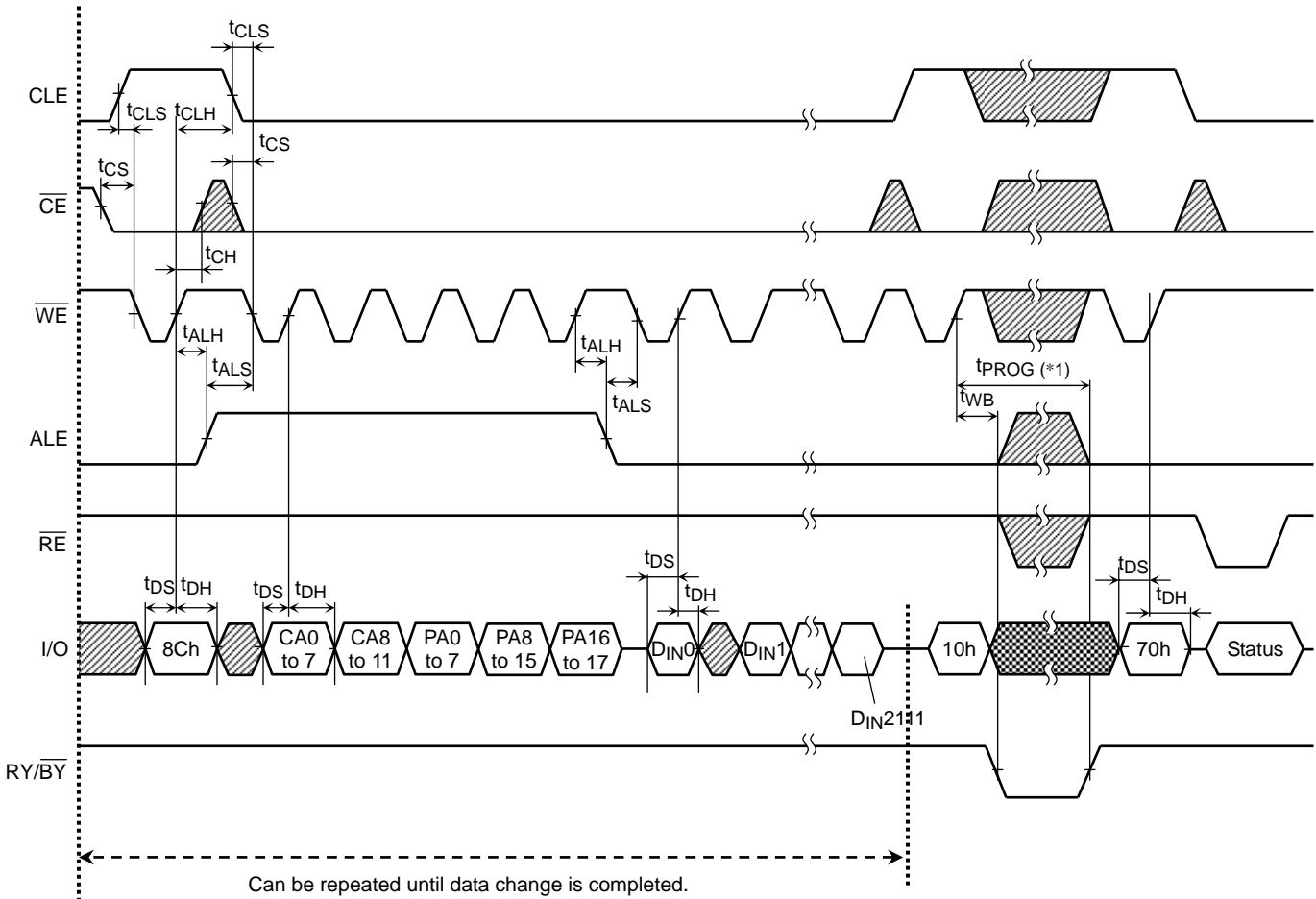
2

Can be repeated from page 0 to 126 within a block

3

Continued from 2 of last page

Continues to 3 of next page



3

Continued from [3] of last page

- : Do not input data while data is being output.
- :  $V_{IH}$  or  $V_{IL}$

(\*1)  $t_{PROG}$ : Since the last page programming by 10h command is initiated after the previous cache program, the  $t_{PROG}$  during cache programming is given by the following equation.

$$t_{PROG} = t_{PROG} \text{ of the last page} + t_{PROG} \text{ of the previous page-A}$$

$$A = (\text{command input cycle} + \text{address input cycle} + \text{data input cycle time of the last page})$$

If "A" exceeds the  $t_{PROG}$  of previous page,  $t_{PROG}$  of the last page is 2000  $\mu$ s max.

## PIN FUNCTIONS

The device is a serial access memory which utilizes time-sharing input of address information.

### Command Latch Enable: CLE

The CLE input signal is used to control loading of the operation mode command into the internal command register. The command is latched into the command register from the I/O port on the rising edge of the  $\overline{WE}$  signal while CLE is High.

### Address Latch Enable: ALE

The ALE signal is used to control loading address information into the internal address register. Address information is latched into the address register from the I/O port on the rising edge of  $\overline{WE}$  while ALE is High.

### Chip Enable: $\overline{CE}$

The device goes into a low-power Standby mode when  $\overline{CE}$  goes High during the device is in Ready state. The  $\overline{CE}$  signal is ignored when device is in Busy state ( $R\overline{Y}/\overline{B\overline{Y}} = L$ ), such as during a Program or Erase or Read operation, and will not enter Standby mode even if the  $\overline{CE}$  input goes High.

### Write Enable: $\overline{WE}$

The  $\overline{WE}$  signal is used to control the acquisition of data from the I/O port.

### Read Enable: $\overline{RE}$

The  $\overline{RE}$  signal controls serial data output. Data is available  $t_{REA}$  after the falling edge of  $\overline{RE}$ .  
The internal column address counter is also incremented (Address = Address + 1) on this falling edge.

### I/O Port: I/O1 to 8

The I/O1 to 8 pins are used as a port for transferring address, command and input/output data to and from the device.

### Write Protect: $\overline{WP}$

The  $\overline{WP}$  signal is used to protect the device from accidental programming or erasing. The internal voltage regulator is reset when  $\overline{WP}$  is Low. This signal is usually used for protecting the data during the power-on/off sequence when input signals are invalid.

### Ready/Busy: $R\overline{Y}/\overline{B\overline{Y}}$

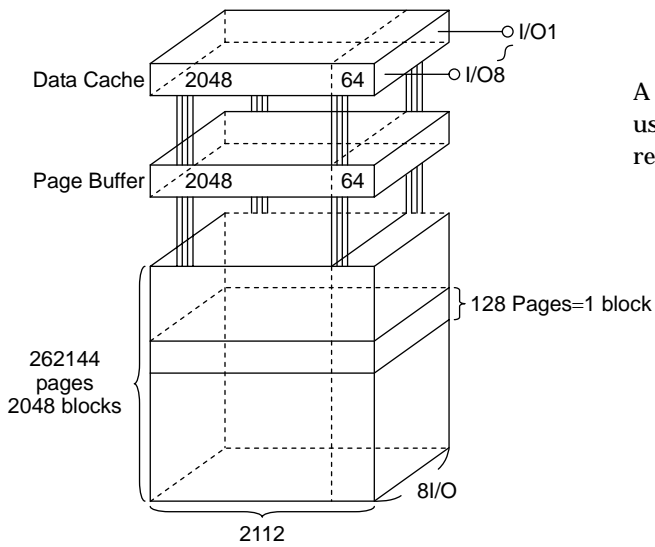
The  $R\overline{Y}/\overline{B\overline{Y}}$  output signal is used to indicate the operating condition of the device. The  $R\overline{Y}/\overline{B\overline{Y}}$  signal is in Busy state ( $R\overline{Y}/\overline{B\overline{Y}} = L$ ) during the Program, Erase and Read operations and will return to Ready state ( $R\overline{Y}/\overline{B\overline{Y}} = H$ ) after completion of the operation. The output buffer for this signal is an open drain and has to be pulled-up to  $V_{cc}$  with an appropriate resistor.

### Power on Select: PSL

The PSL signal is used to select whether the device initialization should take place during the device power on or during the first Reset. Please refer to the application note (2) for details.

Schematic Cell Layout and Address Assignment

The Program operation works on page units while the Erase operation works on block units.



A page consists of 2112 bytes in which 2048 bytes are used for main memory storage and 64 bytes are for redundancy or for other uses.

1 page = 2112 bytes

1 block = 2112 bytes × 128 pages = (256K + 8K) bytes

Capacity = 2112 bytes × 128pages × 2048blocks

Table 1. Addressing

|              | I/O8 | I/O7 | I/O6 | I/O5 | I/O4 | I/O3 | I/O2 | I/O1 |
|--------------|------|------|------|------|------|------|------|------|
| First cycle  | CA7  | CA6  | CA5  | CA4  | CA3  | CA2  | CA1  | CA0  |
| Second cycle | L    | L    | L    | L    | CA11 | CA10 | CA9  | CA8  |
| Third cycle  | PA7  | PA6  | PA5  | PA4  | PA3  | PA2  | PA1  | PA0  |
| Fourth cycle | PA15 | PA14 | PA13 | PA12 | PA11 | PA10 | PA9  | PA8  |
| Fifth cycle  | L    | L    | L    | L    | L    | L    | PA17 | PA16 |

CA0 to CA11: Column address

PA0 to PA17: Page address





PA7 to PA17: Block address

PA0 to PA6: NAND address in block

Operation Mode: Logic and Command Tables

The operation modes such as Program, Erase, Read and Reset are controlled by command operations shown in Table 3. Address input, command input and data input/output are controlled by the CLE, ALE,  $\overline{CE}$ ,  $\overline{WE}$ ,  $\overline{RE}$  and  $\overline{WP}$  signals, as shown in Table 2.

Table 2. Logic Table

|                        | CLE | ALE | $\overline{CE}$ | $\overline{WE}$  | $\overline{RE}$   | $\overline{WP}$ *1  | PSL *3                   |
|------------------------|-----|-----|-----------------|--|---|---------------------|--------------------------|
| Command Input          | H   | L   | L               |  | H   | *                   | 0V/ V <sub>CC</sub> / NU |
| Data Input             | L   | L   | L               |  | H   | H                   | 0V/ V <sub>CC</sub> / NU |
| Address input          | L   | H   | L               |  | H   | *                   | 0V/ V <sub>CC</sub> / NU |
| Serial Data Output     | L   | L   | L               | H  |  | *                   | 0V/ V <sub>CC</sub> / NU |
| During Program (Busy)  | *   | *   | *               | *  | *   | H                   | 0V/ V <sub>CC</sub> / NU |
| During Erase (Busy)    | *   | *   | *               | *  | *   | H                   | 0V/ V <sub>CC</sub> / NU |
| During Read (Busy)     | *   | *   | H               | *  | *   | *                   | 0V/ V <sub>CC</sub> / NU |
|                        | *   | *   | L               | H (*2)   | H (*2)  | *                   | 0V/ V <sub>CC</sub> / NU |
| Program, Erase Inhibit | *   | *   | *               | *  | *   | L                   | 0V/ V <sub>CC</sub> / NU |
| Standby                | *   | *   | H               | *  | *   | 0 V/V <sub>CC</sub> | 0V/ V <sub>CC</sub> / NU |

H: V<sub>IH</sub>, L: V<sub>IL</sub>, \*: V<sub>IH</sub> or V<sub>IL</sub>

\*1: Refer to Application Note (10) toward the end of this document regarding the  $\overline{WP}$  signal when Program or Erase Inhibit

\*2: If  $\overline{CE}$  is low during read busy,  $\overline{WE}$  and  $\overline{RE}$  must be held High to avoid unintended command/address input to the device or read to device. Reset or Status Read command can be input during Read Busy.

\*3: PSL must be tied to either 0V or V<sub>cc</sub>, or left unconnected (NU).

Table 3. Command table (HEX)

|   | First Cycle | Second Cycle | Acceptable while Busy |
|---|-------------|--------------|-----------------------|
| Serial Data Input                                       | 80          | —            |                       |
| Read  | 00          | 30           |                       |
| Column Address Change in Serial Data Output             | 05          | E0           |                       |
| Read with Data Cache                                    | 31          | —            |                       |
| Read Start for Last Page in Read Cycle with Data Cache  | 3F          | —            |                       |
| Auto Page Program                                       | 80          | 10           |                       |
| Column Address Change in Serial Data Input              | 85          | —            |                       |
| Auto Program with Data Cache                            | 80          | 15           |                       |
| Multi Page Program                                      | 80          | 11           |                       |
| Read for Page Copy (2)                                  | 00          | 3A           |                       |
| Auto Program with Data Cache during Page Copy (2)       | 8C          | 15           |                       |
| Auto Program for last page during Page Copy (2)         | 8C          | 10           |                       |
| Auto Block Erase  | 60          | D0           |                       |
| ID Read   | 90          | —            |                       |
| Status Read   | 70          | —            | ○                     |
| Status Read for Multi-Page Program or Multi Block Erase | 71          | —            | ○                     |
| Reset   | FF          | —            | ○                     |

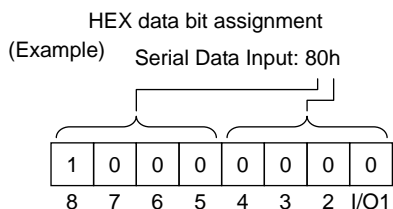


Table 4 shows the operation states for Read mode.

Table 4. Read mode operation states

|                 | CLE | ALE | $\overline{CE}$ | $\overline{WE}$ | $\overline{RE}$ | I/O1 to I/O8   | Power  |
|-----------------|-----|-----|-----------------|-----------------|-----------------|----------------|--------|
| Output select   | L   | L   | L               | H               | L               | Data output    | Active |
| Output Deselect | L   | L   | L               | H               | H               | High impedance | Active |

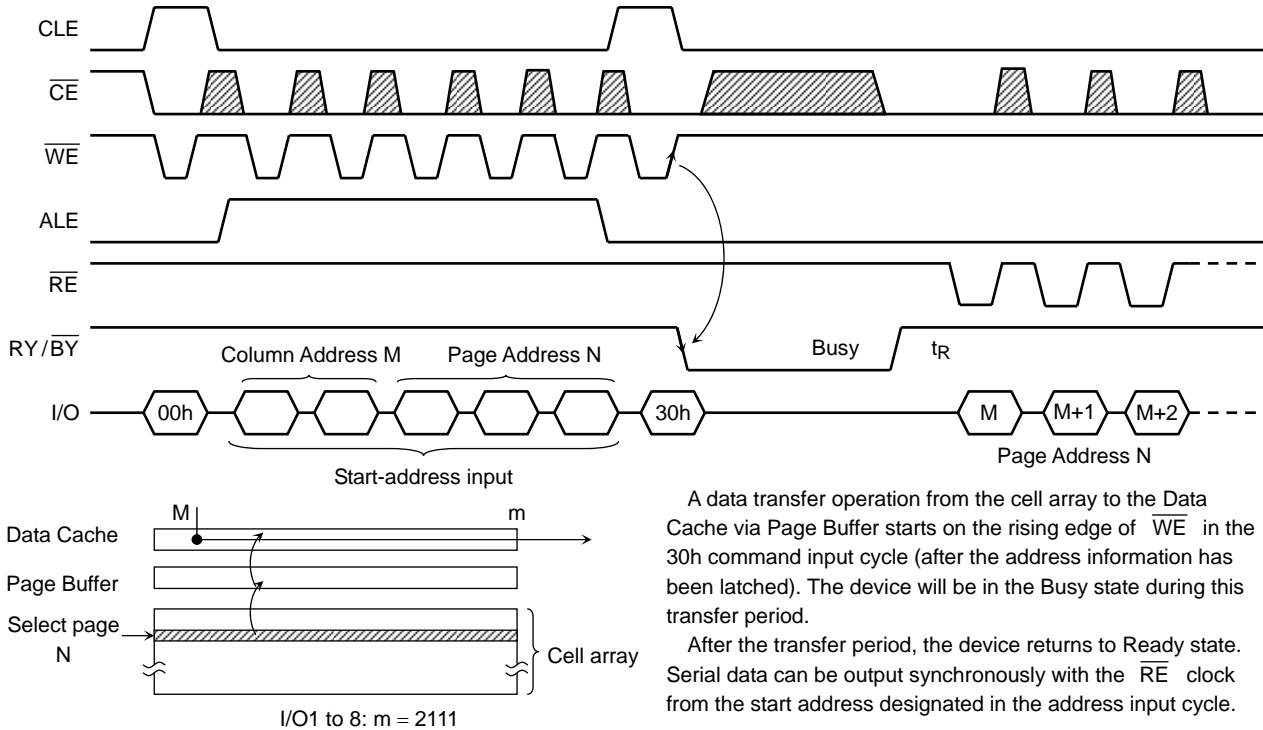
H:  $V_{IH}$ , L:  $V_{IL}$ , \*:  $V_{IH}$  or  $V_{IL}$



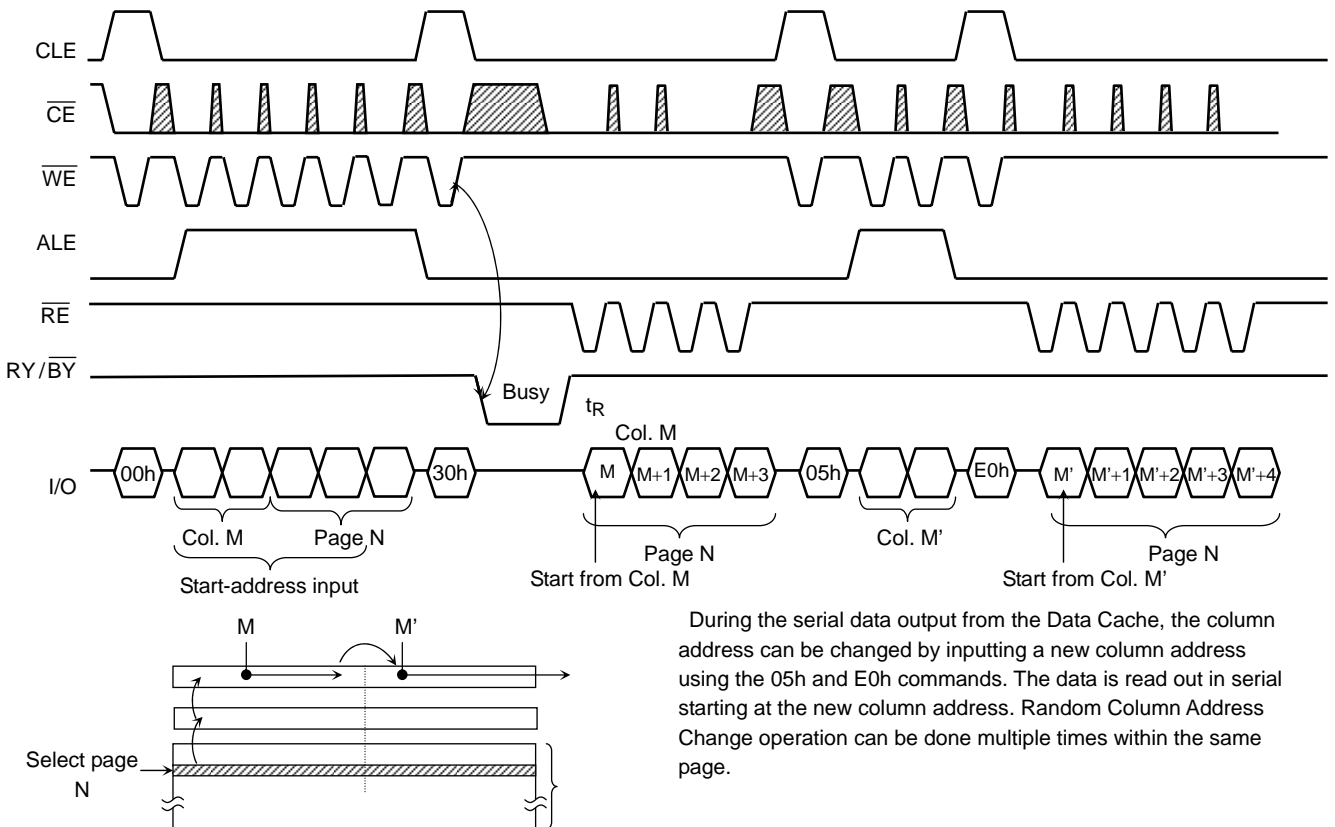
**DEVICE OPERATION**

Read Mode

Read mode is set when the "00h" and "30h" commands are issued to the Command register. Between the two commands, a start address for the Read mode needs to be issued. Refer to the figures below for the sequence and the block diagram (Refer to the detailed timing chart.).

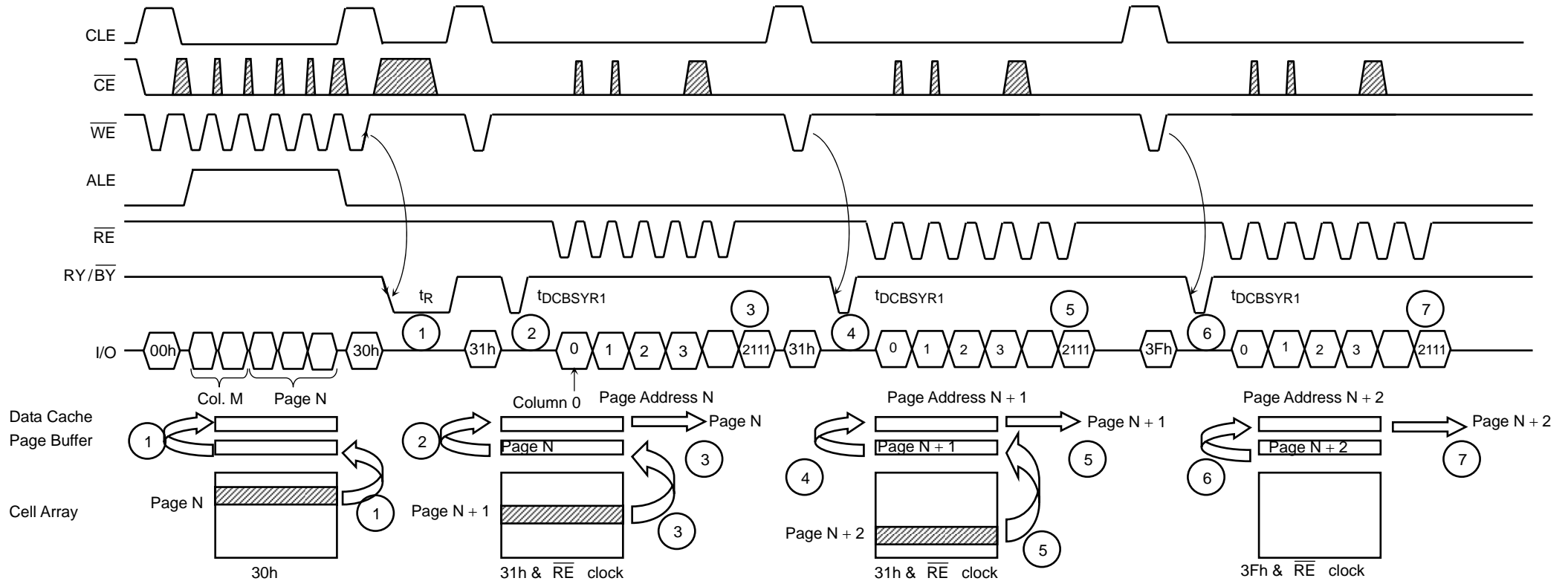


Random Column Address Change in Read Cycle



Read Operation with Read Cache

The device has a Read operation with Data Cache that enables the high speed read operation shown below. When the block address changes, this sequence has to be started from the beginning.

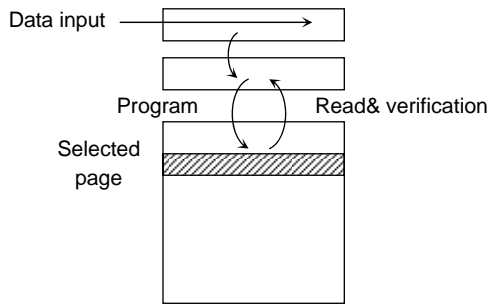
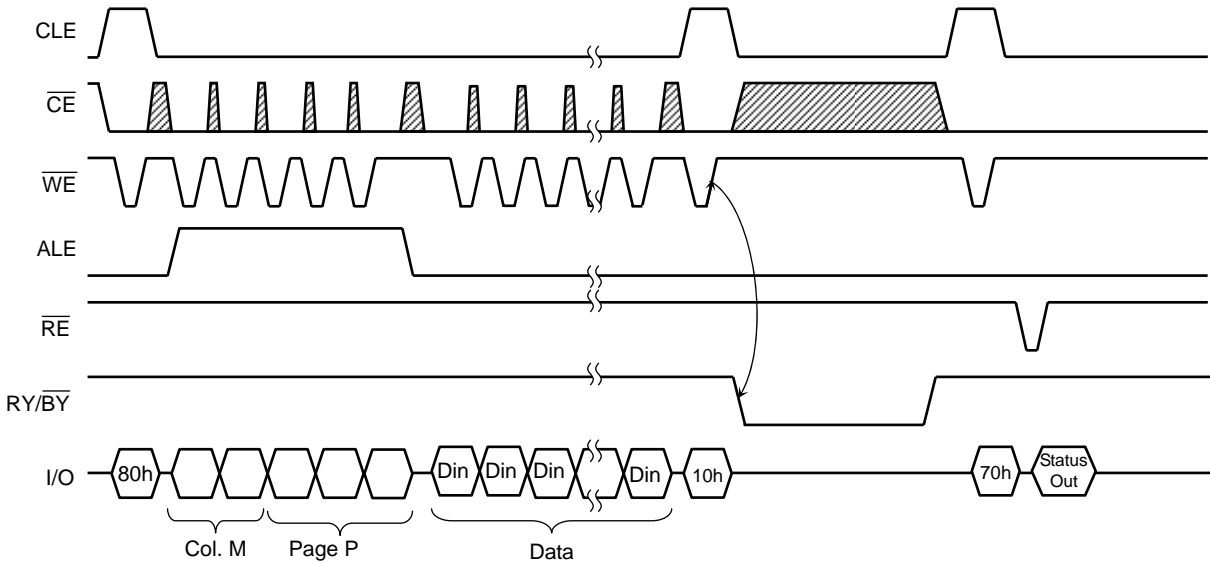


If the 31h command is issued to the device, the data content of the next page is transferred to the Page Buffer during serial data out from the Data Cache, and therefore the  $t_R$  (Data transfer from memory cell to data register) will be reduced.

- 1 Normal read. Data is transferred from Page N to Data Cache through Page Buffer. During this time period, the device outputs Busy state for 50  $\mu$ s max ( $t_R$ ).
- 2 After the Ready/Busy returns to Ready, 31h command is issued and data is transferred to Data Cache from Page Buffer again. This data transfer takes 50  $\mu$ s max ( $t_{DCBSYR1}$ ) and the completion of this time period can be detected by Read/Busy signal.
- 3 Data of Page N + 1 is transferred to Page Buffer from cell while the data of Page N in Data cache can be read out by /RE clock simultaneously.
- 4 The 31h command makes data of Page N + 1 transfer to Data Cache from Page Buffer after the completion of the transfer from cell to Page Buffer. The device outputs Busy state for 50  $\mu$ s max. ( $t_{DCBSYR1}$ ). This Busy period depends on the combination of the internal data transfer time from cell to Page buffer and the serial data out time.
- 5 Data of Page N + 2 is transferred to Page Buffer from cell while the data of Page N + 1 in Data cache can be read out by /RE clock simultaneously
- 6 The 3Fh command makes the data of Page N + 2 transfer to the Data Cache from the Page Buffer after the completion of the transfer from cell to Page Buffer. The device outputs Busy state for 50  $\mu$ s max. ( $t_{DCBSYR1}$ ). This Busy period depends on the combination of the internal data transfer time from cell to Page buffer and the serial data out time.
- 7 Data of Page N + 2 in Data Cache can be read out, but since the 3Fh command does not transfer the data from the memory cell to Page Buffer, the device can accept new command input immediately after the completion of serial data out.

Auto Page Program Operation

The device carries out an Automatic Page Program operation when it receives a "10h" Program command after the address and data have been input. The sequence of command, address and data input is shown below. (Refer to the detailed timing chart.)

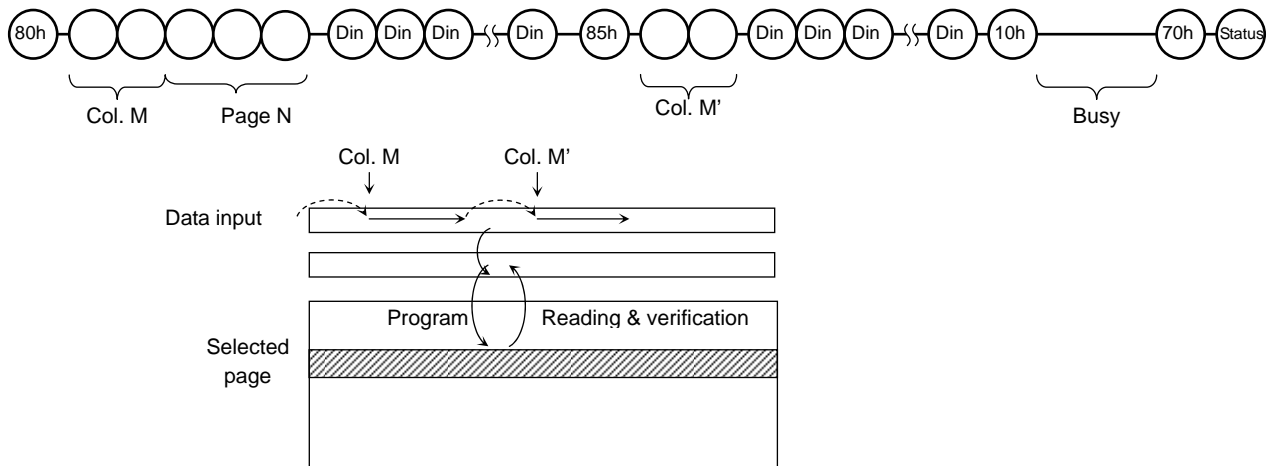


The data is transferred (programmed) from the Data Cache via the Page Buffer to the selected page on the rising edge of WE following input of the "10h" command. After programming, the programmed data is transferred back to the Page Buffer to be automatically verified by the device. If the programming does not succeed, the Program/Verify operation is repeated by the device until success is achieved or until the maximum loop number set in the device is reached.

Random Column Address Change in Auto Page Program Operation

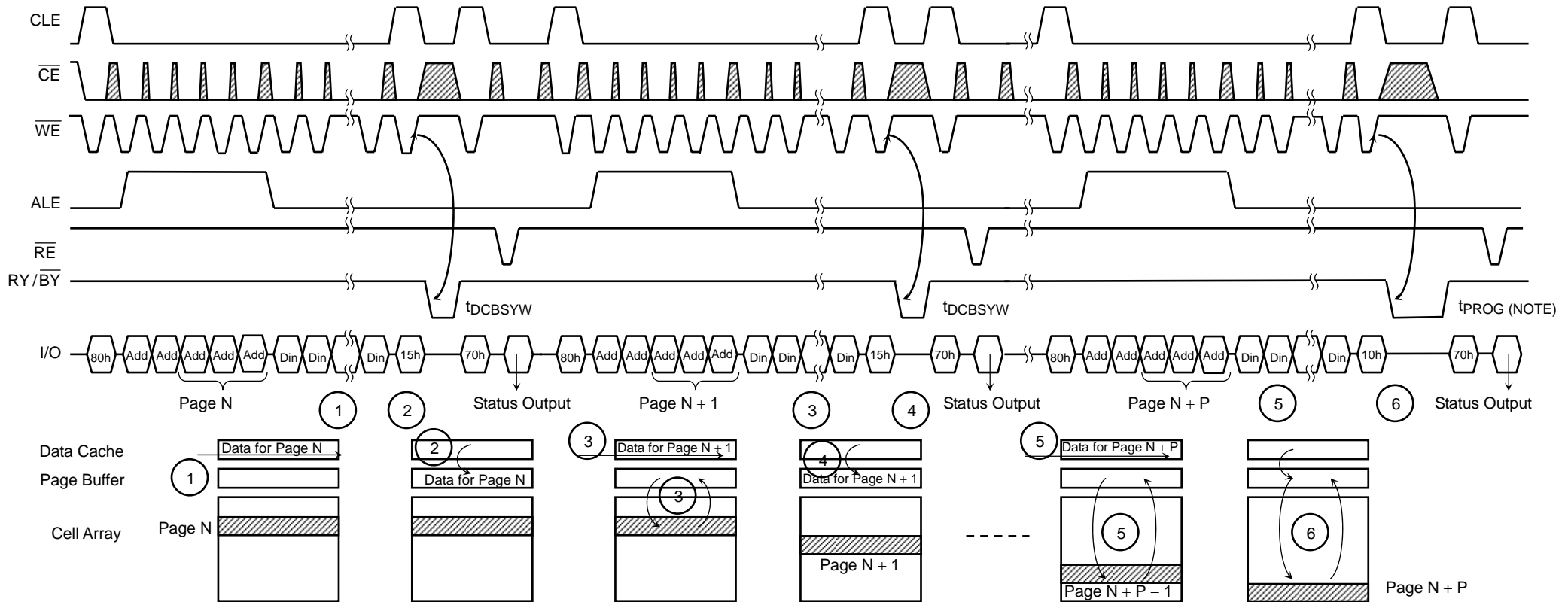
The column address can be changed by the 85h command during the data input sequence of the Auto Page Program operation.

Two address input cycles after the 85h command are recognized as a new column address for the data input. After the new data is input to the new column address, the 10h command initiates the actual data program into the selected page automatically. The Random Column Address Change operation can be repeated multiple times within the same page.



Auto Page Program Operation with Data Cache

The device has an Auto Page Program with Data Cache operation enabling the high speed program operation shown below. When the block address changes this sequenced has to be started from the beginning.



Issuing the 15h command to the device after serial data input initiates the program operation with Data Cache

- 1 Data for Page N is input to Data Cache.
- 2 Data is transferred to the Page Buffer by the 15h command. During the transfer the Ready/Busy outputs Busy State ( $t_{DCBSYW}$ ).
- 3 Data is programmed to the selected page while the data for page N + 1 is input to the Data Cache.
- 4 By the 15h command, the data in the Data Cache is transferred to the Page Buffer after the programming of page N is completed. The device output busy state from the 15h command until the Data Cache becomes empty. The duration of this period depends on timing between the internal programming of page N and serial data input for Page N + 1 ( $t_{DCBSYW}$ : 2000  $\mu$ s max).
- 5 Data for Page N + P is input to the Data Cache while the data of the Page N + P - 1 is being programmed.
- 6 The programming with Data Cache is terminated by the 10h command. When the device becomes Ready, it shows that the internal programming of the Page N + P is completed.

NOTE: Since the last page programming by the 10h command is initiated after the previous cache program, the  $t_{PROG}$  during cache programming is given by the following;

$$t_{PROG} = t_{PROG} \text{ for the last page} + t_{PROG} \text{ of the previous page} - (\text{command input cycle} + \text{address input cycle} + \text{data input cycle time of the previous page})$$

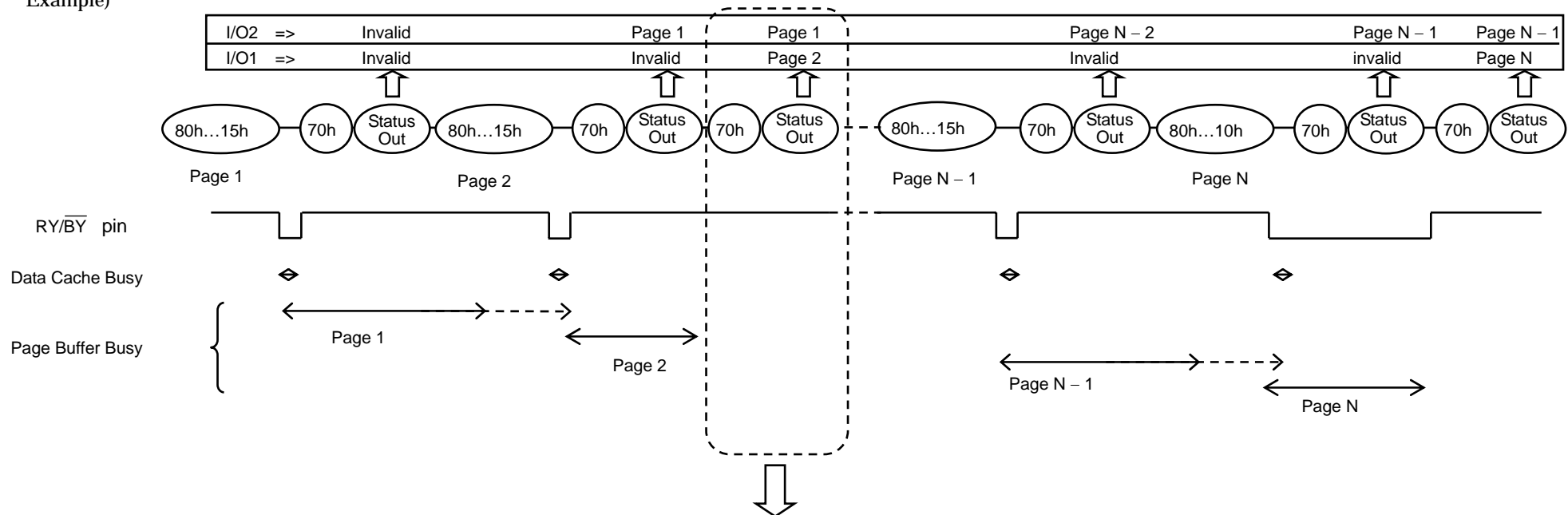
Pass/fail status for each page programmed by the Auto Page Programming with Data Cache operation can be detected by the Status Read operation.

- I/O1 : Pass/fail of the current page program operation.
- I/O2 : Pass/fail of the previous page program operation.

The Pass/Fail status on I/O1 and I/O2 are valid under the following conditions.

- Status on I/O1: Page Buffer Ready/Busy is Ready State.  
The Page Buffer Ready/Busy is output on I/O6 by Status Read operation or  $\overline{RY}/\overline{BY}$  pin after the 10h command
- Status on I/O2: Data Cache Read/Busy is Ready State.  
The Data Cache Ready/Busy is output on I/O7 by Status Read operation or  $\overline{RY}/\overline{BY}$  pin after the 15h command.

Example)

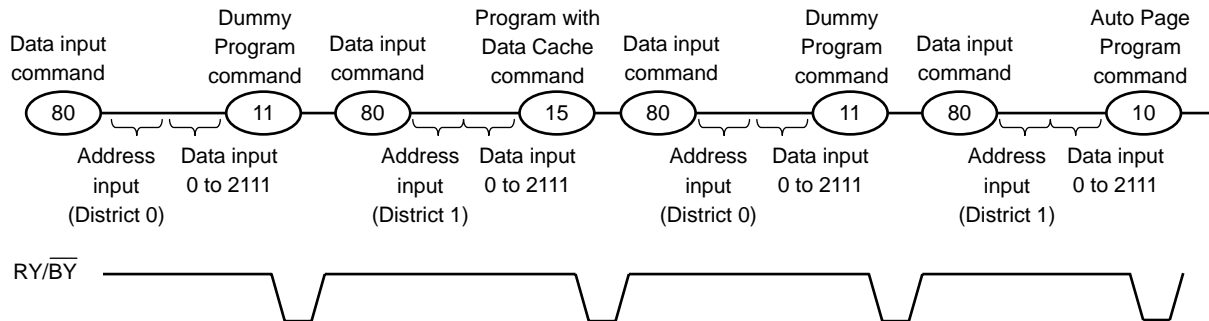


If the Page Buffer Busy returns to Ready before the next 80h command input, and if Status Read is done during this Ready period, the Status Read provides pass/fail for Page 2 on I/O1 and pass/fail result for Page1 on I/O2

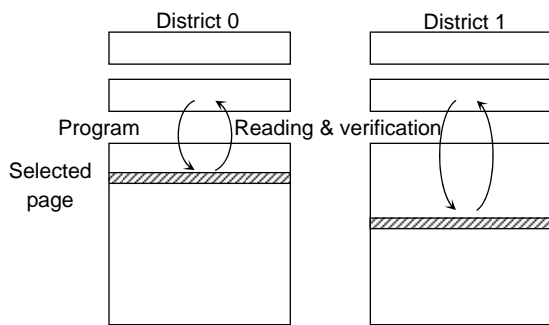
Multi Page Program with Data Cache

The device has a Multi Page Program with Data Cache operation, which enables even higher speed program operation compared to Auto Page Program with Data Cache as shown below. When the block address changes (increments) this sequenced has to be started from the beginning.

The sequence of command, address and data input is shown below. (Refer to the detailed timing chart.)



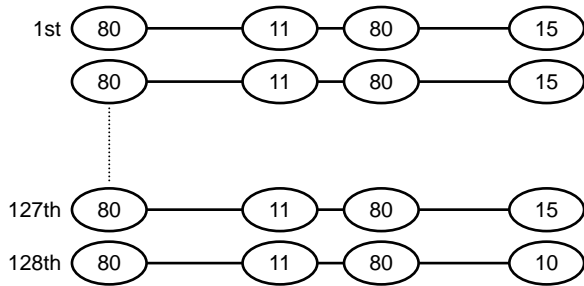
After “15h” or “10h” Program command is input to device, physical programming starts as follows. For details of Auto Program with Data Cache, refer to “Auto Page Program with Data Cache”.



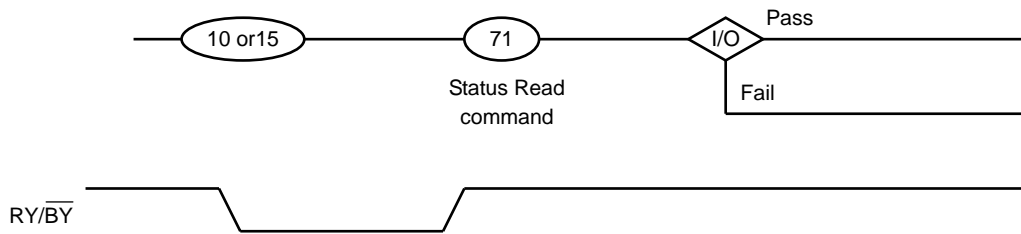
The data is transferred (programmed) from the page buffer to the selected page on the rising edge of -WE following input of the “15h” or “10h” command. After programming, the programmed data is transferred back to the register to be automatically verified by the device. If the programming does not succeed, the Program/Verify operation is repeated by the device until success is achieved or until the maximum loop number set in the device is reached.

Starting the above operation from 1st page of the selected erase blocks, and then repeating the operation total 128 times with incrementing the page address in the blocks, and then input the last page data of the blocks, "10H" command executes final programming.

In this full sequence, the command sequence is following.



After the "15h" or "10h" command, the results of the above operation is shown through the "71h" Status Read command.



The Status description is as below.

|      | STATUS                              | OUTPUT     |                |
|------|-------------------------------------|------------|----------------|
| I/O1 | Total Pass/Fail                     | Pass: 0    | Fail: 1        |
| I/O2 | District 0 Chip Status1 : Pass/Fail | Pass: 0    | Fail: 1        |
| I/O3 | District 1 Chip Status1 : Pass/Fail | Pass: 0    | Fail: 1        |
| I/O4 | District 0 Chip Status2 : Pass/Fail | Pass: 0    | Fail: 1        |
| I/O5 | District 1 Chip Status2 : Pass/Fail | Pass: 0    | Fail: 1        |
| I/O6 | Ready/Busy                          | Ready: 1   | Busy: 0        |
| I/O7 | Data Cache Ready/Busy               | Ready: 1   | Busy: 0        |
| I/O8 | Write Protect                       | Protect: 0 | Not Protect: 1 |

I/O1 describes total Pass/Fail condition of district 0 and 1. If one of the districts fails during program operation, it shows "Fail".

I/O2 to 5 shows the Pass/Fail condition of each district. For details on "Chip Status1" and "Chip Status2", refer to section "Status Read".

### Internal addressing in relation with the Districts

To use Multi Page Program operation, the internal addressing should be considered in relation with the District.

- The device consists from 2 Districts.
- Each District consists from 1024 erase blocks.
- The allocation rule is follows.

District 0: Block 0, Block 1, Block 2, Block 3,..., Block 1023 (PA17 = L)

District 1: Block 1024, Block 1025, Block 1026, Block 1027,..., Block 2047 (PA17 = H)

### Address input restriction for the Multi Page Program with Data Cache operation

There are following restrictions in using Multi Page Program with Data Cache;

(Restriction)

Maximum one block should be selected from each District.

Same page address within two districts has to be selected.

For example;

(80) [District 0, Page Address 0x00000] (11) (80) [District 1, Page Address 0x10000] (15 or 10)

(80) [District 0, Page Address 0x00001] (11) (80) [District 1, Page Address 0x10001] (15 or 10)

(Acceptance)

There is no order limitation of the District for the address input.

For example, following operation is accepted;

(80) [District 0] (11) (80) [District 1] (15 or 10)

(80) [District 1] (11) (80) [District 0] (15 or 10)

It requires no mutual address relation between the selected blocks from each District.

### Operating restriction during the Multi Page Program with Data Cache operation

(Restriction)

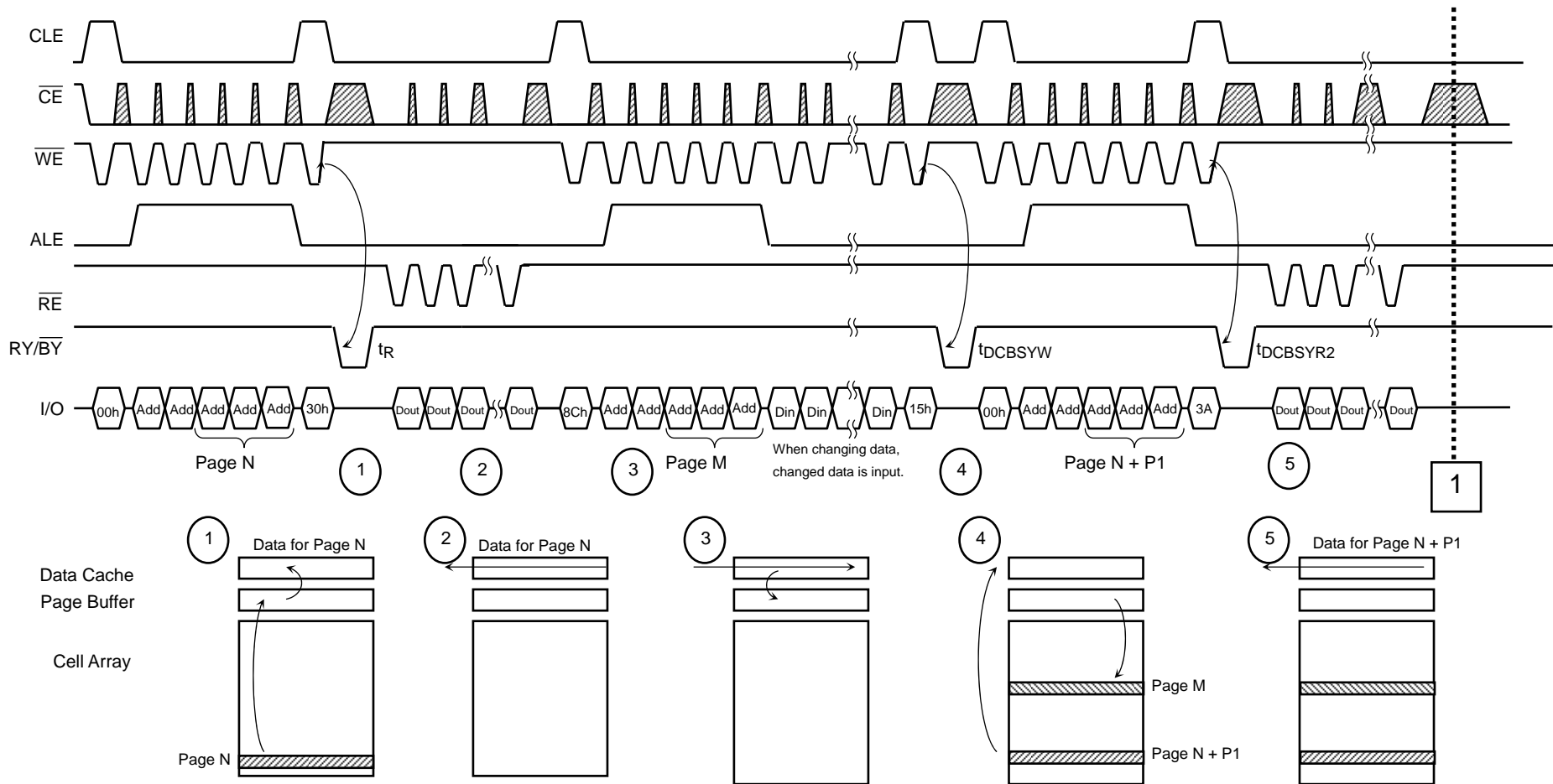
The operation has to be terminated with "10h" command.

Once the operation is started, no commands other than the commands shown in the timing diagram is allowed to be input except for Status Read command and reset command. If FF reset command is input before write operation to odd page (e.g. Page Address 0x00001, 0x1FFFF), is complete, it may cause damage to data not only to the programmed page, but also to the adjacent even page (e.g. Page Address 0x00000, 0x1FFFE in this case).



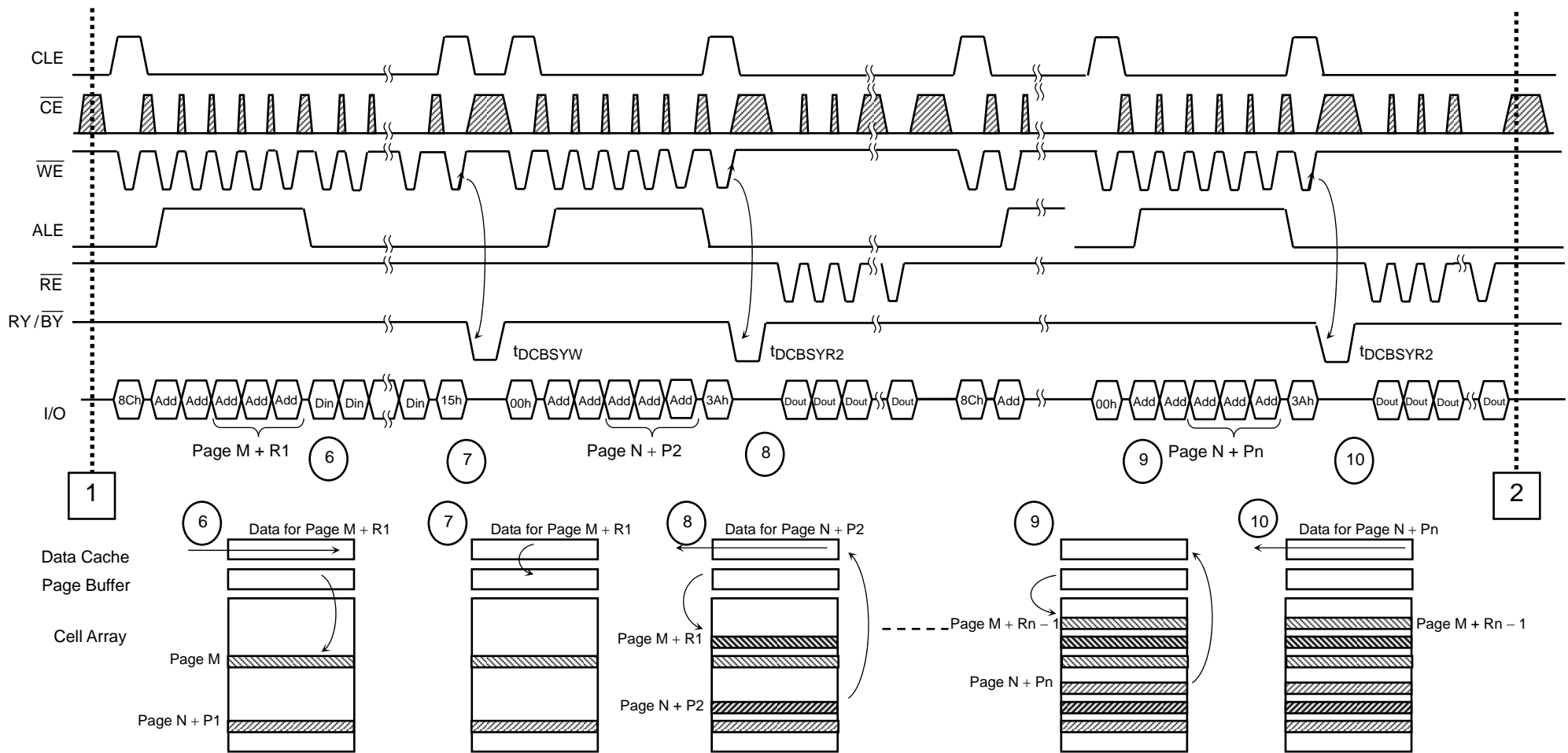
Page Copy (2)

By using Page Copy (2), data in a page can be copied to another page after the data has been read out.

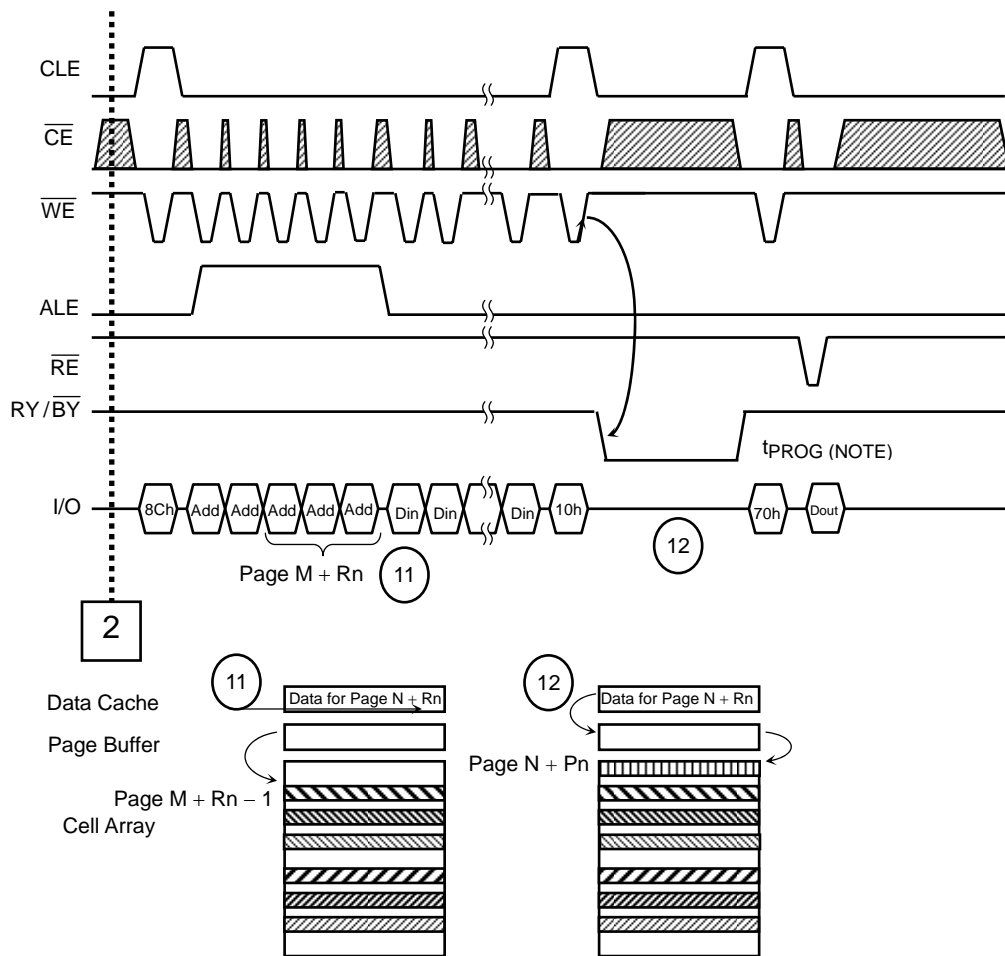


Page Copy (2) operation is as following.

- 1 Data for Page N is transferred to the Data Cache.
- 2 Data for Page N is read out.
- 3 Copy Page address M is input and if the data needs to be changed, changed data is input.
- 4 Using the 15h command, the data in the Page Buffer is programmed to Page M. Data for Page N + P1 is transferred to the Data Cache.
- 5 After the Ready state, Data for Page N + P1 is output from the Data Cache while the data of Page M is being programmed.



- 6 Copy Page address (M + R1) is input and if the data needs to be changed, changed data is input.
- 7 After programming of page M is completed, Data Cache for Page M + R1 is transferred to the Page Buffer.
- 8 By the 15h command, the data in the Page Buffer is programmed to Page M + R1. Data for Page N + P2 is transferred to the Data cache.
- 9 The data in the Page Buffer is programmed to Page M + Rn - 1. Data for Page N + Pn is transferred to the Data Cache.
- 10 Data for Page N + Pn is output.



11 Copy Page address (M + Rn) is input and if the data needs to be changed, changed data is input.

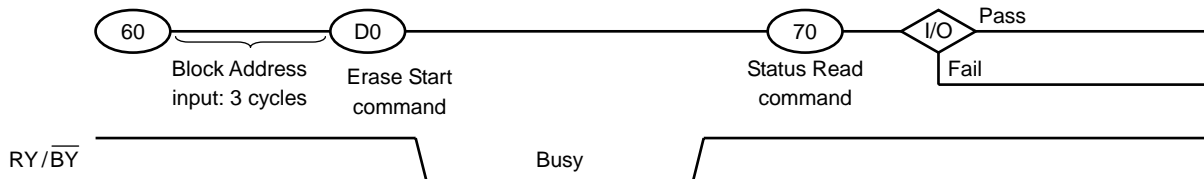
12 By issuing the 10h command, the data in the Page Buffer is programmed to Page N + Rn.

NOTE: Since the last page programming by the 10h command is initiated after the previous cache program, the t<sub>PROG</sub> here will be expected as the following,  
 $t_{PROG} = t_{PROG} \text{ for the last page} + t_{PROG} \text{ of the previous page} - (\text{command input cycle} + \text{address input cycle} + \text{data input cycle time of the previous page})$

Notes: This operation needs to be executed within Block 0 – 1023 or Block 1024 – 2047.  
 Make sure WP is held to High level when Page Copy (2) operation is performed.  
 Also make sure the Page Copy operation is terminated with 8Ch-10h command sequence.

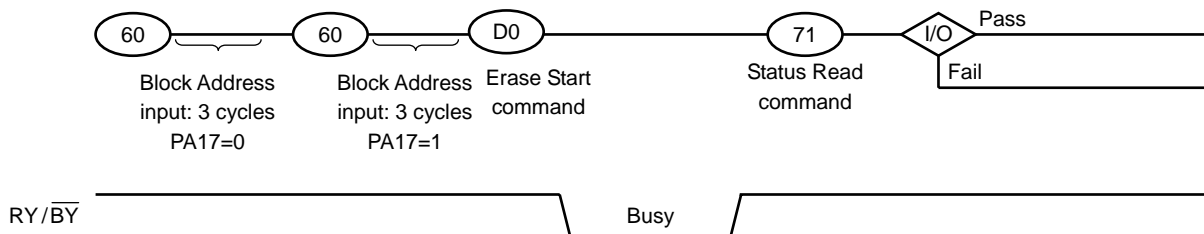
Auto Block Erase

The Auto Block Erase operation starts on the rising edge of  $\overline{WE}$  after the Erase Start command “D0h” which follows the Erase Setup command “60h”. This two-cycle process for Erase operations acts as an extra layer of protection from accidental erasure of data due to external noise. The device automatically executes the Erase and Verify operations.



Multi Block Erase

The Multi Block Erase operation starts by selecting two block addresses before D0h command as in below diagram. The device automatically executes the Erase and Verify operations and the result can be monitored by checking the status by 71h status read command. For details on 71h status read command, refer to section “Multi Page Program with Data Cache”.



Internal addressing in relation with the Districts

To use Multi Block Erase operation, the internal addressing should be considered in relation with the District.

- The device consists from 2 Districts.
- Each District consists from 1024 erase blocks.
- The allocation rule is follows.
  - District 0: Block 0, Block 1, Block 2, Block 3,..., Block 1023 (PA17 = L)
  - District 1: Block 1024, Block 1025, Block 1026, Block 1027,..., Block 2047 (PA17 = H)

Address input restriction for the Multi Block Erase

There are following restrictions in using Multi Block Erase

(Restriction)

Maximum one block should be selected from each District.

For example;

(60) [District 0] (60) [District 1] (D0)

(Acceptance)

There is no order limitation of the District for the address input.

For example, following operation is accepted;

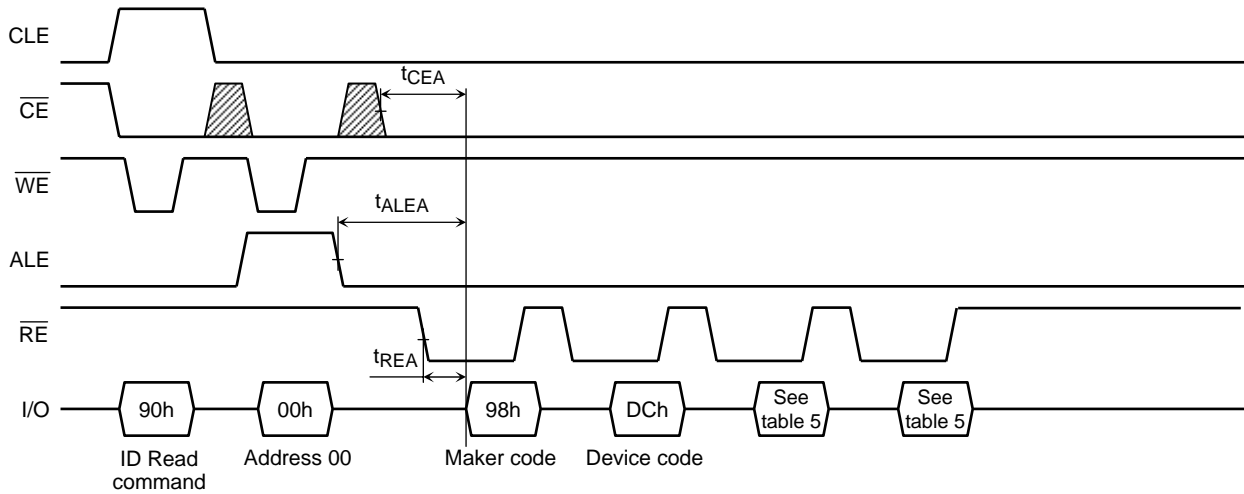
(60) [District 1] (60) [District 0] (D0)

It requires no mutual address relation between the selected blocks from each District.

Make sure to terminate the operation with D0h command. If the operation needs to be terminated before D0h command input, input the FFh reset command to terminate the operation.

ID Read

The device contains ID codes which can be used to identify the device type, the manufacturer, and features of the device. The ID codes can be read out under the following timing conditions:



For the specifications of the access times  $t_{REA}$ ,  $t_{CEA}$  and  $t_{ALEA}$  refer to the AC Characteristics.

Table 5. Code table

|          | Description   | I/O8 | I/O7 | I/O6 | I/O5 | I/O4 | I/O3 | I/O2 | I/O1 | Hex Data  |
|----------|---|------|------|------|------|------|------|------|------|-----------|
| 1st Data | Maker Code  | 1    | 0    | 0    | 1    | 1    | 0    | 0    | 0    | 98h       |
| 2nd Data | Device Code   | 1    | 1    | 0    | 1    | 1    | 1    | 0    | 0    | DCh       |
| 3rd Data | Chip Number, Cell Type, PGM Page, Write Cache       | —    | —    | —    | —    | —    | —    | —    | —    | See table |
| 4th Data | Page Size, Block Size, Redundant Size, Organization | —    | —    | —    | —    | —    | —    | —    | —    | See table |

3rd Data

|                      | Description   | I/O8 | I/O7   | I/O6 | I/O5   | I/O4   | I/O3 | I/O2 | I/O1 |
|----------------------|---------------|------|--------|------|--------|--------|------|------|------|
| Internal Chip Number | 1             |      |        |      |        |        |      | 0    | 0    |
|                      | 2             |      |        |      |        |        |      | 0    | 1    |
|                      | 4             |      |        |      |        |        |      | 1    | 0    |
|                      | 8             |      |        |      |        |        |      | 1    | 1    |
| Cell Type            | 2 level cell  |      |        |      |        |        | 0    | 0    |      |
|                      | 4 level cell  |      |        |      |        |        | 0    | 1    |      |
|                      | 8 level cell  |      |        |      |        |        | 1    | 0    |      |
|                      | 16 level cell |      |        |      |        |        | 1    | 1    |      |
| Reserved             |               |      | 0 or 1 | 0    | 0 or 1 | 0 or 1 |      |      |      |

4th Data

|  | Description | I/O8   | I/O7 | I/O6 | I/O5 | I/O4 | I/O3 | I/O2 | I/O1 |
|--|-------------|--------|------|------|------|------|------|------|------|
| Page Size<br>(without redundant area)  | 1 KB        |        |      |      |      |      |      | 0    | 0    |
|  | 2 KB        |        |      |      |      |      |      | 0    | 1    |
|  | 4 KB        |        |      |      |      |      |      | 1    | 0    |
|  | 8 KB        |        |      |      |      |      |      | 1    | 1    |
| Block Size<br>(without redundant area) | 64 KB       |        |      | 0    | 0    |      |      |      |      |
|  | 128 KB      |        |      | 0    | 1    |      |      |      |      |
|  | 256 KB      |        |      | 1    | 0    |      |      |      |      |
|  | 512 KB      |        |      | 1    | 1    |      |      |      |      |
| Redundant area size<br>(byte/512byte)  | 8           |        |      |      |      | 0    | 0    |      |      |
|  | 16          |        |      |      |      | 0    | 1    |      |      |
|  | Reserved    |        |      |      |      | 1    | 0    |      |      |
|  | Reserved    |        |      |      |      | 1    | 1    |      |      |
| Organization                           | ×8          |        | 0    |      |      |      |      |      |      |
|  | ×16         |        | 1    |      |      |      |      |      |      |
| Reserved                               |             | 0 or 1 |      |      |      |      |      |      |      |

Status Read

The device automatically implements the execution and verification of the Program and Erase operations. The Status Read function is used to monitor the Ready/Busy status of the device, determine the result (pass /fail) of a Program or Erase operation, and determine whether the device is in Protect mode. The device status is output via the I/O port using  $\overline{RE}$  after a “70h” command input. The Status Read can also be used during a Read operation to find out the Ready/Busy status.

The resulting information is outlined in Table 6.

Table 6. Status output table

|      | Definition  | Page Program<br>Block Erase | Cache Program | Read<br>Cache Read |
|------|---|-----------------------------|---------------|--------------------|
| I/O1 | Chip Status1<br>Pass: 0      Fail: 1              | Pass/Fail                   | Pass/Fail     | Invalid            |
| I/O2 | Chip Status 2<br>Pass: 0      Fail: 1             | Invalid                     | Pass/Fail     | Invalid            |
| I/O3 | Not Used  | 0                           | 0             | 0                  |
| I/O4 | Not Used  | 0                           | 0             | 0                  |
| I/O5 | Not Used  | 0                           | 0             | 0                  |
| I/O6 | Page Buffer Ready/Busy<br>Ready: 1      Busy: 0   | Ready/Busy                  | Ready/Busy    | Ready/Busy         |
| I/O7 | Data Cache Ready/Busy<br>Ready: 1      Busy: 0    | Ready/Busy                  | Ready/Busy    | Ready/Busy         |
| I/O8 | Write Protect<br>Not Protected :1    Protected: 0 | Write Protect               | Write Protect | Write Protect      |

The Pass/Fail status on I/O1 and I/O2 is only valid during a Program/Erase operation when the device is in the Ready state.

**Chip Status 1:**

During a Auto Page Program or Auto Block Erase operation this bit indicates the pass/fail result.

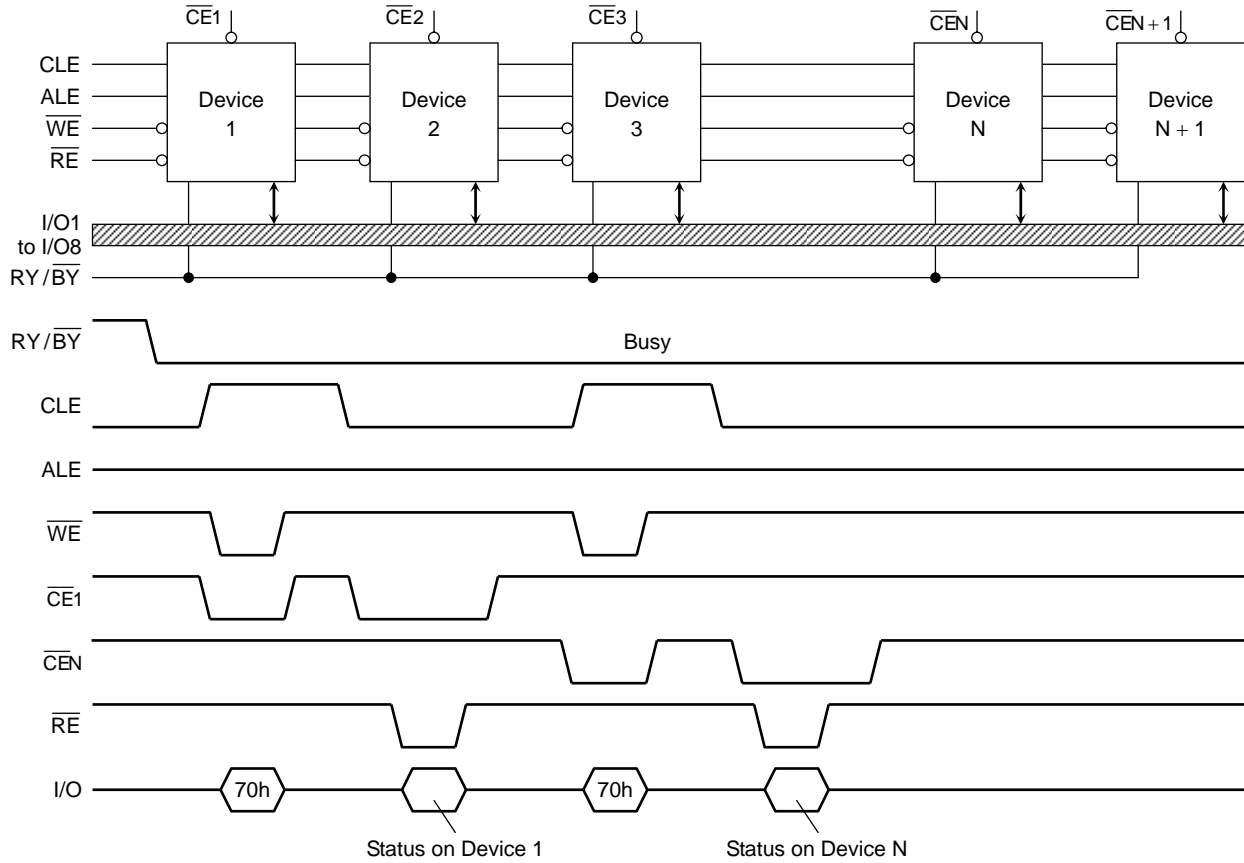
During a Auto Page Programming with Data Cache operation, this bit shows the pass/fail results of the current page program operation, and therefore this bit is only valid when I/O6 shows the Ready state.

**Chip Status 2:**

This bit shows the pass/fail result of the previous page program operation during Auto Page Programming with Data Cache. This status is valid when I/O7 shows the Ready State.

The status output on the I/O6 is the same as that of I/O7 if the command input just before the 70h is not 15h or 31h.

An application example with multiple devices is shown in the figure below.



System Design Note: If the  $\overline{RY}/\overline{BY}$  pin signals from multiple devices are wired together as shown in the diagram, the Status Read function can be used to determine the status of each individual device.

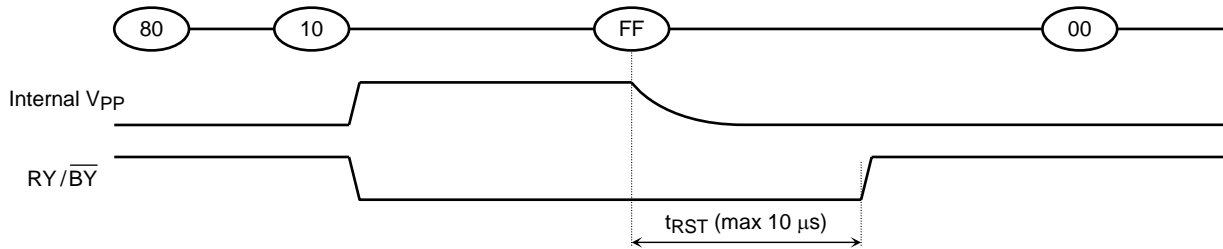
**Reset**

The Reset mode stops all operations. For example, in case of a Program or Erase operation, the internally generated voltage is discharged to 0 volt and the device enters the Wait state.

Reset during a Cache Program/Page Copy may not just stop the most recent page program but it may also stop the previous program to a page depending on when the FF reset is input.

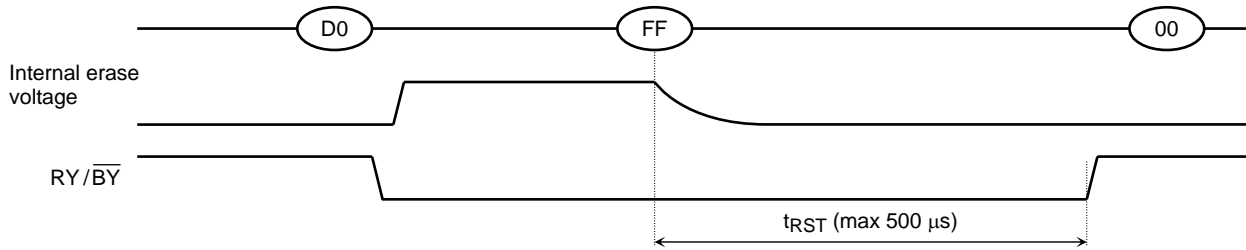
The response to a "FFh" Reset command input during the various device operations is as follows:

When a Reset (FFh) command is input during programming

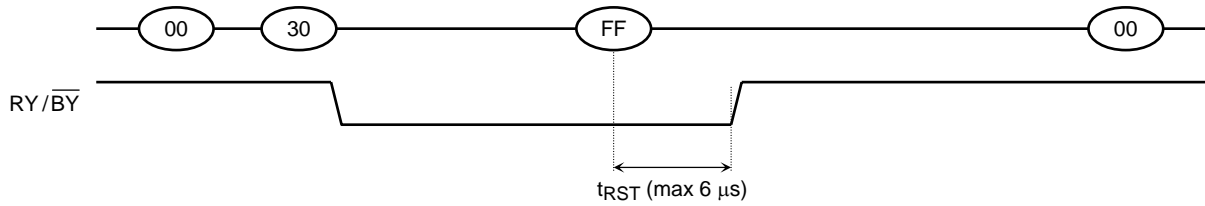




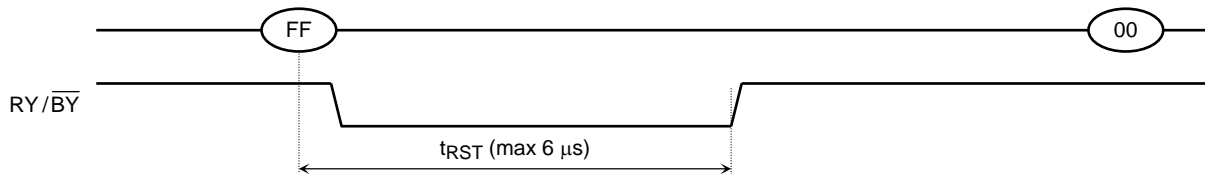
When a Reset (FFh) command is input during erasing



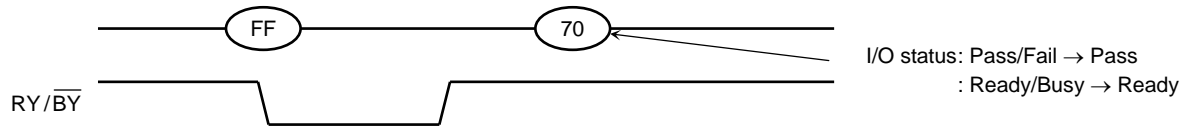
When a Reset (FFh) command is input during Read operation



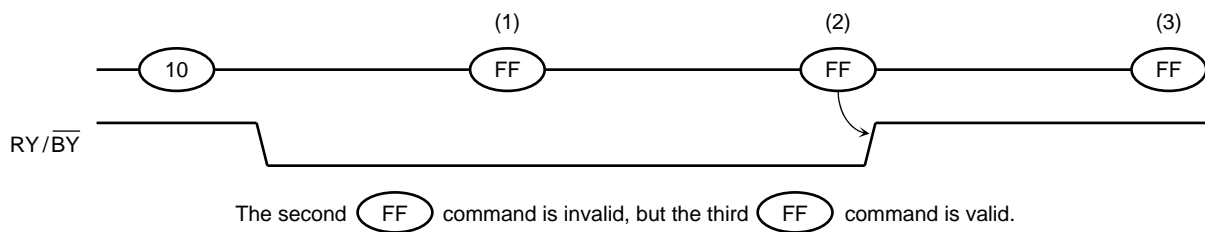
When a Reset (FFh) command is input during Ready



When a Status Read command (70h) is input after a Reset



When two or more Reset commands are input in succession



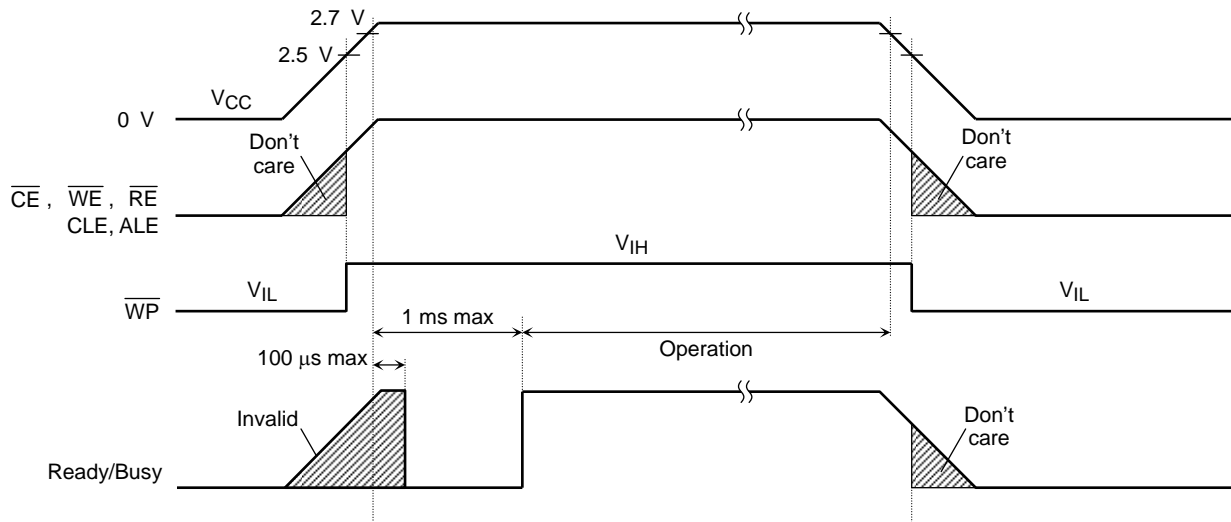
**APPLICATION NOTES AND COMMENTS**

(1) Power-on/off sequence:

The timing sequence shown in the figure below is necessary for the power-on/off sequence.

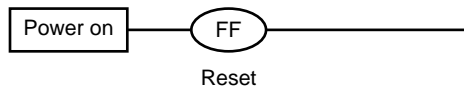
The device internal initialization starts after the power supply reaches an appropriate level in the power on sequence. During the initialization the device Ready/Busy signal indicates the Busy state as shown in the figure below. In this time period, the acceptable commands are FFh or 70h.

The  $\overline{WP}$  signal is useful for protecting against data corruption at power-on/off.



(2) Power-on Reset

The device goes into automatic self initialization during power on if PSL is tied either to GND or NU. During the initialization process, the device consumes a maximum current of 30 mA ( $I_{CC00}$ ). If PSL is tied to VCC, the device will not complete its self initialization during power on and will not consume  $I_{CC00}$ , and completes the initialization process with the first Reset command input after power on. During the first FFh reset Busy period, the device consumes a maximum current of 30 mA ( $I_{CC00}$ ). In either case (PSL = GND/NU or VCC), the following sequence is necessary because some input signals may not be stable at power-on.



(3) Prohibition of unspecified commands

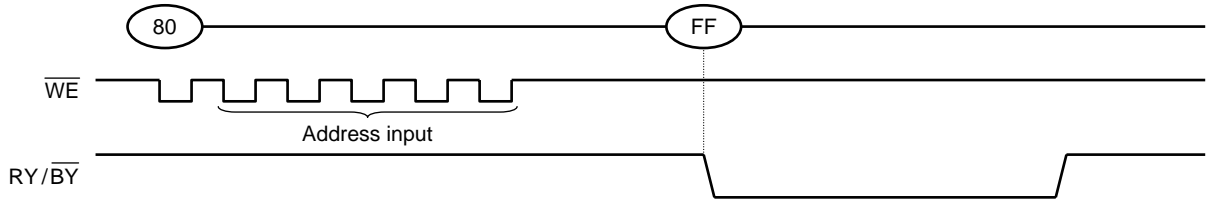
The operation commands are listed in Table 3. Input of a command other than those specified in Table 3 is prohibited. Stored data may be corrupted if an unknown command is entered during the command cycle.

(4) Restriction of commands while in the Busy state

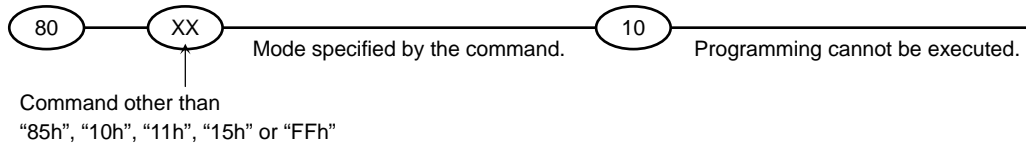
During the Busy state, do not input any command except 70h and FFh.

(5) Acceptable commands after Serial Input command “80h”

Once the Serial Input command “80h” has been input, do not input any command other than the Column Address Change in Serial Data Input command “85h”, Auto Program command “10h”, Multi-Page Program Command “11h”, Auto Program with Data Cache Command “15h”, or the Reset command “FFh”.



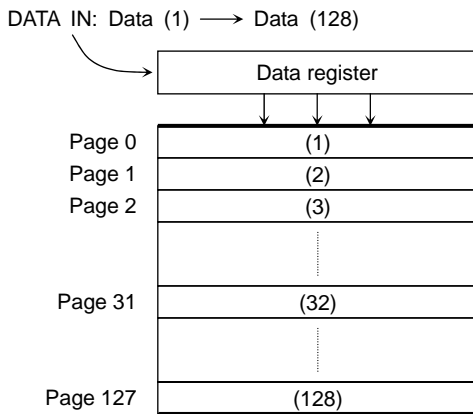
If a command other than “85h”, “10h”, “11h”, “15h” or “FFh” is input, the Program operation is not performed and the device operation is set to the mode which the input command specifies.



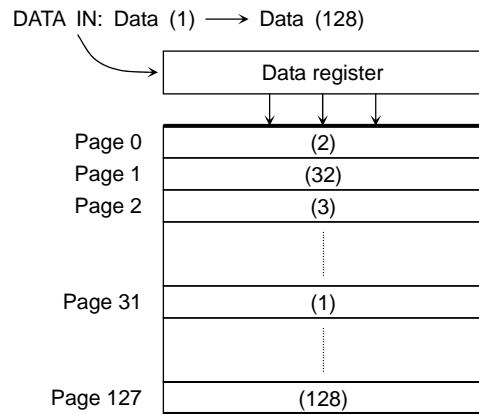
(6) Addressing for program operation

Within a block, the pages must be programmed consecutively from the LSB (least significant bit) page of the block to MSB (most significant bit) page of the block. Random page address programming is prohibited.

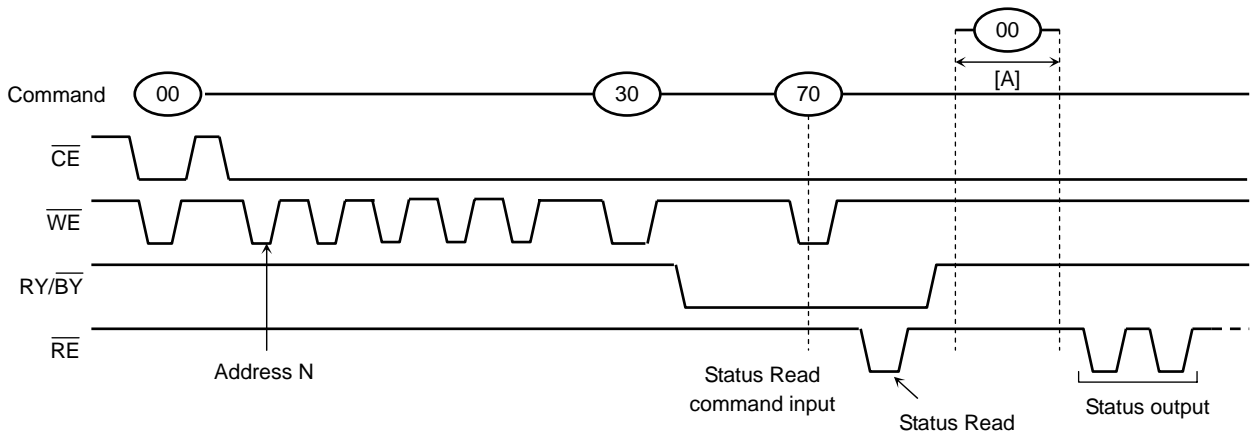
From the LSB page to MSB page



Ex.) Random page program (Prohibition)

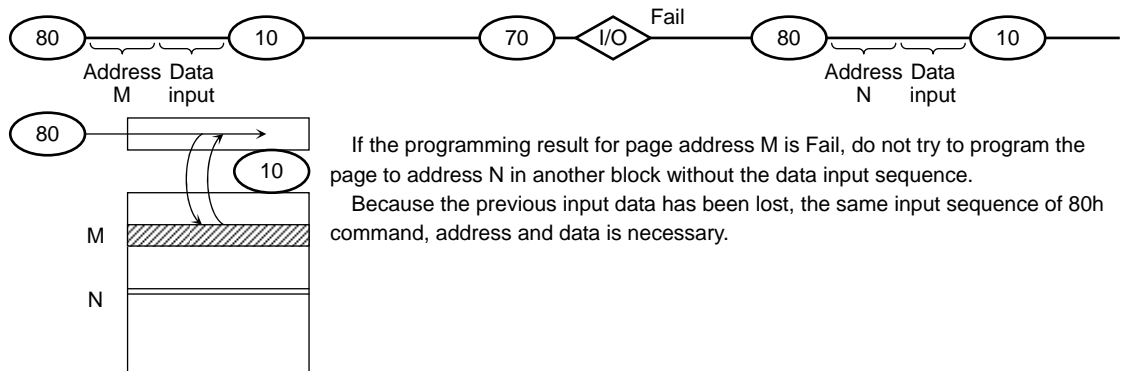


(7) Status Read during a Read operation



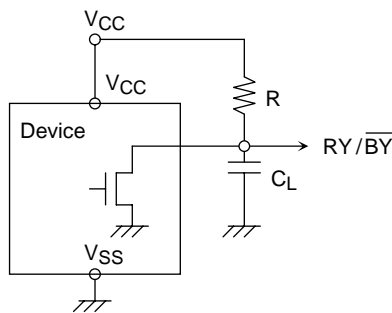
The device status can be read out by inputting the Status Read command “70h” in Read mode. Once the device has been set to Status Read mode by a “70h” command, the device will not return to Read mode unless the Read command “00h” is input during [A]. In this case, data output starts automatically from address N and address input is unnecessary

(8) Auto programming failure

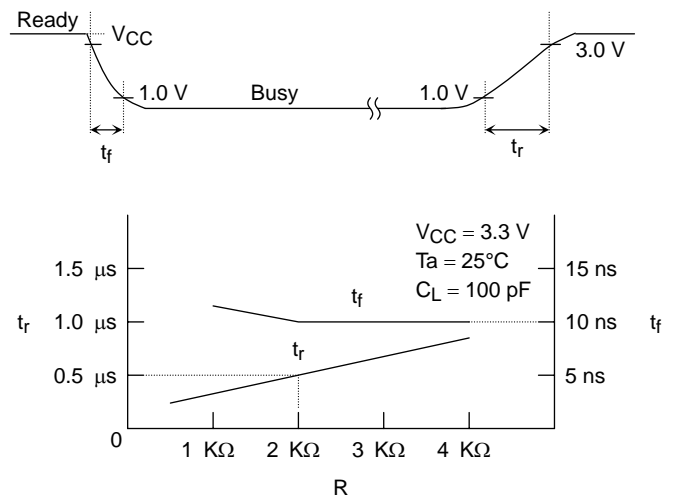


(9) RY / BY : termination for the Ready/Busy pin (RY / BY)

A pull-up resistor needs to be used for termination because the RY / BY buffer consists of an open drain circuit.



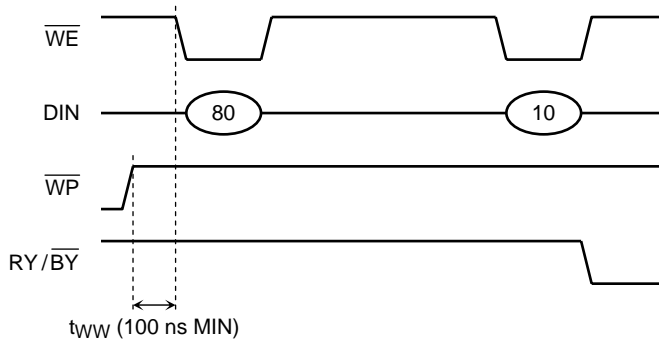
This data may vary from device to device. We recommend that you use this data as a reference when selecting a resistor value.



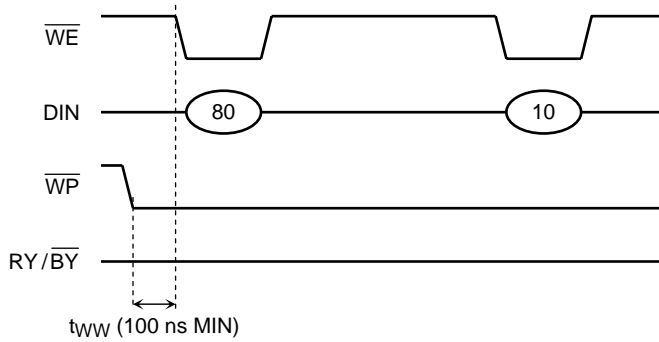
(10) Note regarding the  $\overline{WP}$  signal

The Erase and Program operations are automatically reset when  $\overline{WP}$  goes Low. The operations are enabled and disabled as follows:

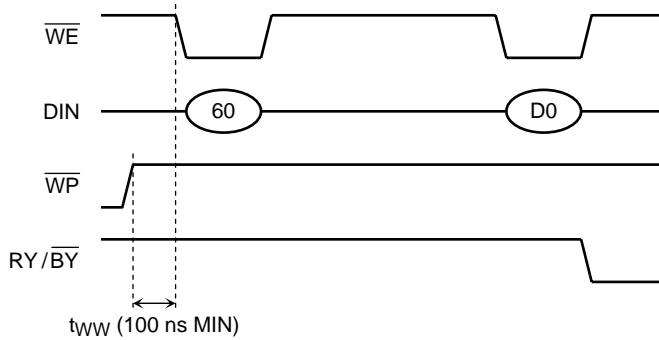
Enable Programming



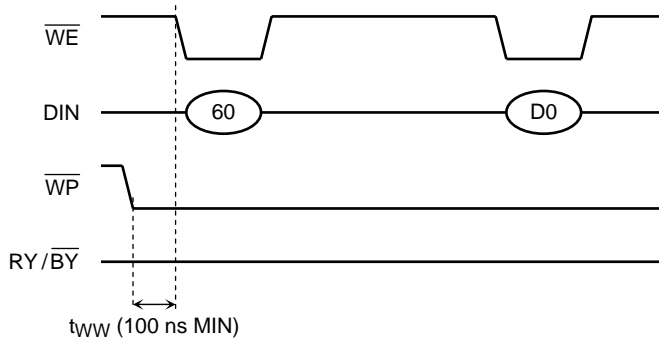
Disable Programming



Enable Erasing



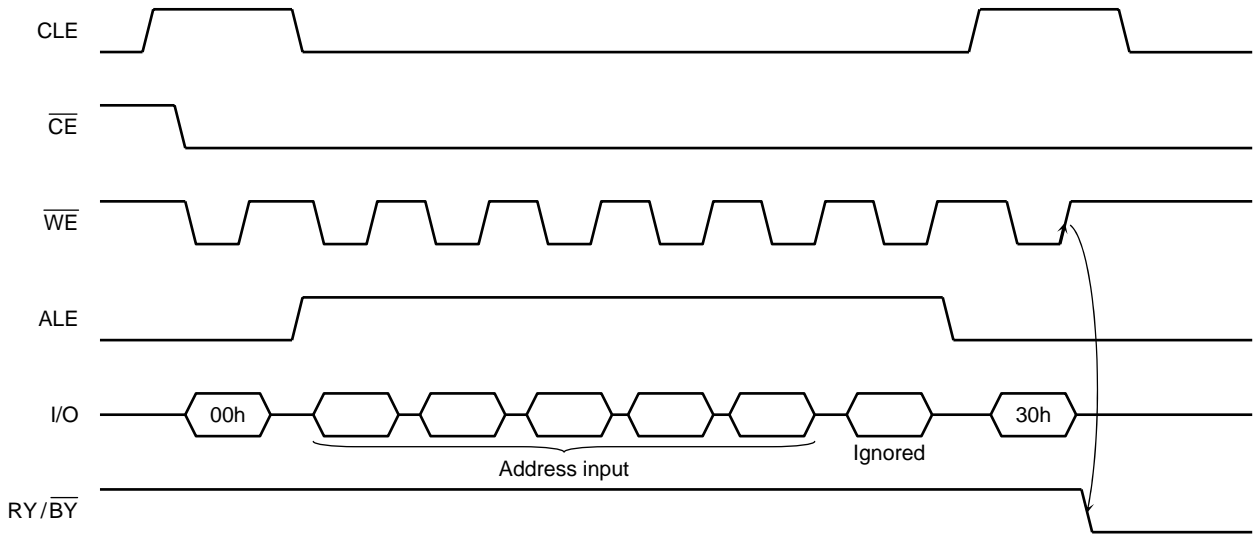
Disable Erasing



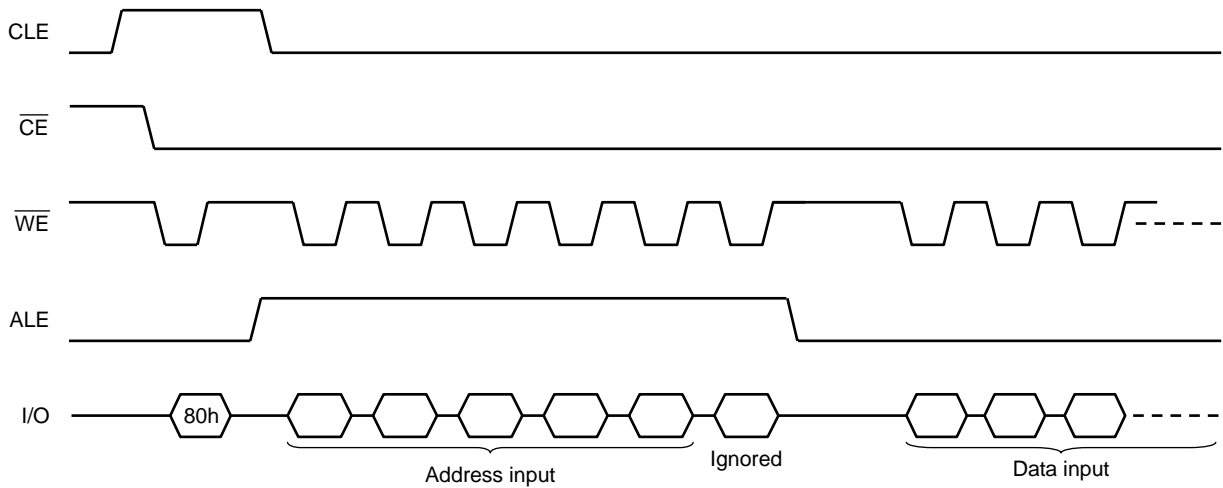
(11) When six address cycles are input

Although the device may read in a sixth address, it is ignored inside the chip.

Read operation



Program operation

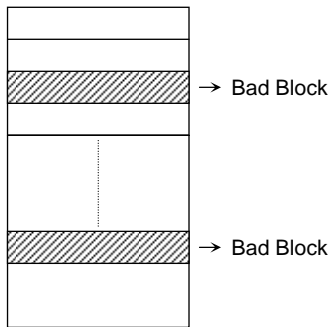


(12) Several programming cycles on the same page (Partial Page Program)

This device does not support partial page programming.

(13) Invalid blocks (bad blocks)

The device occasionally contains unusable blocks. Therefore, the following issues must be recognized:



At the time of shipment, all data bytes in a valid block are FFh. For bad blocks, all bytes are not in the FFh state. Please do not perform an erase operation to bad blocks. It may be impossible to recover the bad block information if the information is erased.

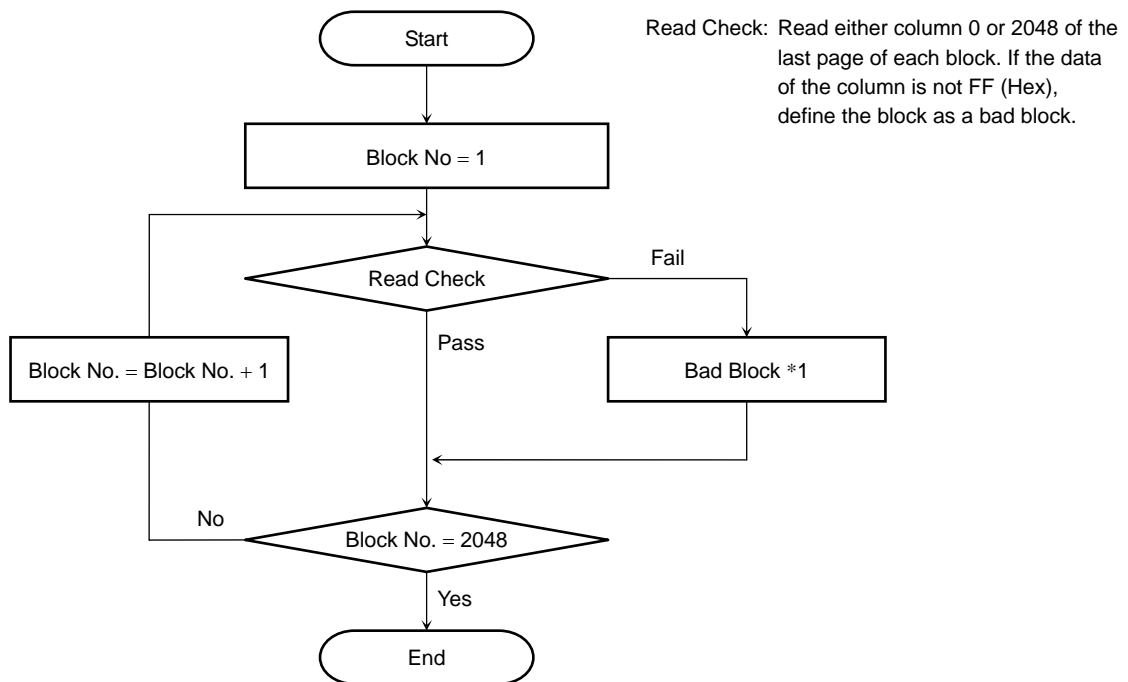
Check if the device has any bad blocks after installation into the system. Refer to the test flow for bad block detection. Bad blocks which are detected by the test flow must be managed as unusable blocks by the system.

A bad block does not affect the performance of good blocks because it is isolated from the bit lines by select gates.

The number of valid blocks at the time of shipment is as follows:

|                           | MIN  | TYP. | MAX  | UNIT  |
|---------------------------|------|------|------|-------|
| Valid (Good) Block Number | 1968 | —    | 2048 | Block |

**Bad Block Test Flow**



\*1: No erase operation is allowed to detected bad blocks



(14) Failure phenomena for Program and Erase operations

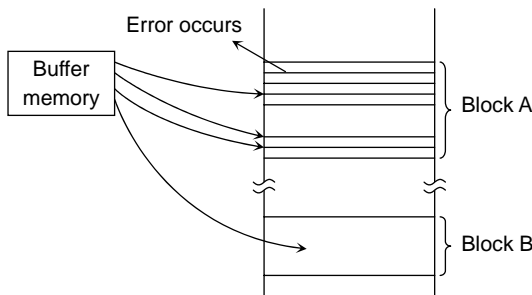
The device may fail during a Program or Erase operation.

The following possible failure modes should be considered when implementing a highly reliable system.

| FAILURE MODE |                                 | DETECTION AND COUNTERMEASURE SEQUENCE         |
|--------------|---------------------------------|---|
| Block        | Erase Failure                   | Status Read after Erase → Block Replacement   |
| Page         | Programming Failure             | Status Read after Program → Block Replacement |
| Single Bit   | Programming Failure<br>"1 to 0" | ECC   |

- ECC: Error Correction Code. 4 bit correction per 528Bytes is necessary.
- Block Replacement

Program



When an error happens in Block A, try to reprogram the data into another Block (Block B) by loading from an external buffer. Then, prevent further system accesses to Block A ( by creating a bad block table or by using another appropriate scheme).

Erase

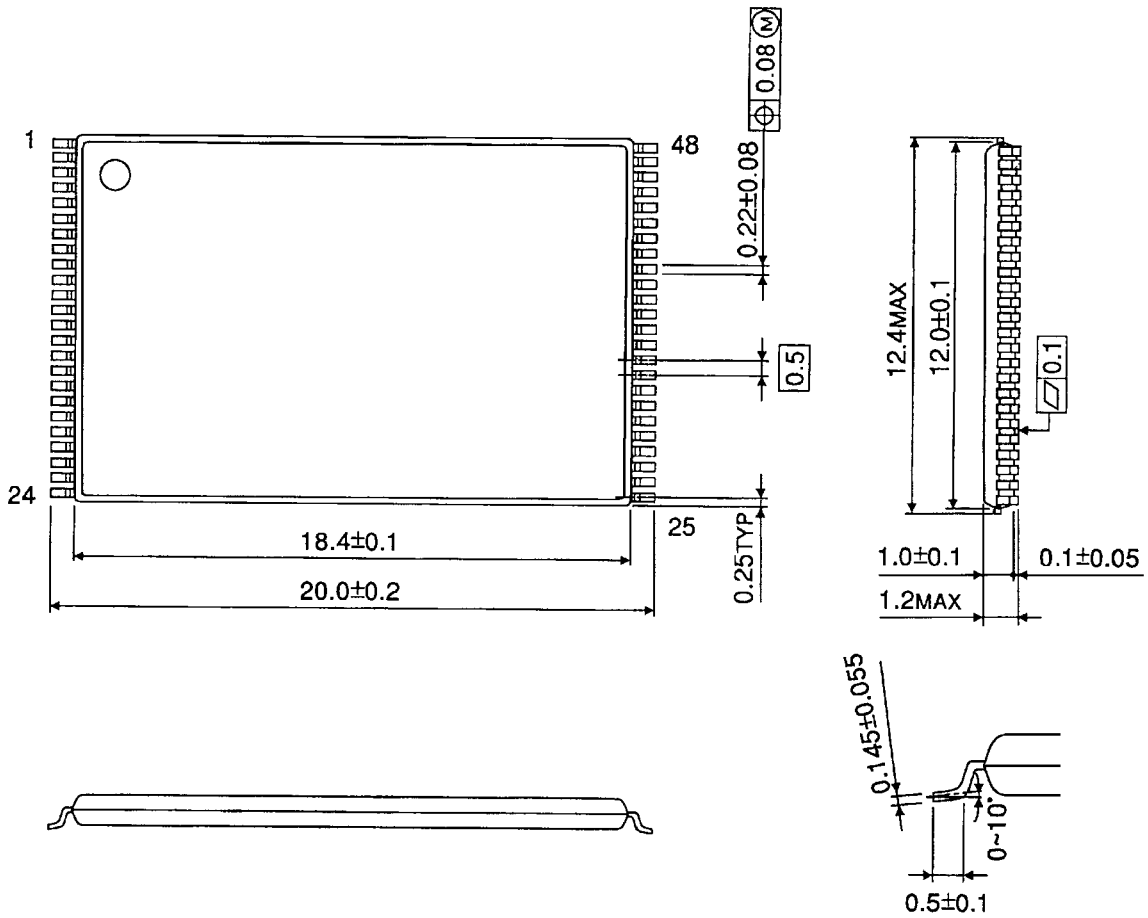
When an error occurs during an Erase operation, prevent future accesses to this bad block (again by creating a table within the system or by using another appropriate scheme).

- (15) Do not turn off the power before write/erase operation is complete. Avoid using the device when the battery is low. Power shortage and/or power failure before write/erase operation is complete will cause loss of data and/or damage to data.
- (16) If FF reset command is input before write operation to odd page (e.g. Page Address 0x00001, 0x1FFFF), is complete, it may cause damage to data not only to the page which is being programmed, but also to the adjacent even page (e.g. Page Address 0x00000, Page 0x1FFFFE in this case).

Package Dimensions

TSOP I 48-P-1220-0.50

Unit : mm



Weight: 0.53 g (typ.)

**Revision History**

| Date       | Rev. | Description   |
|------------|------|---|
| 2003-10-30 | 1.00 | Original version  |
| 2004-01-20 | 1.10 | Deleted Page Copy (1) operation timing diagram & notes.<br>P.28 Deleted command table related to Page Copy (1).   |
| 2004-07-13 | 1.20 | Deleted x16 device from data sheet and all related diagram, notes, and description.<br>Added "TOSHIBA CONFIDENTIAL" in all pages.<br>Added Multi page program as new operation.<br>P.1 Added indication that the device is Multi Level Cell.<br>Deleted x16 device information from organization.<br>Added Auto Program with Cache and Multi Page Program with Cache in Modes.<br>Changed number of valid blocks from 1958 to 1968.<br>Changed Auto Block Erase time from 1.5ms to 3ms.<br>Deleted x16 device information from package.<br>P.2 Deleted x16 information from PIN ASSIGNMENT.<br>Changed pin 6 from GND to NC.<br>Deleted I/O9 to I/O16 from PIN NAMES.<br>Deleted GND from PIN NAMES.<br>P.3 Deleted I/O16 from BLOCK DIAGRAM<br>Changed TOPR to Ta in ABSOLUTE MAXIMUM RATING.<br>P.4 Changed minimum valid blocks from 1958 to 1968 in VALID BLOCKS table.<br>Changed Icco0 (Power on Reset Current) condition from PSL=GND or NC to PSL=GND or NU.<br>Changed condition of Iccs in DC CHARACTERISTICS.<br>Changed minor appearance in table DC CHARACTERISTICS.<br>P.6 Changed tPROG, tDCBSYW max from TBD to 2000µs<br>Changed tBERASE typ from 1.5ms to 3ms. Also changed max from TBD to 10ms.<br>Added new parameter tDCMPW.<br>P.8 Deleted x16 information related to number of data input cycles<br>P.15 Fixed typo in timing diagram.<br>Deleted x16 information related to number of data input cycles.<br>P.16 Added note related to termination of Cache Program operation.<br>Deleted x16 information related to number of data input cycles.<br>P.17 Fixed typo in timing diagram.<br>Deleted x16 information related to number of data input cycles.<br>P.18 Deleted x16 information related to number of data input cycles.<br>P.24 Deleted fifth data output cycle from ID Read Operation.<br>P.25 Added note related to $\overline{WP}$ signal during Page Copy (2).<br>P.26 Deleted x16 information related to number of data input cycles.<br>P.28 Deleted x16 information related to number of data input cycles.<br>P.29 Deleted I/O 9 to I/O 16 information from PIN FUNCTIONS.<br>P.30 Deleted x16 Schematic Cell Layout and Address Assignment.<br>P.31 Added PSL in Logic table and added explanation.<br>P.32 Added Multi page programming and Status Read for Multi Page Program in command table.<br>Deleted I/O9 to I/O 16 from HEX data bit assignment.<br>P.33 Deleted x16 information related to number of data input cycles.<br>P.43 Added notes related to $\overline{WP}$ signal during Page Copy (2).<br>P.45 Deleted x16 information from ID code table<br>Deleted 5 <sup>th</sup> cycle information from ID READ.<br>Changed explanation of 3 <sup>rd</sup> cycle.<br>P.46 Deleted 5 <sup>th</sup> cycle information from ID READ.<br>Fixed typo in ID code table.<br>P.47 Fixed typo in Status output table ( $\overline{WP}$ )<br>Deleted I/O 9 to I/O 16 from Status output table.<br>P.50 Changed PSL state from NC to NU in description of Power On Read. |

|  |  |      |  |
|--|--|------|--|
|  |  | P.51 | Changed description in Comment (5) .                       |
|  |  | P.56 | Changed number of valid blocks from 1958 to 1968 in table. |
|  |  | P.57 | Added note (16).   |
|  |  | P.59 | Added revision history in datasheet.                       |

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030619EBA

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